SERVICE MANUAL

3561A DYNAMIC SIGNAL ANALYZER

VOLUME II







SERVICE MANUAL

MODEL 3561A DYNAMIC SIGNAL ANALYZER

Serial Prefix: 2338A

IMPORTANT NOTICE

This manual applies to instruments with the above serial number and greater. As changes are made in the instrument to improve performance and reliability, the appropriate pages will be revised to include this information.

WARNING

To prevent potential fire or shock hazard, do not expose instrument to rain or moisture.

Manual Part No. 03561-90010 Microfiche Part No. 03561-90060

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CERTIFICATION

Hewlett-Packard Company certifies that this product met its published specifications at the time of shipment from the factory. Hewlett-Packard further certifies that its calibration measurements are traceable to the United States National Bureau of Standards, to the extent allowed by the Bureau's calibration facility, and to the calibration facilities of other International Standards Organization members.

WARRANTY

This Hewlett-Packard product is warranted against defects in material and workmanship for a period of one year from date of shipment [,except that in the case of certain components listed in Section I of this manual, the warranty shall be for the specified period]. During the warranty period, Hewlett-Packard Company will, at its option, either repair or replace products which prove to be defective.

For warranty service or repair, this product must be returned to a service facility designated by -hp-. Buyer shall prepay shipping charges to -hp- and -hp- shall pay shipping charges to return the product to Buyer. However, Buyer shall pay all shipping charges, duties, and taxes for products returned to -hp- from another country.

HP software and firmware products which are designated by HP for use with a hardware product, when properly installed on that hardware product, are warranted not to fail to execute their programming instructions due to defects in materials and workmanship. If HP receives notice of such defects during the warranty period, HP shall repair or replace software media and firmware which do not execute their programming instructions due to such defects. HP does not warrant that the operation of the software, firmware or hardware shall be uninterrupted or error free.

LIMITATION OF WARRANTY

The foregoing warranty shall not apply to defects resulting from improper or inadequate maintenance by Buyer. Buyer-supplied software or interfacing, unauthorized modification or misuse, operation outside of the environmental specifications for the product, or improper site preparation or maintenance.

NO OTHER WARRANTY IS EXPRESSED OR IMPLIED. HEWLETT-PACKARD SPECIFICALLY DISCLAIMS THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE.

EXCLUSIVE REMEDIES

THE REMEDIES PROVIDED HEREIN ARE BUYER'S SOLE AND EXCLUSIVE REMEDIES. HEWLETT-PACKARD SHALL NOT BE LIABLE FOR ANY DIRECT, INDIRECT, SPECIAL, INCIDENTAL, OR CONSEQUENTIAL DAMAGES, WHETHER BASED ON CONTRACT, TORT, OR ANY OTHER LEGAL THEORY.

ASSISTANCE

Product maintenance agreements and other customer assistance agreements are available for Hewlett-Packard products.

For any assistance, contact your nearest Hewlett-Packard Sales and Service Office. Addresses are provided at the back of this manual.



SAFETY SUMMARY

The following general safety precautions must be observed during all phases of operation, service, and repair of this instrument. Failure to comply with these precautions or with specific warnings elsewhere in this manual violates safety standards of design, manufacture, and intended use of the instrument. Hewlett-Packard Company assumes no liability for the customer's failure to comply with these requirements. This is a Safety Class 1 instrument.

GROUND THE INSTRUMENT

To minimize shock hazard, the instrument chassis and cabinet must be connected to an electrical ground. The instrument is equipped with a three-conductor ac power cable. The power cable must either be plugged into an approved three-contact electrical outlet or used with a three-contact to two-contact adapter with the grounding wire (green) firmly connected to an electrical ground (safety ground) at the power outlet. The power jack and mating plug of the power cable meet International Electrotechnical Commission (IEC) safety standards.

DO NOT OPERATE IN AN EXPLOSIVE ATMOSPHERE

Do not operate the instrument in the presence of flammable gases or fumes. Operation of any electrical instrument in such an environment constitutes a definite safety hazard.

KEEP AWAY FROM LIVE CIRCUITS

Operating personnel must not remove instrument covers. Component replacement and internal adjustments must be made by qualified maintenance personnel. Do not replace components with power cable connected. Under certain conditions, dangerous voltages may exist even with the power cable removed. To avoid injuries, always disconnect power and discharge circuits before touching them.

DO NOT SERVICE OR ADJUST ALONE

Do not attempt internal service or adjustment unless another person, capable of rendering first aid and resuscitation, is present.

USE CAUTION WHEN EXPOSING OR HANDLING THE CRT

Breakage of the Cathode-ray Tube (CRT) causes a high-velocity scattering of glass fragments (implosion). To prevent CRT implosion, avoid rough handling or jarring of the instrument. Handling of the CRT shall be done only by qualified maintenance personnel using approved safety mask and gloves.

DO NOT SUBSTITUTE PARTS OR MODIFY INSTRUMENT

Because of the danger of introducing additional hazards, do not install substitute parts or perform any unauthorized modification to the instrument. Return the instrument to a Hewlett-Packard Sales and Service Office for service and repair to ensure that safety features are maintained.

DANGEROUS PROCEDURE WARNINGS

Warnings, such as the example below, precede potentially dangerous procedures throughout this manual. Instructions contained in the warnings must be followed.

WARNING

Dangerous voltages, capable of causing death, are present in this instrument. Use extreme caution when handling, testing, and adjusting.

SAFETY SYMBOLS

General Definitions of Safety Symbols Used On Equipment or In Manuals.



Instruction manual symbol: the product will be marked with this symbol when it is necessary for the user to refer to the instruction manual in order to protect against damage to the instrument.



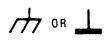
Indicates dangerous voltage (terminals fed from the interior by voltage exceeding 1000 volts must be so marked).



Protective conductor terminal. For protection against electrical shock in case of a fault. Used with field wiring terminals to indicate the terminal which must be connected to ground before operating equipment.



Low-noise or noiseless, clean ground (earth) terminal. Used for a signal common, as well as providing protection against electrical shock in case of a fault. A terminal marked with this symbol must be connected to ground in the manner described in the installation (operating) manual, and before operating the equipment.



Frame or chassis terminal. A connection to the frame (chassis) of the equipment which normally includes all exposed metal structures.



Alternating current (power line).

Direct current (power line).

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Alternating or direct current (power line).

WARNING

The WARNING sign denotes a hazard. It calls attention to a procedure, practice, condition or the like, which, if not correctly performed or adhered to, could result in injury or death to personnel.



The CAUTION sign denotes a hazard. It calls attention to an operating procedure, practice, condition or the like, which, if not correctly performed or adhered to, could result in damage to or destruction of part or all of the product.

NOTE:

The NOTE sign denotes important information. It calls attention to procedure, practice, condition or the like, which is essential to highlight.

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SECTION VII SERVICE

7-1 INTRODUCTION

The information contained in this section is used for troubleshooting a circuit board to the component level. The following information is given for each board: circuit description, troubleshooting procedures, component locator, and schematic diagram. A complete list of schematic diagrams is given in Table 7-1.

The equipment needed to perform the troubleshooting procedures is listed in Table 1-5. If the recommended equipment is not available, a substitute may be used which meets or exceeds the critical specifications listed in the table.

NOTE

After completing a test or repair, check that all jumpers have been returned to the NORMAL or RUN position and that all cables have been re-connected.



Do not remove or replace any circuit boards when the LINE power switch is ON.



To protect the -hp-3561A circuits from static discharge, remove or replace circuit boards only at static protected work stations.

Table 7-1 Schematic Diagrams

Schematic/ Assembly Number	Number of Schematics	Board Description
A10	2	Input Amplifier
A15	2	Digitizer
A20	4	Digital Filter
A30	2	FFT/RAM
A40	4	Processor/ROM
A50	3	Local Oscillator/Noise Source
A60	3	Digital Display Driver
A65	1	CMOS/Bubble Memory
A66	1	CMOS Memory
A70, A71, A72	2	Power Supply
A80, A81	1	Keyboard
A82	1	Rear Panel
6	1	Analog Display Driver

7-2 SAFETY CONSIDERATIONS

WARNING

Maintenance described herein is performed with power supplied to the instrument and with the protective covers removed. Such maintenance should be performed only by service-trained personnel who are aware of the hazards involved.

Any interruption of the protective grounding conductor inside or outside the instrument, or disconnection of the protective earth terminal, is likely to make the instrument hazardous.

WARNING

±170 Volts are present on the A70 and A71 Assemblies. ±170 Volts are present on the heat sinks on the A70 Assembly. This voltage is exposed whenever the protective power supply cover is removed. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

Capacitors in the power supply will remain charged to ± 170 Volts dc for at least three(3) minutes after power is removed from the instrument. Do not remove the power supply assemblies (A70, A71, A72) or disconnect cables W70 or W71 for at least three(3) minutes after power is removed from the -hp-3561A.

WARNING

Only fuses with the required current rating and of the specified type should be used for replacement. The use of repaired fuses or short circuiting the fuse holder is not permitted. Whenever it is likely that the protection offered by the fuse has been impaired, the instrument must be made inoperative, and secured against any unintended operation.

WARNING

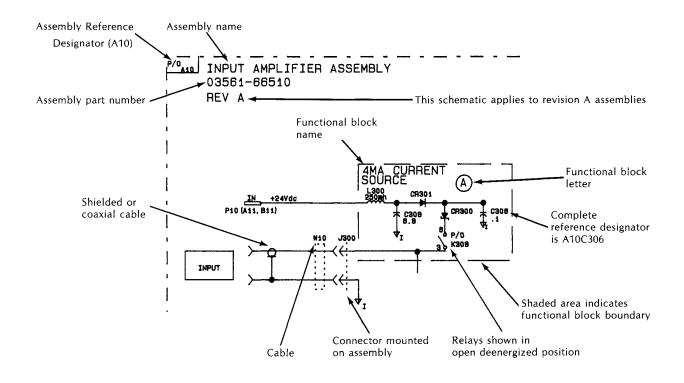
The protective power supply covers are removed exposing ± 170 Volts while troubleshooting the A66 CMOS Memory Assembly or the A65 CMOS/Bubble Memory Assembly. Be extremely careful when working in this area, the high voltage could cause serious personal injury if contacted.

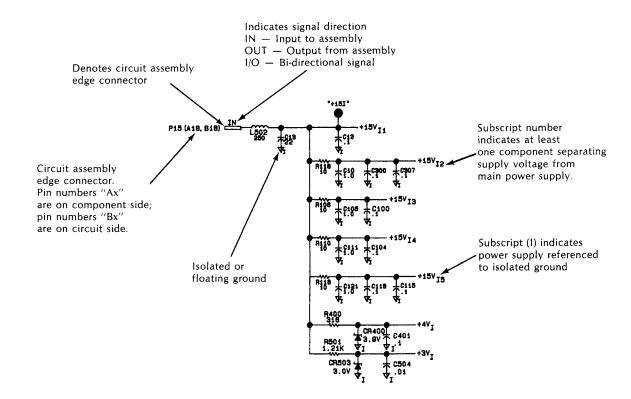
WARNING

+8000 Volts are present in the CRT AT ALL TIMES, EVEN WHEN POWER IS REMOVED FROM THE INSTRUMENT! Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

7-3 SCHEMATIC NOTES

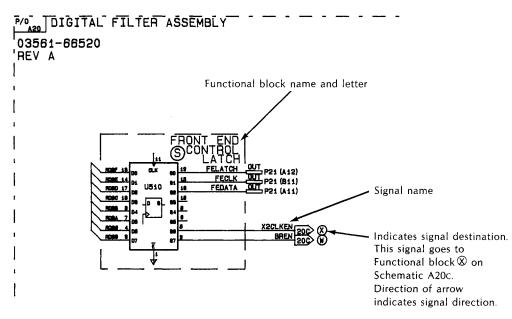
1.	PARTIAL REFERENCE DESIGNATIONS ARE SHOWN. PREFIX WITH ASSEMBLY DESIGNATION FOR COMPLETE DESIGNATION.	10. DENOTES REAR PANEL MARKING. 11. DENOTES SCREWDRIVER ADJUST
2.	COMPONENT VALUES ARE SHOWN AS FOLLOWS UNLESS OTHERWISE NOTED. RESISTANCE IN OHMS CAPACITANCE IN MICROFARADS INDUCTANCE IN MILLIHENRIES	12. AVERAGE VALUE SHOWN. OPTIMUM VALUE SELECTED AT FACTORY. THE VALUE OF THESE COMPONENTS MAY VARY FROM ONE INSTRUMENT TO ANOTHER. 13. DENOTES RF SHIELD
3.	DENOTES EARTH GROUND USED FOR TERMINALS WITH NO LESS THAN A NO. 18 GAUGE WIRE CONNECTED BETWEEN TERMINAL AND EARTH GROUND TERMINAL OF AC POWER RECEPTACLE	14. ALL RELAYS ARE SHOWN DEENERGIZED. ALL ANALOG SWITCH IC'S ARE SHOWN NOT ACTIVE. 15. DENOTES RESISTOR
4.	DENOTES FRAME GROUND USED FOR TERMINALS WHICH ARE PERMANENTLY CONNECTED WITHIN APPROXIMATELY 0.1 OHM OF EARTH GROUND.	16. ALL WAVEFORMS SHOWN ARE MEASURED WITH A 10:1 OSCILLOSCOPE PROBE UNLESS OTHERWISE NOTED. ALL DC VOLTAGES ARE MEASURED WITH A 1:1 PROBE
5.	DENOTES GROUND ON PRINTED CIRCUIT ASSEMBLY (ELECTRICALLY CONNECTED TO FRAME GROUND.)	AND A DVM. 17. R3 MAY BE LOADED WITH A ZERO OHM RESISTOR 0 OR A JUMPER WIRE.
6. 7.	DENOTES ISOLATED (I) OR SIGNAL(S) CIRCUIT GROUND. DENOTES ASSEMBLY	18. MOVEABLE JUMPER. N INDICATES NORMAL OR RUN POSITION; T INDICATES TEST POSITION.
8.	DENOTES MAIN SIGNAL PATH	M3 N C
9.	DENOTES FRONT PANEL MARKING	

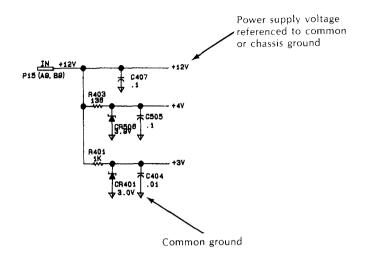




Schematic A20c P/0A20 DIGITAL FILTER ASSEMBLY 03561-66520 REV A Functional block name and letter COUNTER CLOCK SELECT U300c S SOB XSCIKEN Indicates signal source. Signal name This signal comes from functional block S on Schematic A20B. Direction of arrow indicates signal direction.

Schematic A20B





7-4 A10 INPUT AMPLIFIER ASSEMBLY

7-5 Input Amplifier Circuit Description

GENERAL

The main function of the Input Amplifier Assembly is to implement the RANGE function. This function allows the -hp-3561A to measure signals of different amplitudes. The range setting specifies the maximum input amplitude which will not overload the -hp-3561A. Other circuitry on the A10 Assembly includes the Auto-Zero DAC, Trigger Level DAC, and A-Weight Filter.

[A] 4 mA CURRENT SOURCE, FRONT PANEL GROUND SWITCH

When signal ICP ON/OFF is TTL high, relay K308 closes, and a 4 milliamp current is delivered to the center conductor of the BNC input connector.

The front panel ground switch determines the ground reference for the the input connector. When the ground switch is in the FLOAT position, signal FEISO is pulled low to tell the processor the position of the ground switch for HP-IB access.

[B] CAL SIGNAL GENERATOR, [O] CAL SIGNAL CONTROL

These circuits produce a signal with a precise amplitude of 195 mVrms (-14.2 dBV) which is used to calibrate the amplitude accuracy of the -hp-3561A. The cal signal frequency, which is set on the A20 Assembly, is 4 kHz when the cal signal is selected by pressing the INPUT key and selecting CAL SIG ON. To isolate the front panel input connector when the cal signal is enabled, BNC1 goes low to open K305 and K307 and BNC2 goes high to close K306. For more information, see the "Self Calibration" paragraph in Section 6 of this manual.

[C] ATTENUATOR #1,[F] ATTENUATOR #2, [H] ATTENUATOR #3,[J] ATTENUATOR #4

These attenuators are programmable through the front end control register to the attenuation values specified on the schematic. The equivalent attenuation in linear terms is also given on the schematic. The attenuators are used to scale the input signal to a nominal level for the A/D converter. Table 7-2 lists all of the attenuator setting as a function of the instrument RANGE setting.

[K] A-WEIGHT FILTER

The A-Weight Filter is enabled by the AWHT ON/OFF signal from the front end control register. The A-Weight Filter implements ANSI Standard S1.4-1971. A table of filter gain verses frequency is given in Table 7-3.

Table 7-2 Attenuator Settings vs. Range Settings

++++++	+ 27 + 26 + 25 + 24	40		(dBV)	(dBV)
++++++	+ 26 + 25	1 40	12	12	14
+++++++++++++++++++++++++++++++++++++++	⊢ 25	40	13	10	14
+++++++++++++++++++++++++++++++++++++++		40	12	10	14
+++++++++++++++++++++++++++++++++++++++		40	13	8	14
+	+ 23	40	12	8	14
+	+ 22	40	13	6	14
	+ 21	40	12	6	14
	+ 20	40	13	4	14
	. 20 ⊦19	40	12	4	14
	⊦ 18	40	13	2	14
	. 13 ⊦17	40	12	2	14
	⊦16	40	1	12	14
	+ 15 + 15	40	o o	12	14
	+14	40	1	10	14
	⊦13	40	o o	10	14
	+ 12	40	1	8	14
	. 1 <u>-</u> ⊦11	40	0	8	14
	+ 10	40	1	6	14
	⊦9	40	0	6	14
	+ 8	40	1	4	14
	+ <i>7</i>	20	12	12	14
	+ 6	20	13	10	14
	+ 5	20	12	10	14
	+ 4	20	13	8	14
	+ 3	20	12	8	14
	+ 2	20	13	6	14
	· - +1	20	12	6	14
	0	20	13	4	14
	-1	20	12	4	14
	-2	20	13	2	14
	-3	20	12	2	14
	-4	20	1	12	14
	-5	20	0	12	14
	-6	20	1	10	14
	-7	20	0	10	14
	-8	20	1	8	14
	-9	20	0	8	14
	-10	20	1	6	14
	-11	20	0	6	14
	-12	20	1	4	14
	-13	0	12	12	14
	-14	0	13	10	14
	-15	0	12	10	14
	-16	0	13	8	14
	-1 <i>7</i>	0	12	8	14
	-18	o o	13	6	14
	-19	o o	12	6	14
	-20	0	13	4	14
	-21	0	12	4	14
	-22	ō	13	2	14
	-23	0	12	2	14
	-24	Ō	1	12	14
	-25	0	0	12	14
	-26	0	1	10	14
	-27	0	0	10	14

Table 7-2 Attenuator Settings vs. Range Settings (Cont'd)

RANGE (DBV)	ATTENUATOR#1 (dBV)	ATTENUATOR#2 (dBV)	ATTENUATOR#3 (dBV)	ATTENUATOR#4 (dBV)
-28	0	1	8	14
-29	0	0	8	14
-30	0	1	6	14
-31	0	0	6	14
-32	0	1	4	14
-33	0	0	4	14
-34	0	1	2	14
-35	0	0	2	14
-36	0	1	0	14
-37	0	0	0	14
-38	0	1	0	12
-39	0	0	0	12
-40	0	1	0	10
-41	0	0	0	10
-42	0	1	0	8
-43	0	0	0	8
-44	0	1	0	6
-45	0	0	0	6
-46	0	1	0	4
-47	0	0	0	4
-48	0	1	0	2
-49	0	0	0	2
-50	0	1	0	0
-51	0	0	0	0

[L] AUTO-ZERO DAC

The auto-zero DAC is programmed through the front end control register to zero the dc offset in the input circuitry. An auto-zero is performed whenever a calibration is performed or the instrument range is changed. This function can be disabled by moving jumper A10W100 to the test position.

[N] DIGITAL CONTROL INPUT AND ISOLATION

The FEDATA, FECLOCK and FELATCH signals work together to input, clock, and latch digital information from the processor into the front end control register. These three signals are transformer coupled to maintain isolation between the chassis ground and the isolated ground.

[P] FRONT END CONTROL REGISTER

The front end control register is a serial in parallel out register which latches and stores A10 Assembly programming data. Data stored in the front end control register is only updated when an instrument front panel control is changed which requires a change in the setup of the A10 Assembly or the A15 Assembly.

Table 7-3 A-Weight Filter Characteristics

Frequency (Hz)	Amplitude Gain (dB)	Tolerance (dB)
10.0	-70.4	± 4.0
12.5	-63.4	± 3.5
16.0	-56.7	± 3.0
20.0	-50.5	± 2.5
25.0	-44.7	± 2.0
31.5	-39.4	±1.5
40.0	-34.6	±1.5
50.0	-30.2	±1.0
63.0	-26.2	±1.0
80.0	-22.5	±1.0
100	-19.1	±1.0
125	-16.1	±1.0
160	-13.4	±1.0
200	-10.9	±1.0
250	-8.6	±1.0
315	-6.6	±1.0
400	-4.8	±1.0
500	-3.2	±1.0
630	-1.9	±1.0
800	-0.8	±1.0
1000	0	±1.0
1250	0.6	±1.0
1600	1.0	±1.0
2000	1.2	±1.0
2500	1.3	±1.0
3150	1.2	±1.0
4000	1.0	±1.0
5000	-0.5	+1.5,-2
6300	-0.8	+1.5,-2
8000	-1.1	+1.5,-3
10000	-2.5	+ 2,-4
12500	-4.3	+ 3,-6
16000	-6.6	+3,-∞
20000	-9.3	+3,-∞

[Q] TRIGGER LEVEL DAC

The Trigger Level DAC is used to set up the voltage level at which the -hp-3561A will trigger on the input signal. The trigger level is established by the DEFINE % OF RNC soft key. A trigger level of 100 % of range corresponds to a DAC output of 1.29 Vdc regardless of the range selected. The DAC output for other percentage settings may be directly calculated by taking the percentage selected of 1.29 Vdc (eg., .645 Vdc for a 50 % setting).

Table 7-4 A10 Assembly Signal Descriptions

Signal Name	Description
AC/DC CPL	AC/DC CouPLing: TTL high for dc coupling of the input signal, low for ac coupling.
ATTN1 - ATTN4	ATTeNuator #1 through ATTeNuator #4: These signals program the attenuation of the four input attenuators.
BNC1	Isolates the front panel BNC connector when the CAL BNC2 signal is enabled.
COMP OUT	COMPare OUTput: This signal is used on the A15 Assembly to generate the over-range, under-range, and input trigger signals.
FE CAL	Front End CALibration: TTL signal from the A20 Assembly which sets the frequency of the CAL signal used for self calibration.
FE CALG	Front End CALibration Gated: FE CAL gated by CAL ON/OFF Signal.
FECLOCK	Front End CLOCK: Clocks the FEDATA signal into the front end control register.
FEDATA	Front End DATA: Serial data which programs all circuits on the A10 Assembly when latched into the front end control register.
FEDATAIC	Front End DATA Isolated Continue: A continuation of the FEDATA signal. This signal contains programming information for the A15 Assembly.
FELATCH	Front End LATCH: Latches the FEDATA signal into the front end control register.
TRIG0-7	TRIGger bus (0-7): Programs the trigger level D/A converter.
0DAC0-7	0 Digital to Analog Converter bus (0-7): Programs the auto zero D/A converter.

7-6 Troubleshooting the Input Amplifier

ECAUTION 3

Before removing the A10 Assembly, remove the bottom cover and disconnect the input cable (W10).

GENERAL

The primary method for troubleshooting this assembly is to input a sine wave to the -hp-3561A and check the signal at each amplifier stage. Table 7-5 lists the signal amplitudes at the AMP1, AMP2, and AMP3 test points and at the A10 output (J200) for an input sine wave with an amplitude equal to the -hp-3561A range setting.

All signal amplitudes listed have a tolerance of $\pm 5\%$ ($\pm .4$ dB)

[C] ATTENUATOR #1,[E] AMPLIFIER #1,[F] ATTENUATOR #2,[G] AMPLIFIER #2, [H] ATTENUATOR #3,[I] AMPLIFIER #3,[J] ATTENUATOR #4,[M] AMPLIFIER #4

To check these circuits, place the A10 Assembly on an extender board and use a BNC to SMB adapter cable to input a 1 kHz, 1 Vrms (1.414 Vpeak) sine wave into A10J10. Set the -hp-3561A controls as follows:

PRESET		
RANGE	DEFINE RANGE	 0 dBV

Verify the signal amplitudes listed in the 0 dBV range column of Table 7-5. This test can be repeated at the other range settings listed.

Table 7-5 Signal Amplitudes vs. Range Setting

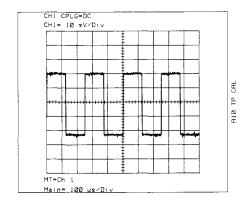
-hp-3561A	dBV	+9	0	-5	-36	-51
RANGE	Vrms	2.818	1.00	.5623	.0158	.0028
SETTING	Vpeak	3.985	1.414	.7952	.0223	.0039
TP AMP1	dBV	-21.46	-10.46	-15.46	-26.46	-41.56
	Vrms	.085	.300	.168	.047	.0085
	Vpeak	.120	.424	.238	.066	.012
TP AMP2	dBV	-11.92	-13.92	-5.92	-17.92	-31.92
	Vrms	.254	.201	.506	.127	.025
	Vpeak	.359	.284	. 716	.180	.035
TP AMP3	dBV	-8.37	-8.37	-8.37	-8.37	-22.37
	Vrms	.381	.381	.381	.381	.076
	Vpeak	.539	.539	.539	.539	.107
OUTPUT	dBV	-12.83	-12.83	-12.83	-12.83	-12.83
	Vrms	.228	.228	.228	.228	.228
	Vpeak	.323	.323	.323	.323	.323

[B] CAL SIGNAL GENERATOR, [O] CAL SIGNAL CONTROL

To check these circuits, set the -hp-3561A controls as shown below, and use a digital voltmeter to check for .216 Vac at the CAL test point. Verify the CAL signal as shown in Figure 7-1.

PRESET
INPUT..... AUTO CAL OFF
CAL SIG ON

Figure 7-1 CAL Signal Waveform



Probe: 10:1

Ch1: Connection- A10 TP CAL Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

Troubleshooting for Distortion

To troubleshoot for distortion failures, a low distortion oscillator, which meets the required characteristics listed in Table 1-5, is used to input a sine wave to each of the test points AMP1, AMP2, AMP3, and to A15J1. The -hp-3561A display can then be monitored for distortion introduced by each amplifier stage.

1. Set the -hp-3561A controls as follows:

PRESET
INPUT..... AUTO CAL OFF

- Disconnect cable W15 from connector A15J1 and move test jumper A10W100 to the TEST position.
- 3. Using a BNC to SMB adapter cable and the low distortion oscillator, input a 1 kHz, .228 Vrms(±5%) sine wave into A15J1. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the -hp-3561A main measurement path through the A15, A20, and A30 Assemblies is operating correctly. This main measurement path can now be used to test the A10 Assembly. If a full scale 1 kHz sine wave does not appear on the display, or the harmonic signals are less than 80 dB below the fundamental, troubleshoot the A15, A20, and A30 Assemblies before troubleshooting distortion on the A10 Assembly.
- 4. Reconnect cable W15 to connector A1511.

5.	Set	the	-hp-3561A	controls	as	follows:

- 6. Connect a 50Ω termination to A10J300 through a BNC to SMB adapter cable.
- 7. Using a clip lead or a shielded connector, input a 1 kHz, 76 mVrms (±5%) sine wave to the AMP3 test point. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the circuits between the AMP3 test point and A10J200 are operating correctly.
- 8. Set the -hp-3561A controls as follows:

RANGE36 dBV

- 9. Using a clip lead or a shielded connector, input a 1 kHz, 127 mVrms (\pm 5%) sine wave to the AMP2 test point. If all harmonics are greater than 80 dB below the carrier, the circuits between the AMP2 test point and A10J200 are operating correctly.
- 10. Set the -hp-3561A controls as follows:

- 11. Using a clip lead or a shielded connector, input a 1 kHz, 169 mVrms ($\pm 5\%$) sine wave to the AMP1 test point. If all harmonics are greater than 80 dB below the 1 kHz fundamental, the circuits between the AMP1 test point and A10J200 are operating correctly.
- 12. Move test jumper A10W100 back to NORM position, and reconnect cable W15 to connector A15J1.

[K] A-WEIGHT FILTER

To check the A-Weight Filter for proper operation, connect the -hp-3561A noise source output to the -hp-3561A input connector and set the -hp-3561A controls as follows:

PRESET

WINDOW UNIFORM

SOURCE PERIODIC NOISE

DEFINE ATTEN 0 dB

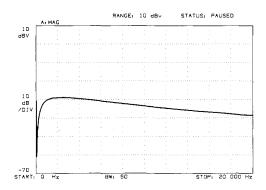
FREQuency DEFINE SPAN20 kHz

INPUT..... A WT FLT ON

FORMAT SINGLE

Check the frequency response by varying the -hp-3561A frequency span. To check for distortion or noise, input a sine wave rather than the noise signal to the -hp-3561A. Table 7-3 lists the A-Weight Filter gain for various frequencies.

Figure 7-2 A-Weight Filter Response



[A] 4 mA CURRENT SOURCE

To check the 4 mA ICP Current Source for proper operation, terminate the -hp-3561A input port with a 50Ω load and set the -hp-3561A controls as follows:

PRESET INPUT..... ICP CURR ON

Use a digital voltmeter to check the voltage across the 50Ω load for approximately .2 Vdc. If the voltage is incorrect, check the +24 V power supply and the current source circuitry.

[Q] Trigger Level DAC

The output of the trigger level DAC may be monitored at the TRG test point. To troubleshoot the DAC, set the -hp-3561A controls as follows:

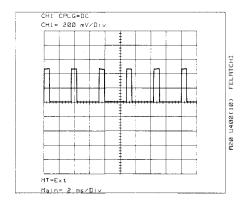
The DAC output should be 1.29 \pm .13 Vdc. Vary the % of range selected and check the corresponding DAC output voltage (eg. a trigger level of 50 % of range will result in a .645 Vdc output).

[N] Digital Control Input and Isolation, [P] Front End Control Register

To check the these circuits, select self test 110 as follows, and check the waveforms shown in Figure 7-3.

PRESET	
MODE	TEST SELECTDEFINE TEST NUM110 ENTER
	START CONT TEST

Figure 7-3 Front End Control Register Waveforms

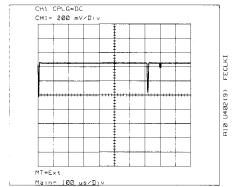




Ch1: Connection- A10 U400(10) "FELATCHI" Coupling- dc Ground- Center Graticule

Trigger: External- A20 J200(5) Slope: Positive

Bandwidth Limit: OFF



Probe: 10:1

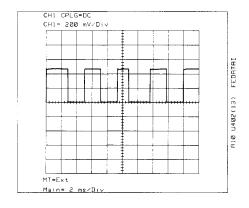
Ch1: Connection- A10 U402(9) "FECLKI"

Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1
Slope: Negitive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A10 U402(13) "FEDATAI"

Coupling- dc

Ground- Center Graticule

Trigger: External- A20 J200(5) Slope: Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection-

This waveform is available at any of the following connection points. The waveform will be shifted in time relative to the external trigger at each different connection point.

U401(4,5,6,7,11,12,13,14) U201(4,5,6,7,11,12,13,14) U105(4,5,6,7,11,12,13,14) U107(4,5,6,7,11,12,13,14)

Coupling- dc

Ground- Center Graticule

Trigger: External- A20 J200(5) Slope: Positive

Bandwidth Limit: OFF

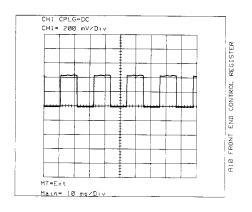


Table 7-6 A10 Assembly Signal Connections

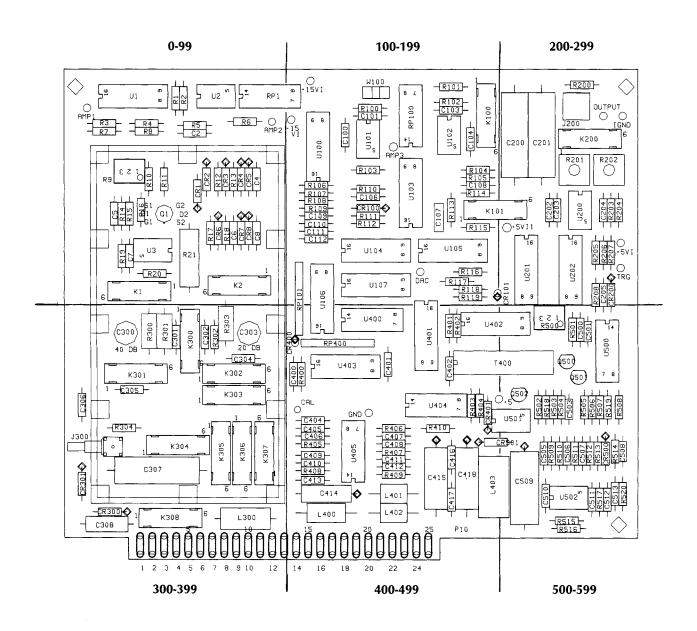
INPUTS

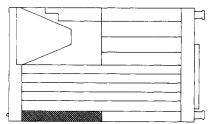
Signal Name	Functional Block	Connector Number	Origin Assembly
FE CAL	N	P10(A15)	A20
FECLOCK	N	P10(A16)	A20
FEDATA	N	P10(B16)	A20
FELATCH	N	P10(B15)	A20
INPUT	A	J10	Front panel
+24 V	A	P10(A11)	A99

OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assemblies
COMP OUT	M	P10(B25)	A15
FECLK	Р	P10(A24)	A15
FEDATA	Р	P10(A25)	A15
FEISO	Α	A99 J11	A20
FELATCH	P	P10(A23)	A15
SIGNAL OUT	K	J200	A15

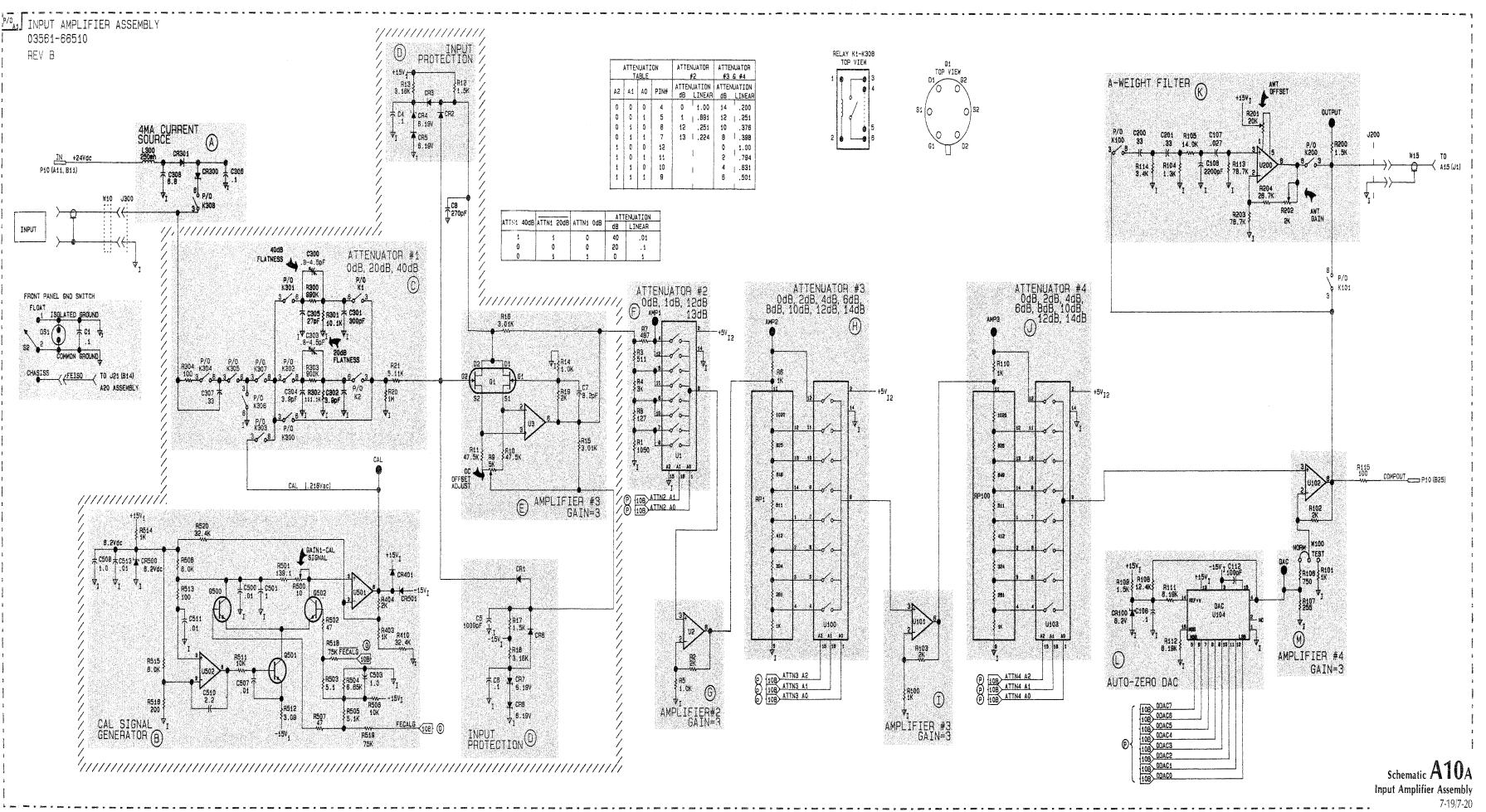
Service

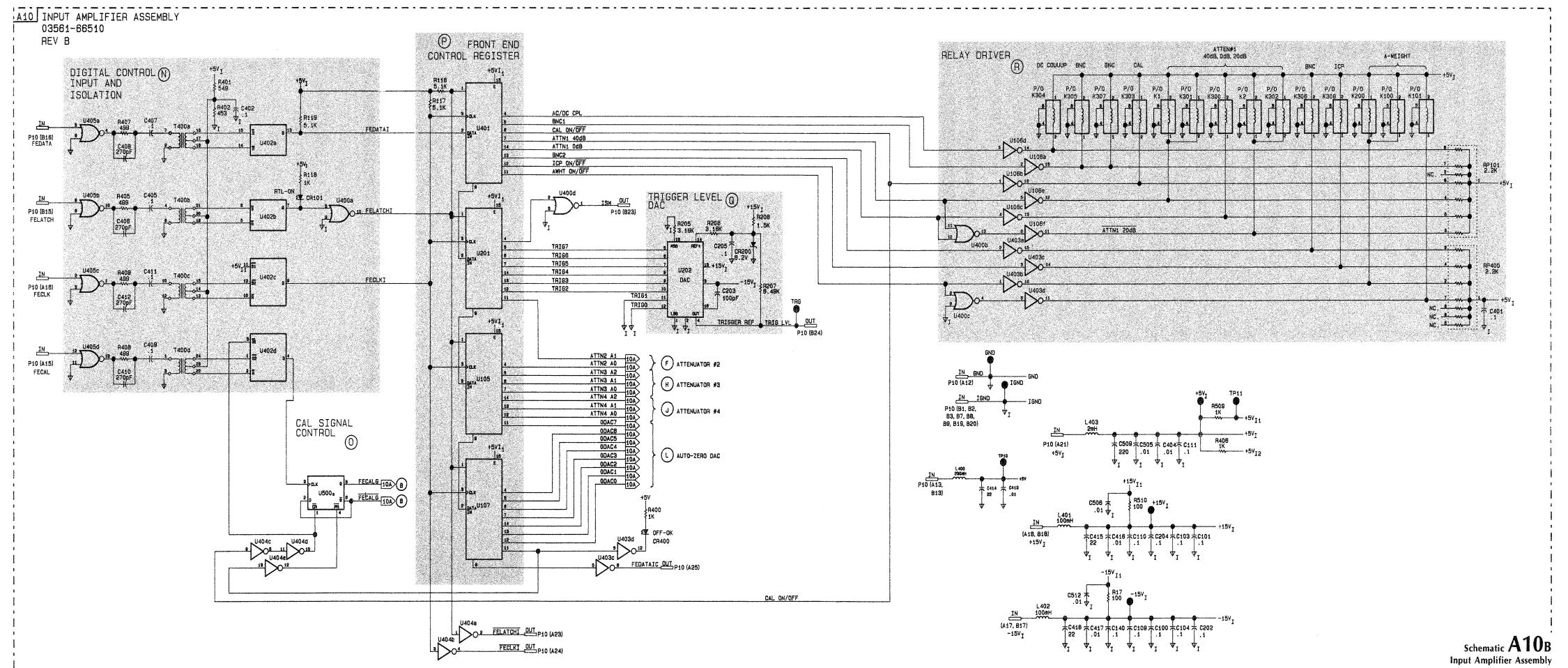




A10 Assembly

							***************************************		By-Pass
	+15V ₁	+15V ₁₁	-15V ₁	-15V ₁₁	+5V _i	GNDI	+57	GND	Capacitors
U1	13		3						C110, C109
U2	7		4					}	
U3	7		. 4						C101, C100
U100	13		3						C103, C104
U101	7		4						
U102	7		4						C202
U103	13		3						
U104	13		3					ľ	
U105					16	8			
U106					9	8			
U107					-16	8			
U200	7]	4						C204
U201					16	8		<u> </u>	
U202	13		3						
U400					14	7			
U401					16	8			
U402					16	8			
U403					9	8			
U403					14	7			
U405	1						14	7	
U500					14	7			
U501	7		4						
U502		7		4					





7-7 A15 DIGITIZER ASSEMBLY

7-8 Digitizer Circuit Description

GENERAL

The A15 Assembly uses a "two-pass residue" type A/D converter to digitize the analog input signal into a 13 bit digital output. A track and hold circuit samples the input signal and holds it long enough for the analog to digital conversion to take place. In addition the A15 Assembly contains a 100 kHz low-pass filter to attenuate higher frequency signals which may interact with the measurement. Other circuits on the assembly include the over-range and half-range comparators, the trigger level comparators, a test register, and a ground isolation interface.

Figure 7-4 gives a timing diagram of the complete analog to digital conversion process. The heart of the A15 Assembly digitizer is a single chip, 8 bit A/D converter which will be referred to as the "8 bit ADC". Each complete analog to digital conversion consists of two passes of data through the 8 bit ADC. In the first pass, the track and hold output signal is input to the 8 bit ADC. The result of the first pass conversion is an 8 bit digital approximation to the analog track and hold output. The timing and control circuit then transfers this 8 bit digital signal to the second pass input circuit. In the second pass, the result of the first pass conversion is converted back into an analog signal and subtracted from the analog track and hold output, resulting in a signal that is equal to the error between the first pass 8 bit approximation and the track and hold output. This error signal is multiplied by 32 and input to the 8 bit ADC. The second pass conversion is then scaled back down by 32 and added to the first pass conversion to obtain a final 13 bit digital result.

Between each conversion, the 8 bit ADC is reset by passing a fixed dc voltage of .34 volts through it. The dc voltage is derived from the the 6.2 volt reference and is selected by the ADC input switch.

[A] 100 kHz LOW PASS FILTER

The 100 kHz low pass filter is a 4 stage filter with a gain of 0.557 and zeros at 371 kHz, 166 kHz, 151 kHz, and 214 kHz.

[F] TIMING CONTROL ISOLATION INTERFACE, [N] DATA OUTPUT ISOLATION INTERFACE, [T] STATUS ISOLATION INTERFACE, [U] TRIGGER ISOLATION INTERFACE

The isolation interface circuits use transformer coupling to isolate the floating ground from the chassis ground. Move the -hp-3561A front panel ground switch to the CHASSIS position to short the two grounds together. All of the transformer coupled interfaces are non-inverting.

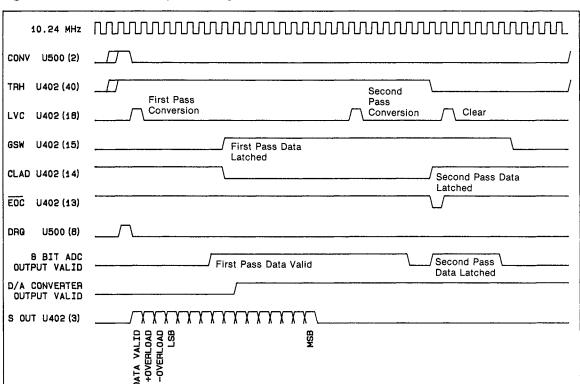


Figure 7-4 A/D Converter Signal Timing

[G] TRACK AND HOLD

The track and hold circuit is controlled by the TRH signal generated in the ADC timing and control circuit. When the TRH signal is high, this circuit is an inverting unity gain amplifier. When the TRH signal goes low, the track and hold circuit samples the input signal and holds the sampled value until the TRH signal goes high again. The track and hold circuit samples the input data at a 256 kHz rate.

[H] SECOND PASS ADC INPUT

The Second Pass ADC input circuit consists of a 13 bit D/A converter, and a summing amplifier. The D/A converter outputs an analog signal which is equal to the first pass 8 bit ADC conversion. This signal is then subtracted from the actual track and hold output signal in U205 resulting in a signal which is equal to the error between the first pass 8 bit digital approximation, and the actual track and hold output. This error signal is multiplied by 32 and then input to the 8 bit ADC for the second pass conversion.

[I] TEST REGISTER

The test register is an extension of the front end control register on the A10 Assembly. The FEDATAIC signal is clocked into the register with the FECLKI signal. When the register is full the FELATCHI signal latches the data. The test register output programs the ADC timing and control circuit.

[K] A/D INPUT SWITCH

The A/D input switch selects which signal will be input to the 8 bit ADC. The GSW and CALD signals generated in the A/D timing and control circuit control the position of the ADC input switch as shown in Table 7-7.

GSW	CLAD	Input Selected	
1	o	Second Pass Input	
1	1 .34 Vdc Reference		
0	0	0 First Pass Input	
0	1	First Pass Input	

Table 7-7 ADC input Switch Control

[L] A/D TIMING AND CONTROL

The A/D timing and control circuit performs four major functions. First, the A/D timing and control circuit generates the control signals which coordinate the two passes of data through the 8 bit ADC, and control the track and hold circuit. Second, it transfers the first pass 8 bit ADC output to the D/A converter in the second pass input circuit. Third, it divides the second pass 8 bit ADC output by 32 and adds the result to the first pass 8 bit ADC output to obtain a final 13 bit result. Finally, the timing and control circuit transfers the 13 bit digital data to the digital filters on the A20 Assembly.

The digital filter on the A20 Assembly controls the A/D converter through the CONV and DRQ signals. The CONV signal is used to initiate an A/D conversion, and the DRQ signal is used to request the resultant data. Data is transferred to the digital filter with every DRQ, however, if the A/D conversion is not yet complete, the data will be invalid. The digital filter reads the DATA VALID bit of the transferred data to determine whether it should use the data or request the data again by sending another DRQ.

To improve the linearity of the A/D converter, the timing and control circuit adds 5 bits of noise to the first pass result, and then subtracts this noise back out of the second pass results.

[O] ANALOG TO DIGITAL CONVERTER (8 BIT ADC)

This circuit is a single chip 8 bit A/D converter. An analog to digital conversion is initiated on the rising edge of the LCV signal and data is valid 600 nSec later. The 8 bit ADC has an operating range of +0 volts to -1.0 volts.

[P] OVER-RANGE/HALF-RANGE

This circuit compares the input signal to a fixed voltage reference to generate the overload (OVLD), and half-range (6dB+,6dB-) signals. Comparator outputs are high when tripped by a fault condition.

Table 7-8 A15 Assembly Signal Descriptions

Signal	Description
CLAD	CLear 8 bit ADC: Selects a .34 Vdc signal as the input to the 8 bit ADC between the first and second pass conversions to clear the 8 bit ADC.
СОМР	COMPare input: Identical to the main signal input from the A10 Assembly. This signal is used to generate HALFR, OVERR, and FETRIG.
CONV	CONVert: This signal initiates the two pass A/D conversion process.
DATAOUT	DATA OUTput: 13 bit serial data transferred to the digital filter LSB leading plus two bits to indicate overloads, and one bit to indicate data valid.
DRQ	Data ReQuest: Tells the A/D converter that the digital filter on the A20 Assembly is ready for new data.
EOC	End Of Conversion: Signifies that the two pass A/D conversion is complete.
FECLKI	Front End CLOCK: Clocks the FEDATA signal into the test register.
FEDATAIC	Front End DATA: Serial data which, when latched into the test register, programs the A/D timing and control circuit.
FELATCHI	Front End LATCH: Latches the FEDATA signal in the test register.
FETRIG	Front End TRIGger: Triggers a measurement when the instrument is in the input trigger mode.
GSW	Gate SWitch: Goes low to select the first pass ADC input circuit and goes high to select the second pass ADC input circuit.
HALFR	HALF-Range: Goes high when the input is more than 6 dB below the range setting.
LCV	Local ConVert: Initiates an A/D conversion in the 8 bit ADC. Two 8 bit ADC conversions and one clear are needed for each complete A/D conversion.
OVERR	OVER-Range: Goes high when the input signal is greater than 2.8 dB above the range setting.
OFERQ	Over-FREQuency: Goes high when the external sample frequency is greater than 256 kHz.
SSTAT	Serial STATus: Serial data which outputs the status of the HALFR, OVERR, OFREQ, and FEDATA signals to the digital filter.
TRH	TRack/Hold: Goes high to place the track and hold circuit in the track mode and low to place the track and hold circuit in hold mode.
TRIG LVL	TRIGger LeVeL: Sets the trigger level for the input trigger.

[R] STATUS LATCH

Three status bits are generated for each A/D data output, half-range (HALFR), over-range (OVERR), and over-frequency (OFREQ). HALFR is high when the input signal is between 0dB and 6dB below the range setting, and OVERR is high when the input

signal is greater than 2.8 dB over the range setting. OFREQ is high when the external sample frequency is greater 256 kHz. In addition, the status word contains one bit of the FEDATA signal. This allows the processor to read the front end programming data to verify proper programming. The status data is transferred to the digital filter when a data request (DRQ) signal is received.

[S] TRIGGER LEVEL COMPARATOR

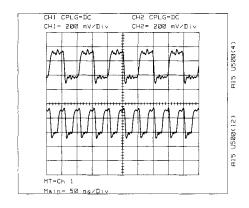
This circuit compares the input signal to the trigger level signal generated on the A10 Assembly. When the input signal exceeds the trigger level signal, the comparator output goes low. A trigger level of 100 % of range results in a 1.29 Vdc \pm .12 Vdc signal at the TRIG LEV test point.

7-9 Troubleshooting the Digitizer

GENERAL

Troubleshooting the A15 Assembly should be performed in two steps: analog troubleshooting and digital troubleshooting. The primary method for troubleshooting the analog circuitry is to input a sine wave into A15J1 and then check the signal at each of the analog circuit blocks. The primary method for troubleshooting the digital circuitry is to check the control signals against the timing diagram given in Figure 7-4. Move the front panel ground switch to the CHASSIS position and verify the 20.48 MHz and 10.24 MHz clocks shown in Figure 7-5 before troubleshooting this assembly.

Figure 7-5 A15 Assembly Clock Waveforms



Probe: 10:1

Ch1: Connection: A15U500(4) 10.24 MHz Coupling- dc Ground- Third Graticule From Top

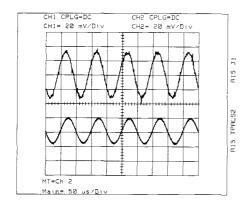
Ch2: Connection- A15U500(12) 20.48 MHz Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth limit: ON

Figure 7-6 A15 Assembly Analog Waveforms in Test 115



Probe: 10:1

Ch1: Connection: A15J1

 $(.23 \pm .01 \text{ Vrms})$

Coupling- dc

Ground- Third Graticule From Top

Ch2: Connection- A15TP"ALS2"

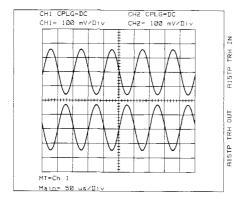
 $(.135 \pm .006 \text{ Vrms})$

Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal- Ch2 Slope- Negative

Bandwidth limit: ON



Probe: 10:1

Ch1: Connection- A15TP"TRH IN"

(1.1 Vrms)

Coupling- dc

Ground- Third Graticule From Top

Ch2: Connection- A15TP"TRH OUT"

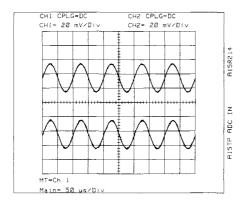
(1.1 Vrms)

Coupling- dc

Ground-Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A15 R214

 $(.14 \pm .01 \text{ Vrms})$

 ${\sf Coupling-}\ dc$

Ground- Second Graticule From Top

Ch2: Connection- A15TP"ADC IN"

 $(.14 \pm .01 \text{ Vrms})$

Coupling- dc

Ground- Fourth Graticule From Bottom

Trigger:- Internal- Ch1

Slope- Positive

Bandwidth Limit: ON

[A] 100 kHz LOW PASS FILTER, [B] X3 AMPLIFIER, [C] 482 kHz LOW PASS FILTER, [D] X3 AMPLIFIER, [G] TRACK AND HOLD, [H] SECOND PASS ADC INPUT, [M] ADC INPUT BUFFER

To check these circuits, set the -hp-3561A controls as follows:

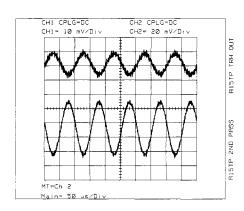
DDECET

PRESEI		
RANGE	DEFINE RANGE 0 dBV	1
MODE	TEST SELECTDEFINE TST NUM115 ENTER	
	START SNGL TST	

In this test the TRH signal is held low, causing the track and hold circuit to operate as a unity gain inverting amplifier. In addition, Test 115 programs the ADC input switch to select the first pass ADC input circuit as the input path to the 8 bit ADC.

- 1. Remove cable W15 from A15J1. Use the frequency synthesizer and a BNC to SMB adapter cable to input a .228 Vrms, 11 kHz sine wave into A15J1. Terminate the frequency synthesizer with 50 Ω .
- 2. Verify the waveforms shown in Figure 7-6. The signals shown in the figure are listed in the order of signal flow.
- 3. If all the signals in Figure 7-6 are correct, reduce the amplitude of the input sine wave to 10 mVrms, and verify the signals as shown in Figure 7-7. In Test 115, the output of the D/A converter (U102) is set to zero.

Figure 7-7 Second Pass ADC Input Waveforms in Test 115



Probe: 10:1

Ch1: Connection- A15TP"TRH OUT"
(15 ±1 mVrms)
Coupling- dc
Ground- Second Graticule From Top

Ch2: Connection- A15TP"2ND PASS" (55 ± 3 mVrms) Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch2 Slope- Positive

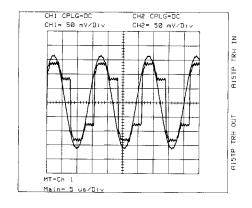
Bandwidth Limit: OFF

[G] TRACK AND HOLD

To check the track and hold circuit for proper operation, press the -hp-3561A PRESET key. When the preset is complete, use a frequency synthesizer, and a BNC to SMB adapter cable to input a 64 kHz, .228 Vrms sine wave into A15J1. Terminate the frequency synthesizer with 50 Ω . Check the TRH IN and TRH OUT test points for

the waveforms shown in Figure 7-8 to verify that the track and hold circuit is sampling the sine wave. Check for excessive DC offset or overshoot of the sampled signal. If there appears to be a problem in the track and hold output signal, check the TRH and FETG signals for the waveforms shown in Figure 7-8.

Figure 7-8 Track and Hold Waveforms



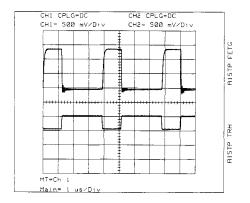
Probe: 10:1

Ch1: Connection- A15TP"TRH IN" Coupling- dc Ground- Center Graticule

Ch2: Connection- A15TP"TRH OUT" Coupling- dc Ground- Center Graticule Invert Ch2

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A15TP"FETG"
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A15TP"TRH"

Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Positive

NOTE

Adjust the frequency of the frequency synthesizer to within .5 Hz of 64 kHz to stabilize the waveform.

TROUBLESHOOTING DISTORTION

Distortion may be isolated to either the 100 kHz filter and X3 amplifiers, or the track and hold and A/D converter circuits. Use a low distortion oscillator, which meets the required characteristics listed in Table 1-5, when making any distortion or noise measurements.

1. Press the -hp-3561A PRESET key. When the preset is complete, use the low distortion oscillator and a BNC to SMB adapter cable to input an 11 kHz, 0.228 Vrms sine wave into A15J1. Terminate the low distortion oscillator in 600 Ω . If any of the harmonics are less than 80 dB below the 11 kHz fundamental, proceed with step 2.

2. Remove jumper J100 on the A15 Assembly, and input a 11 kHz, 1.14 Vrms (1.61 Vpeak) sine wave into the TRH IN test point. This removes circuit blocks A through D from the signal path.

If any of the harmonics are less than 80 dB below the 10 kHz fundamental, the distortion failure is most likely in the track and hold circuit or the A/D converter.

If all of the harmonics are now greater than 80 dB below the 10 kHz fundamental, the distortion failure is most likely in the 100 kHz low pass filter or the X3 amplifiers.

[F] TIMING AND CONTROL ISOLATION INTERFACE, [L] ADC TIMING AND CONTROL

To check these circuits, press the -hp-3561A PRESET key, and verify the control signals as shown in Figure 7-4.

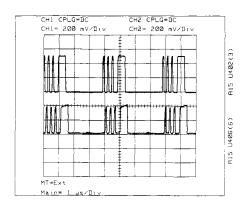
[N] DATA OUTPUT ISOLATION INTERFACE

To check this circuit, set the -hp-3561A controls as follows:

PRESET	
RANGE	DEFINE RANGE 0 dBV
MODE	TEST SELECTDEFINE TEST NUM112 ENTER
	START SNGL TST

In this test, the timing and control circuit outputs a test pattern as shown in Figure 7-9.

Figure 7-9 Test pattern Output in Test 112



Probe: 10:1

Ch1: Connection- A15U402(3)

Coupling- dc

Ground- Fourth Graticule From Top

Ch2: Connection- A15U406(6)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: External- A15TP"DRQ" Slope- Positive

Bandwidth Limit: ON

BREAKING THE SECOND PASS FEEDBACK LOOP

Test 113 is provided to isolate failures to either the first pass circuit or the second pass circuit. To initiate this test, set the -hp-3561A controls as follows:

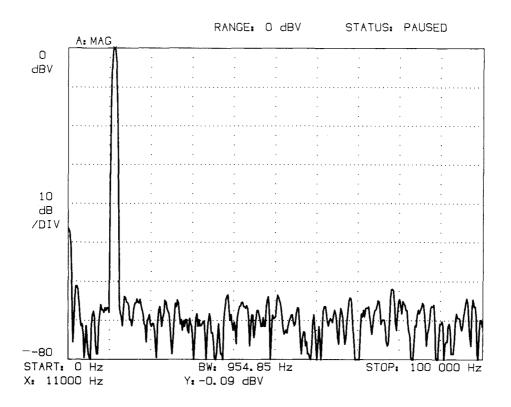
PRESET	
FORMAT	SINGLE
RANGE	DEFINE RANGE 0 dBV
MODE	TEST SELECTDEFINE TEST NUM113 ENTER
	START SNGL TST

When the "TEST #113 IS COMPLETE" message is displayed, press the MODE key. In this test, data is not passed through the second pass ADC input circuit, thus, if a failure appears, it is most likely in the 8 bit ADC, or the timing and control circuit. Use the frequency synthesizer and a BNC to SMB adapter cable to input an 11 kHz, .228 Vrms sine wave into A15J1. Terminate the frequency synthesizer in 50 Ω . Check the -hp-3561A display for a full scale sine wave as shown in Figure 7-10.

NOTE

Because the second pass circuit is not operating, noise and harmonics will be 50 to 70 dB below the amplitude of the 11 kHz fundamental. The test is failing if either the noise or harmonics are less than 50 dB below the fundamental.

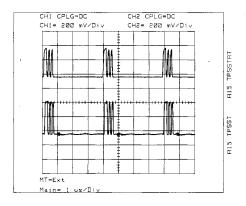
Figure 7-10 -hp-3561A Display in Test 113



[R] Status Latch, [T] Status Isolation Interface

To check these circuits, press the -hp-3561A PRESET key, disconnect the input signal, and verify the waveforms shown in Figure 7-11.

Figure 7-11 A15 Status Output



Probe: 10:1

Ch1: Connection: A15TP"SST" Coupling- dc Ground- Third Graticule From Top

Ch2: Connection: A15TP"SSTAT" Coupling- dc Ground- Third Graticule From Bottom

Trigger: External- A15TP"DRQ" Slope-Positive

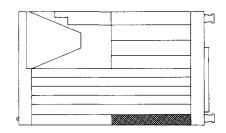
Table 7-9 A15 Assembly Signal Connections

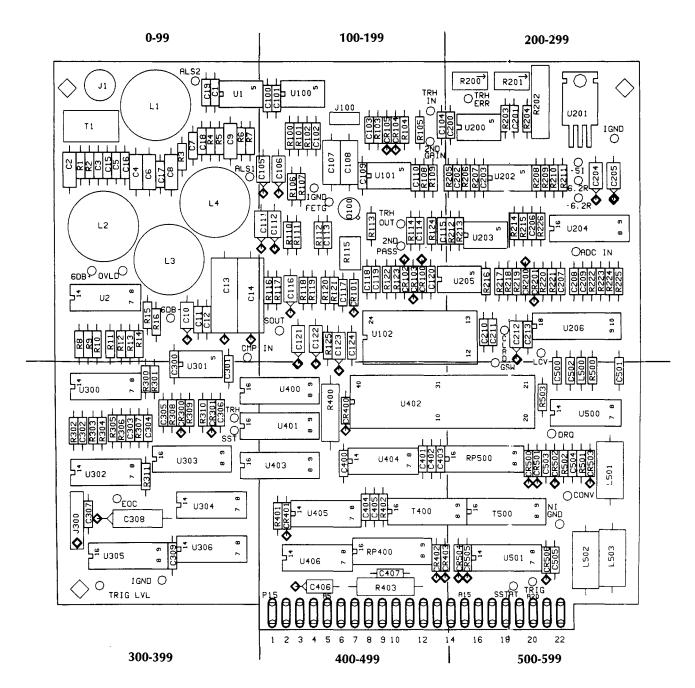
INPUTS

Signal Name	Functional Block	Connector Number	Origin Assembly
COMP	Q	P15(B1)	A10
CONVERT	F	P15(B16)	A20
DATA REQ	F	P15(B14)	A20
FECLOCK	ı	P15(A2)	A10
FEDATA	ı	P15(A1)	A10
FELATCH	I	P15(A3)	A10
ISM	L	P15(A6)	A20
SIGNAL INPUT	A	J1	A10
TRIGLVL	S	P15(B2)	A10
10 MHz	F	P15(A15)	A20
20 MHz	F	P15(B15)	A40

OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assemblies	
SSTAT	Т	P15(A14)	A20	
FETRIG U		P15(A13)	A20	
A/D DATA	N	P15(B13)	A20	

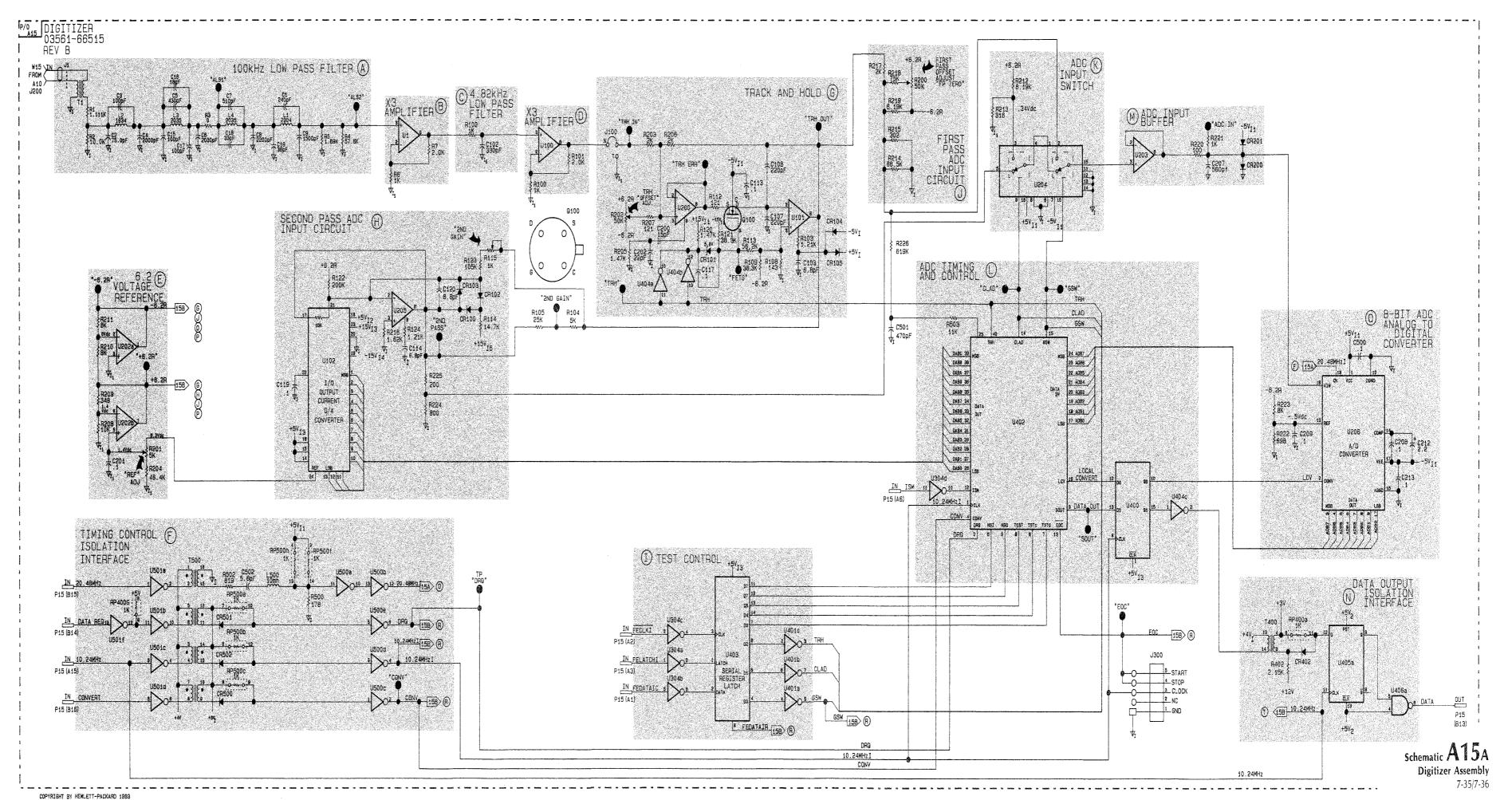


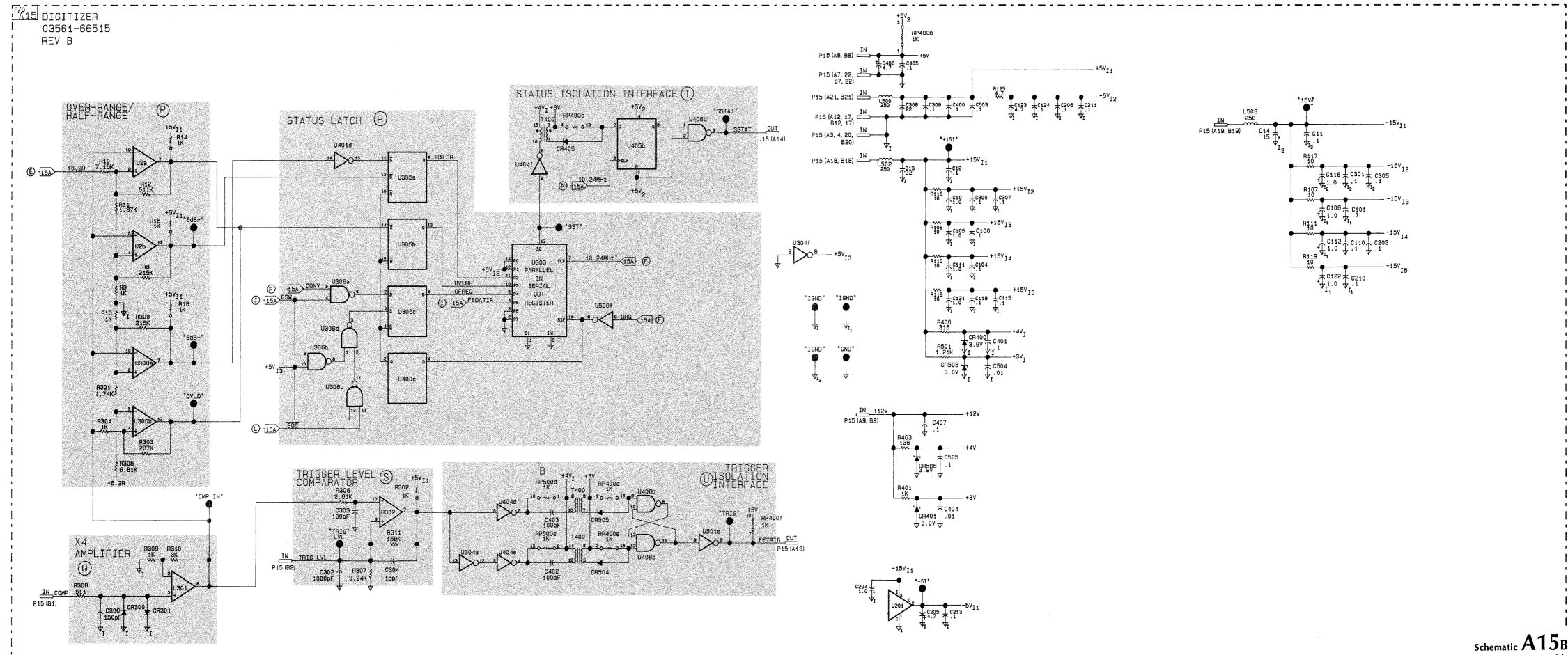


A15 Assembly

	+15V ₁₂	+15V ₁₃	+15V ₁₄	+15V ₁₅	-15V ₁₂	-15V ₁₃	-15V ₁₄	-15V ₁₅	+5V ₁	+ 5V ₁₂	-5V ₁	GNDI
U1		7				4						
U2	11				6							
U100		7				4						
U101	7						4					
U102				23				19			18	
U200			7				4					
U201												
U202				8				4		1		
U203				7				4		1		
U204										7	16	
U205				7				4				
U206									1	17		
U300	11				6							
U301	7				4							
U302	11				6							
U303									16			8
U304									14			7
U305									16			8
U306									14			7
U400									16			8
U401									16			8
U402									30			10
U403									16			8
U404									14			7
U500									14			7

	+ 5	GND
U405	14	7
U406	14	7
U501	14	7





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chematic A15B Digitizer Assembly 7-37/7-38

7-10 A20 DIGITAL FILTER ASSEMBLY

7-11 Digital Filter Circuit Description

GENERAL

The primary purpose of the digital filter is to provide anti-alias filtering when the -hp-3561A frequency span is less than 100 kHz. The digital filter receives input data from the A/D converter, it then processes the data and stores the results directly into the instrument RAM. Other circuits on the A20 Assembly include the timing and control counter, the A/D converter interface, and the direct memory access (DMA) counters which interface the digital filter with the instrument RAM.

DIGITAL FILTER CHANNEL DESCRIPTIONS

The digital filter can store output data into two independent 1024 data point buffers in RAM, channel R, and channel G. Addressing is accomplished through the channel R and channel G direct memory access (DMA) counters. Each channel is set to one of three data modes. The data mode for a channel defines what type of data is transferred from the digital filter into RAM on that channel. In mode one, the digital filter outputs "real part" data (filtered by U1 only); in mode two, the digital filter outputs "imaginary part" data (filtered by U401 only); and in mode three, the digital filter outputs unfiltered A/D data directly. More than one type of data can be stored in a channel at the same time (e.g., in zoom mode, 512 real part and 512 imaginary part data samples are stored in channel G). Table 7-10 lists the data mode settings for each -hp-3561A measurement mode.

[B] CHANNEL R DMA COUNTER, [D] CHANNEL R ADDRESS BUS LATCH

The output of this counter defines the address in RAM where channel R data is stored. The channel R bus grant signal latches the counter output onto the RAM address bus, and increments the counter by one. The channel R counter clocks through 1024 positions and then issues a DONER signal to indicate that the channel R buffer in RAM has been filled and is ready to be processed by the FFT processor.

[C] CHANNEL G DMA COUNTER, [E] CHANNEL G ADDRESS BUS LATCH [L] CHANNEL G COUNTER PRESET

The output of this counter defines the address in RAM where channel G data is stored. The channel G bus grant signal latches the counter output onto the RAM address bus and increments the counter by one. The channel G DMA counter clocks through up to 40,960 positions before a DONEG signal is issued. The exact number is programmed by the central processor through the channel G preset circuit.

[H] DMA CONTROL LATCH, [J] DMA CHANNEL CONTROL

Through this register, the central processor programs the data mode for channel R and channel G, the number of counts for the channel G DMA counter, the trigger state, and the digital filter test mode. On the falling edge of the DIS1-3 signals, the digital filter processes one time record (1024 data points).

[I] RAM BUS INTERFACE, [K] DMA CHANNEL SELECT

The digital filter issues a RAM bus request whenever it is ready to store a data point in RAM. The particular bus request issued depends on the data mode the digital filter is operating in. When the digital filter receives a bus grant from RAM, the DMA channel select circuit issues a bus grant to the selected DMA counter, which then transfers the data onto the RAM data bus.

[M] DIGITAL FILTER

The digital filter consists of three integrated circuits, U1, U4, and U401. The actual digital filtering occurs in U1 and U401, which are identical and interchangable. The digital filter control circuit, U4, is primarily an interface and data selector. The digital filter receives three data inputs: A/D DATA and the local oscillator inputs, COSINE, and -SINE. The local oscillator inputs which are only active during zoom operation are multiplied with the A/D DATA signal within the digital filter. The digital filter control circuit, based on the -hp-3561A front panel settings, selects the type of data (mode one, mode two or mode three) which is output to the RAM data bus. Table 7-10 lists which digital filter ICs are active in each -hp-3561A measurement mode.

Table 7-10 Digital Filter Operation

-hp-3561 Front Panel Setting	Digital Filter Circuits in Use	Channel G Data Mode	Channel R Data Mode
Baseband -Magnitude -Phase -Time	U4, U1	1	not used
Zoom -Magnitude -Phase -Time	U4, U1, U401	1	not used
Third Octave	U4, U1, U401	1	2
Full Octave	U4, U1, U401	1	2
Input Time	U4	not used	3
Input Magnitude	U4	not used	3

[O] A/D STATUS LATCH, [Q] DATA REQUEST/SYNC2 SIGNAL GENERATOR [U] DIGITAL FILTER INPUT DATA LATCH

These circuits comprise the A/D converter and local oscillator interface. To initiate an A/D data transfer, the digital filter issues a SHIFT1 signal which triggers a DATA REQ signal. On receipt of a DATA REQ signal, the A/D converter transfers one 13 bit data sample into the digital filter through the digital filter input data latch, and one 4 bit status word into the digital filter through the A/D status latch. If the A/D does not yet have a new data sample, it will transfer invalid data. The digital filter reads the first bit of the A/D data to determine if the data is valid. If the data is invalid, the digital filter will continue to request data at a 512 kHz rate. When valid data is received, the digital filter will continue to request new data samples at a 256 kHz rate.

For each valid A/D data sample received, the digital filter issues a SYNC2 signal, which is a data request to the local oscillator. On receipt of a SYNC2 signal, the local oscillator transfers one 16 bit COSINE value and one 16 bit -SINE value to the digital filter.

[P] CONVERT SIGNAL TIMING, [T] CONVERT SIGNAL SELECT

The CONVERT signal establishes the sampling rate of the -hp-3561A. On receipt of a CONVERT signal, the A/D converter samples the input data and initiates an A/D conversion. In internal sample mode, the DATA REQ signal is selected to trigger a CONVERT pulse and in external sample mode, the rear panel "EXT SAMP" input is selected to trigger a CONVERT pulse.

[Y] TIMING AND CONTROL COUNTER, [X] COUNTER CLOCK SELECT [V] TRIGGER TIMING, [W] PHASE COUNTER CLOCK

All of these circuits provide inputs to the multi-function counter, U202. The multi-function counter contains six counters which can each be programmed to use any one of the four clock inputs. The central processor programs the multi-function counter to determine the timing relationship between the various activities within the -hp-3561A. It then uses this information to calculate phase corrections for the input signal.

[CC] CAL SIGNAL/TRIGGER CONTROL [EE] TRIGGER SELECT, [DD] CAL SIGNAL SELECT

Through these circuits, the central processor programs the correct trigger and calibration signal for the current front panel setting. The resulting trigger signal, NSTRIG, is syncronized to the internal 10.24 MHz clock in the trigger timing circuit, and used to trigger a measurement.

Table 7-11 A20 Assembly Signal Descriptions

Signal	Description
BGG	RAM Bus Grant channel G: Clocks the channel G DMA counter output onto the RAM address bus and increments the counter by one.
BGR	RAM Bus Grant channel R: Clocks the channel R DMA counter output onto the RAM address bus and increments the counter by one.
BREN	Bus Request ENable: Enables the channel G bus request signal to be input to the multi-function counter.
CAL GEN	CALibration signal GENerator: A square wave with a frequency programmed by the central processor (4 kHz when the front panel cal signal is selected).
CAL TRIG	CALibration signal TRIGger: Triggers a measurement at the start of the PRN cal signal.
CHGCNT	CHannel G CouNT: Used by the central processor to read the position of the channel G DMA counter over the RAM address bus.
CLRTRIG	CLeaR TRIGger: Clears the current instrument trigger state.
CONVERT	A/D CONVERT: Initiates a data sample in the A/D converter and establishes the instrument sample rate.
CTRRS	CounTeR Read Select: Used by the central processor to read data from the multi-function counter.
CTRWS	CounTeR Write Select: Used by the central processor to write programming data to the multi-function counter.
DATA REQ	A/D DATA REQuest: Causes the A/D converter to transfer its current data to the digital filter.
DF1BG DF2BG DF3BG	Digital Filter 1-3 Bus Grant: RAM bus grant for data mode one, two, or three.
DF1BR DF2BR DF3BR	Digital Filter 1-3 Bus Request: RAM bus request for data mode one, two, or three.
DFIS1	Digital Filter Input Status: Used by the processor to address the digital filter status word.
DFOS1 DFOS2 DFOS3	Digital Filter Data Strobe: Used by the processor to load data directly from the RAM data bus into the digital filter for processing (data mode one, two, or three).
DIS1 DIS2 DIS3	DISable data mode 1-3: Disables data mode one, two, or three in the digital filter.
DONEG	DONE with channel G count: Triggers a DMA interrupt to the central processor to indicate that the channel G RAM buffer is full.
DONER	DONE with channel R count: Triggers a DMA interrupt to the central processor to indicate that the channel R RAM buffer is full.
EXTSAMP	EXTernal SAMPle clock: Rear panel external sample input signal.
FECLK	Front End CLock: Clocks the FEDATA signal into the front end control register on the A10 Assembly.

Table 7-11 A20 Assembly Signal Descriptions (Cont'd)

Signal	Description		
FEDATA	Front End Data: Data to program the relays and other circuits on the A10 and A15 Assemblies.		
FECS	Front End Control Select: Clocks data into the front end control latch and the cal signal/trigger select circuits.		
FELATCH	Front End LATCH: Latches the front end data into the front end control register on the A10 Assembly.		
G0S, G1S	Channel G Data Mode Select: Data Mode G0S G1S Mode 1 0 0 Mode 2 0 1 Mode 3 1 0		
HALFR	HALF Range: Input Signal is between 0 dB and 6 dB below the range setting.		
OFREQ	Over FREQuency: External sample frequency is greater than 256 kHz.		
OVERR	OVER Range: Input signal is greater than 2.8 dB above the range setting.		
ROS, R1S	Channel R Data Mode Select: Data Mode R0S R1S Mode 1 0 0 Mode 2 0 1 Mode 3 1 0		
SETTRIG	SET TRIGger: Used by the processor to trigger a measurement when the -hp-3561A is set to internal trigger.		
SSTAT	A/D Serial STATus: 4 bit serial data which indicates the status of the current A/D DATA signal. SSTAT is transferred to the digital filter when a DATA REQ signal is received by the A/D converter.		
SYNC2	Issued by the digital filter to request data from the local oscillator.		

7-12 Troubleshooting the A20 Assembly

GENERAL

Troubleshoot the circuits on the A20 Assembly in the order given in Table 7-12. In this table, level one circuits must be operational before level two circuits can be tested, and so on. Table 7-13 list some failure symptoms and the most likely cause of the failure. In addition, Table 7-14 lists all of the return codes for diagnostic self tests 13, 14, and 18. With the return code is given an error description and the most likely cause of the error. For the return code descriptions to be accurate, the diagnostic self tests should be run in numerical order.

Table 7-12 A20 Troubleshooting Order

ocks: FF GG ocessor Address Decoder: F ocessor Data Latch: S H N CC
ocessor Data Latch: S H N CC
ounter Clocks and Cal Signal Generator: V X AA
ming and Control Counter: W Y Z DD EE
igital Filter and Channel R DMA Counter: B D I K M
MA Counters: C E G L
ONVERT Signal Timing: P Q T
i

Table 7-13 A20 Failure Symptoms

Symptom	Most Likely Cause of Failure	
Instrument operates incorrectly in Input Time or Input Magnitude measurements only.	B Channel R DMA Counter	
Instrument operates correctly in Input Time or Input Magnitude measurements only.	C Channel G DMA Counter Y Timing and Control Counter	
Instrument operates incorrectly in zoom mode only.	U4 or U401	

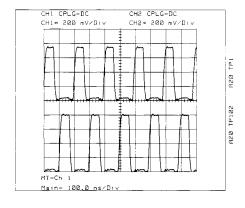
Table 7-14 A20 Diagnostic Test Return Code Descriptions

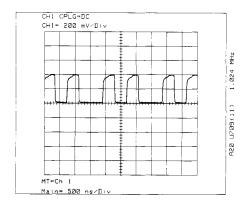
Return Code	Description	Most Likely Cause of Error	
13 1 00 through 13 1 05	The processor is unable to program the timing and control counter.	U202 or U600, U300	
13 6 00 through 13 6 02	The timing and control counter returns incorrect data.	U202 or X Counter Clock Select V Trigger Timing	
14 2 00 through 14 2 02	The channel R DMA counter has not requested a data transfer in the allotted time.	B Channel R DMA Counter K DMA Channel Select I RAM Bus Interface or U1, U4, U401	
14 2 03 through 14 2 10	The channel R DMA counter has not requested a data transfer in the allotted time.	U1 or U4: Odd numbered error code. U401 or U4: Even numbered error code.	
14 5 00 through 14 5 10	The digital filter indicates a data overload.	U1 or U4: Odd numbered error code, or error code 00. U401 or U4: Even numbered error code.	
14 6 00 through 14 6 02	Incorrect Data transferred to RAM.	B Channel R DMA Counter or U1, U4, U401	
14 6 03 through 14 6 10	Incorrect Data transferred to RAM.	U1 or U4: Odd numbered error code. U401 or U4: Even numbered error code	
14 2 11 14 5 11 14 6 11	Data Incorrect or overload in zoom mode only.	U4	
18 1 01 through 18 1 06	Timing and control counter error.	U202	
18 3 01 through 18 3 07 Y	Incorrect Trigger.	J DMA Channel Control W Phase Counter Clock Timing and Control Counter	
18 5 01	Digital filter indicates a data overload.	U1, U4, U401	
18 9 01 through 18 9 04 or 18 6 01 18 6 02	Channel G DMA address error.	C Channel G DMA counter E Channel G Address Bus	
18 8 00 through 18 8 15	Channel G DMA address error when using the channel G counter preset circuit.	E Channel G Address Bus L Channel G Counter Preset	

[FF] CLOCK GENERATOR, [GG] LOW FREQUENCY CLOCK GENERATOR

Verify the clock waveforms with the waveforms given in Figure 7-12. The other clock signals can be checked against the frequencies listed on the schematic.

Figure 7-12 A20 Clock Waveforms





Probe: 10:1

Ch1: Connection- A20 TP1 "DFCLKφ2"Coupling- dcGround- Center Graticule

Ch2: Connection- A20 TP102 "DFCLK ϕ 1" Coupling- dc Ground- Bottom Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A20 U709(11) "1.024 MHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[F] PROCESSOR I/O ADDRESS DECODING, [H] DMA CONTROL LATCH [N] DIGITAL FILTER DATA BUS LATCH, [S] FRONT END CONTROL LATCH [CC] CAL SIGNAL/TRIGGER CONTROL

- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Move jumper A40W1 on the A40 Assembly to the test position, and place the A20 Assembly on an extender board.
- 3. Turn the -hp-3561A LINE power switch ON.
- 4. When the "BLT TEST ROUTINE" message is displayed on the CRT screen, check the signatures given in Table 7-15.

NOTE

The A60 Assembly may be removed during this test to disable the beeper, however, this also disables the display so the "BLT TEST ROUTINE" message will not be displayed. The signatures will be valid when the front panel LEDs begin to blink.

Table 7-15 A20 Processor Interface Signatures

Signature Analyz	er Setup		
Signal	Polarity	Connection	
Clock	5	A20J200(3) "RIOS"	
Start		A40J100(5)	
Stop		A40J100(4)	
+5 V Signature - 1	H7PC		
Processor I/O Addi	ress Decoding	DMA Control Late	ch
U106(6)	1590	U501(2)	0 volts
		U501(5)	0 volts
U306(7)	400C	U501(6)	C829
U306(9)	P86U	U501(9)	C829
U306(10)	PHPP	U501(12)	32F5
U306(11)	571U	U501(15)	6UF2
U306(12)	F4H9	U501(16)	0 volts
U306(15)	8HFP	U501(19)	0 volts
U307(7)	5250	U506(2)	6UF2
U307(9)	4712	U506(5)	5H07
U307(12)	PH40	U506(6)	32F5
U307(13)	18CU	U506(9)	32F5
U307(14)	962P	U506(12)	P52P
U307(15)	C068	U506(15)	P52P
0307(13)	2000	U506(16)	5H07
Front End		U506(19)	32F5
Control Latch		0300(19)	3213
Control Editori		Cal Signal	
U510(2)	5A72	Trigger Control	
U510(5)	5C31	Trigger Control	
U510(6)	5C31	U509(2)	5C31
U510(9)	H6A8	U509(3)	8FHA
U510(12)	H6A8	U509(7)	8FHA
U510(15)	0143	U509(10)	0143
U510(16)	+5 volts	U509(15)	H6A8
U510(19)	8H99	0303(13)	110/10
Counter Data			
Bus Latch			
U600(11)	4746		
U600(12)	7PHA		
U600(13)	4746		
U600(14)	PCFU		
U600(15)	4746		
U600(16)	H253		
U600(17)	PCFU		
U600(18)	PCFU		
	·		

Table 7-15 A20 Processor Interface Signatures (Cont'd)

- ,	Setup:		
Signal	Polarity	Connection	
Clock		A20J200(3) "RIOS"	
Start	_	A40J100(5)	
Stop		A40J100(4)	
+5 V Signature	- H253		
Digital Filter Dat	a Bus Latch		
U400(2)	OPFP	U402(2)	U78H
` '	0PFP 0P41	U402(2) U402(3)	U78H 853F
U400(3)			- · · · · ·
U400(3) U400(4)	0P41	U402(3)	853F
U400(3)	0P41 4242	U402(3) U402(4)	853F FHU5
U400(3) U400(4) U400(5)	0P41 4242 8U1F	U402(3) U402(4) U402(5)	853F FHU5 U91F
U400(3) U400(4) U400(5) U400(6)	0P41 4242 8U1F 3A27	U402(3) U402(4) U402(5) U402(6)	853F FHU5 U91F 4UPA

[V] TRIGGER TIMING, [X] COUNTER CLOCK SELECT, [AA] PRN CAL SIGNAL GENERATOR

1. Set the -hp-3561A controls as follows:

PRESET

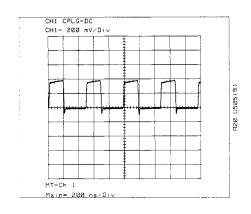
TRIGger SELect... TRIGGER

INTERNAL TRIGGER

INPUT..... CAL SIG ON

2. Check the waveforms as shown in Figure 7-13.

Figure 7-13 A20 Counter Clock Waveforms



Probe: 10:1

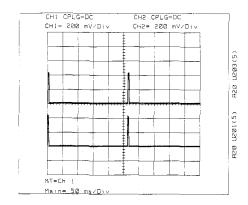
Ch1: Connection- A20 U505(9) "U202 Clock" A20 U300(3)

Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



CHI CPLG-DC
CH2 200 mV/Div
CH2= 200 mV/Div
CH2= 200 mV/Div

MT-Ch 1
Main= 5 us/Div

Probe: 10:1

Ch1: Connection- A20 U203(5) "ITRIG" Coupling- dc Ground- Center Graticule

Ch1: Connection- A20 U201(5) "ITRIG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

Note: the period of these signals alternates between 280 mSec, and 460 mSec.

Probe: 10:1

Ch1: Connection- A20 U507(12) "CAL TRIG" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20U304(5) "PRN CAL"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Negative

Bandwidth Limit: ON

[W] PHASE COUNTER CLOCK, [Y] TIMING AND CONTROL COUNTER, [Z] COUNTER DATA BUS LATCH, [DD] CAL SIGNAL SELECT, [EE] TRIGGER SELECT

1. Set the -hp-3561A Controls as follows:

PRESET

MODE TEST SELECT.....DEFINE TEST NUM.......121 ENTER START CONT TST

- 2. Check the waveforms as shown in Figure 7-14.
- 3. If all of the waveforms given in Figure 7-14 are correct, set the -hp-3561A controls as shown below to run Test 13. If Test 13 fails with one or more return codes, the failure is most likely in U202, U300, or U600.

PRESET

4. If Test 13 passes with no return codes, set the -hp-3561A controls as follows:

PRESET

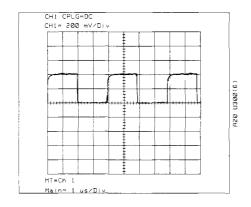
TRIGger SELect... TRIGGER

INTERNAL TRIGGER

INPUT..... CAL SIG ON

5. Check the waveforms given in Figure 7-15.

Figure 7-14 Test 121 Counter Input Waveforms

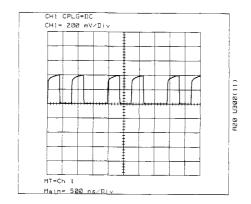


Probe: 10:1

Ch1: Connection- A20 U300(6) "PHASE CLK" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

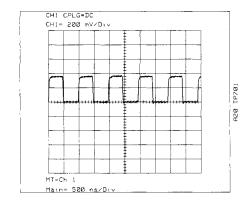
Ch1: Connection- A20 U300(11) "PHASE CLK" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Note: The waveform at U202(31) will be the "or" of these two signals gated on and off by the ITRIG signal. The signal at U202(31) can be checked by triggering on either U300(6) or U300(11).

Figure 7-15 A20 Counter Output Waveforms

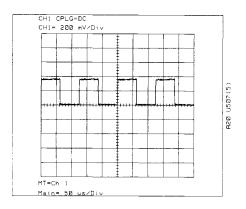


Probe: 10:1

Ch1: Connection- A20 TP701 "ESR*4" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A20 U507(5) "CAL GEN" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

[B] CHANNEL R DMA COUNTER, [D] CHANNEL R ADDRESS BUS LATCH [I] RAM BUS INTERFACE, [K] DMA CHANNEL SELECT, [M] DIGITAL FILTER

1. Set the -hp-3561A controls as follows:

PRESET

MODE123 ENTER

START CONT TST

- 2. Check the waveforms given in Figure 7-16. These waveforms depend on the proper operation of the RAM bus interface, the DMA channel select, and the digital filter control IC (U4).
- 3. When the waveforms given in Figure 7-16 are correct, check the waveforms given in Figure 7-17 and the signatures given Table 7-16 to troubleshoot the channel R DMA counters.

4. When the channel R DMA counter is operating correctly, Diagnostic Self Test #14 can be used to troubleshoot the real and imaginary digital filters. Set the -hp-3561A controls as follows:

PRESET

MODE TEST SELECT DEFINE TEST NUM 14 ENTER

START CONT TST

If no return codes are displayed, the digital filters are operational. If only even numbered return codes are displayed, the failure is in U4 or U401. If only odd numbered return codes are displayed the failure is in U4 or U1. If both odd and even numbered return codes are displayed, the failure could be in any one of the three digital filter ICs. To isolate the failure, either U1 or U401 can be removed. When U401 is removed, only even numbered errors should occur, and when U1 is removed, only odd errors should occur. U1 and U401 are completely interchangeable and can be swapped to see if the failure follows the digital filter. If the error does not follow the digital filter, the failure is in U4.

5. To check the digital filter control IC (U4), set the -hp-3561A controls as follows:

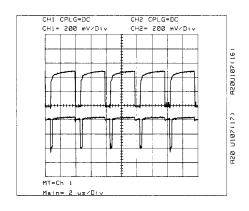
PRESET

MODE120 ENTER

START CONT TST

6. Check the signatures given in Table 7-17.

Figure 7-16 Test 123 RAM Bus Interface Waveforms



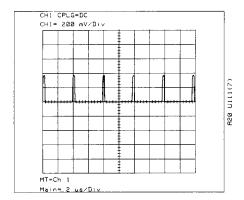
Probe: 10:1

Ch1: Connection- A20 U107(16) "DF2BR" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U107(17) "DF2BG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Negative

Bandwidth Limit: ON



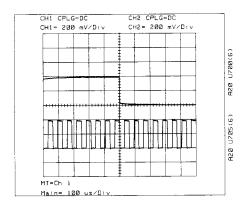
Probe: 10:1

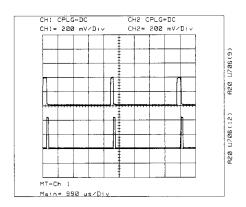
Ch1: Connection- A20 U111(7) "BGR" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Figure 7-17 Test 123 Channel R DMA Counter Waveforms





Probe: 10:1

Ch1: Connection- A20 U700(6) Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U705(6)
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A20 U706(9) "DONER" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U706(12) "ER" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-16 Test 123 Channel R Address Bus Latch Signatures

Signature Analyze	er Setup		
Signal	Polarity	Connection	
Clock		A20U703(12) "BGR"	
Start	$\overline{}$	A20U706(9) "DONER"	
Stop	<u></u>	A20U706(9) "DONER"	
+5 V Signature -	472A		
Channel R Addres	s Bus Latch		
U603(2)	3H19		
U603(5)	14U7		
U603(6)	0431		
U603(9)	PPA9		
U603(12)	P30H		
U603(15)	8084		
U603(16)	1H4H		
U603(19)	6886		
U607(2)	94A3		
U607(5)	22FC		

Table 7-17 Test 120 Digital Filter Signatures

ignal	Polarity	Connection
Clock		A20J100(3) "DFCLKφ1"
Start		A20J100(4) "CLR"
Stop		A20J100(5) "DSASTOP"
Note: The stop ar	nd start connections are rev	ersed from the labels printed on the PC board.
+5 V Signature -	695A	
- Signature		
Digital Filter		
Interface Signals		
U4(3)	03U9	
U4(19)	38HU	
U4(20)	H914	
U4(21)	54P2	
U4(36)	0 volts	
U4(49)	2208	
U4(50)	8UP9	
O7(30)	8UP9	
	2208	
U4(51)		
U4(51) U4(52)	25P6	
U4(51) U4(52) U4(59)		
U4(51) U4(52) U4(59) U4(60)	U614	
U4(51) U4(52) U4(59) U4(60) U4(61) U4(62)		

[C] CHANNEL G DMA COUNTER, [E] CHANNEL G ADDRESS BUS LATCH, [L] CHANNEL G COUNTER PRESET

1. Set the -hp-3561A controls as follows:

PRESET	
MODE	TEST SELECTDEFINE TEST NUM122 ENTER
	START CONT TST

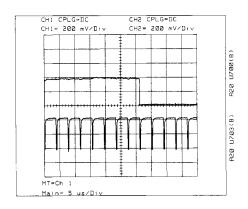
- 2. Check the waveforms given in Figure 7-18.
- 3. If all of the waveforms in Figure 7-18 are correct, check all of the signatures in Table 7-18.

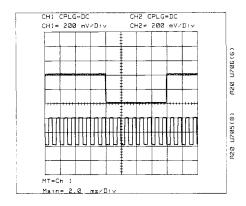
4. Set the -hp-3561A controls as follows:

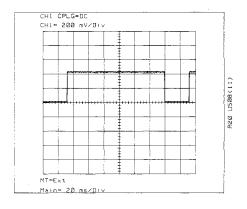
PRESET
TRIGger SELect... TRIGGER
INTERNAL TRIGGER

5. Check the waveform given in Figure 7-19.

Figure 7-18 Test 122 Channel G DMA Counter Waveforms







Probe: 10:1

Ch1: Connection- A20 U700(8) "G3" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U703(8) "BGG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A20 U706(6) "GB" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U705(8) "G7"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

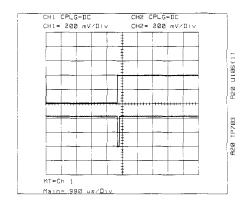
Probe: 10:1

Ch1: Connection- A20 U508(11) "GCNTF" Coupling- dc Ground- Center Graticule

Trigger: External- U700(12) "EG" Slope- Positive

Bandwidth Limit: OFF

Figure 7-19 "DONEG" Waveforms



Probe: 10:1

Ch1: Connection- A20 U106(1) Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 TP703 "DONEG"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Negative

Bandwidth Limit: ON

Table 7-18 Test 122 Channel G Address Bus Latch Signatures

Signature Analyze	er Setup		
Signal	Polarity	Connection	
Clock		A20U703(8) "BGC	"
Start	<u></u>	A20U508(11) "GC	NTF"
Stop	~	A20U508(11) "GC	NTF"
+5 V Signature -	755U		
Channel G Addre Bus Latch	255		
U602(2)	H335	U606(2)	7707
U602(5)	C113	U606(5)	577A
U602(6)	7050	U606(6)	HH86
U602(9)	0772	U606(9)	89F1
U602(12)	A3C1	U606(12)	755U
U602(15)	7211	U606(15)	1180
U602(16)	AA08	U606(16)	PCF3
U602(19)	C4C3	U606(19)	AC99

[Q] DATA REQ/SYNC2 GENERATOR, [T] CONVERT SIGNAL SELECT [P] CONVERT SIGNAL TIMING

1. Set the -hp-3561A controls as follows:

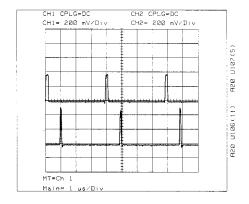
PRESET

MODE122 ENTER

START CONT TST

2. Check the waveforms given in Figure 7-20.

Figure 7-20 Convert/Sync2 Waveforms in Test 122



Probe: 10:1

Ch1: Connection- A20 U107(5) "CONVERT" Coupling- dc Ground- Center Graticule

Ch2: Connection- A20 U106(11) "SYNC2"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Table 7-19 A20 Assembly Signal Connections

INPUTS

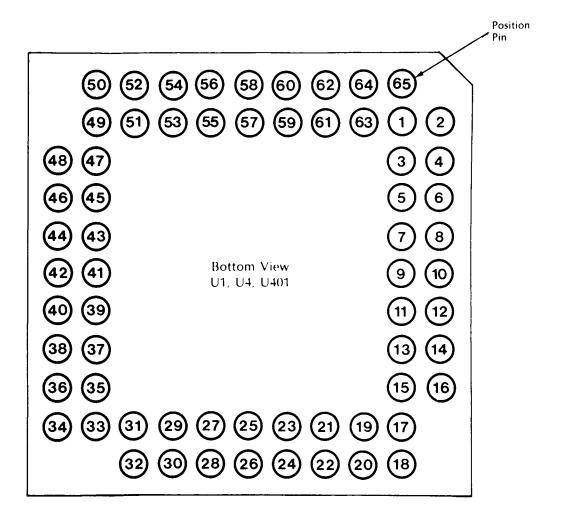
Signal	Functional	Connector Origin	
Name	Block	Number	Assembly
A/D DATA	U	P22(A2)	A15
COSINE	U	P21(A19)	A50
DF1BG	1	P22(A11)	A30
DF2BG	1	P22(A10)	A30
DF3BG	1	P22(A9)	A30
EXT SAMP	Т	P22(A7)	A82
FEISO	ВВ	P21(A23)	S2 (front panel)
FETRIG	EE	P22(B5)	A15
RBR/\overline{W}	F	P21(A10)	A30
RESET	Н	P21(A21)	A40
RIOS	F	P21(B10)	A30
-SINE	U	P21(B19)	A50
SSTAT	0	P22(B4)	A15
1/3TRIG	EE	P22(B7)	A50
20.48 MHz	FF	P21(B24)	A40

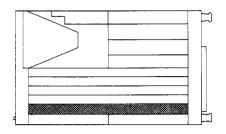
OUTPUTS

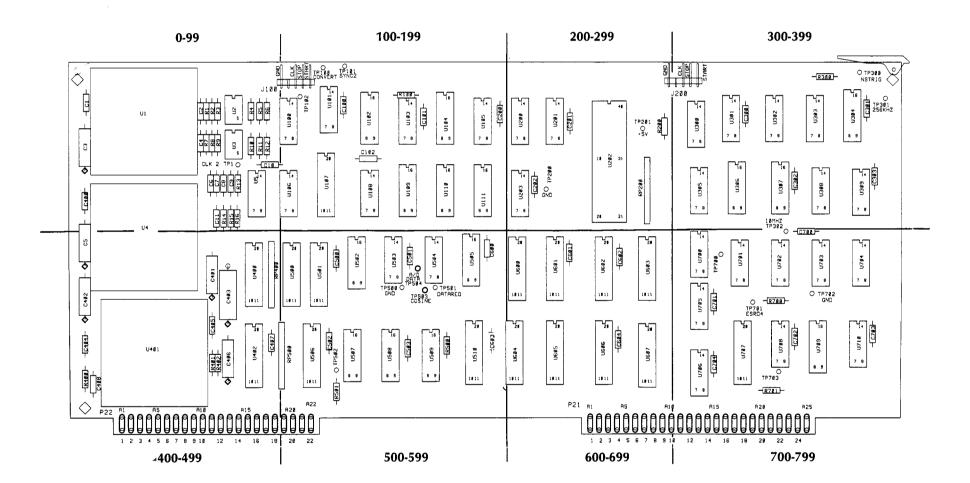
Signal	Functional	Connector	Destination
Name	Block	Number	Assemblies
CONVERT	Р	P22(B2)	A15
DATA REQ	Q	P22(B3)	A15
DMAI	Υ	P21(B16)	A40
DF1BR	1	P22(B11)	A30
DF2BR	1	P22(B10)	A30
DF3BR	1	P22(B9)	A30
ESR*4	Υ	P21(A23)	A50
FE CAL	DD	P21(B12)	A10
FECLK	S	P21(B11)	A10
FEDATA	S	P21(A11)	A10
FELATCH	S	P21(A12)	A10
SYNC2	Q	P21(B18)	A50
ZPHTRIG	V	P21(A17)	A50
256 KHz	GG	P21(B23)	A70
10.24 MHz	FF	P21(A24)	A15, A50

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assemblies
RAM Address Bus RAB0 - RABF	А	P21(A2 - A9) P21(B2 - B9)	A30, A40
RAM Data Bus RDB0 - RDBF	R	P22(A12 - A19) P22(B12 - B19)	A30

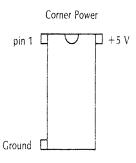




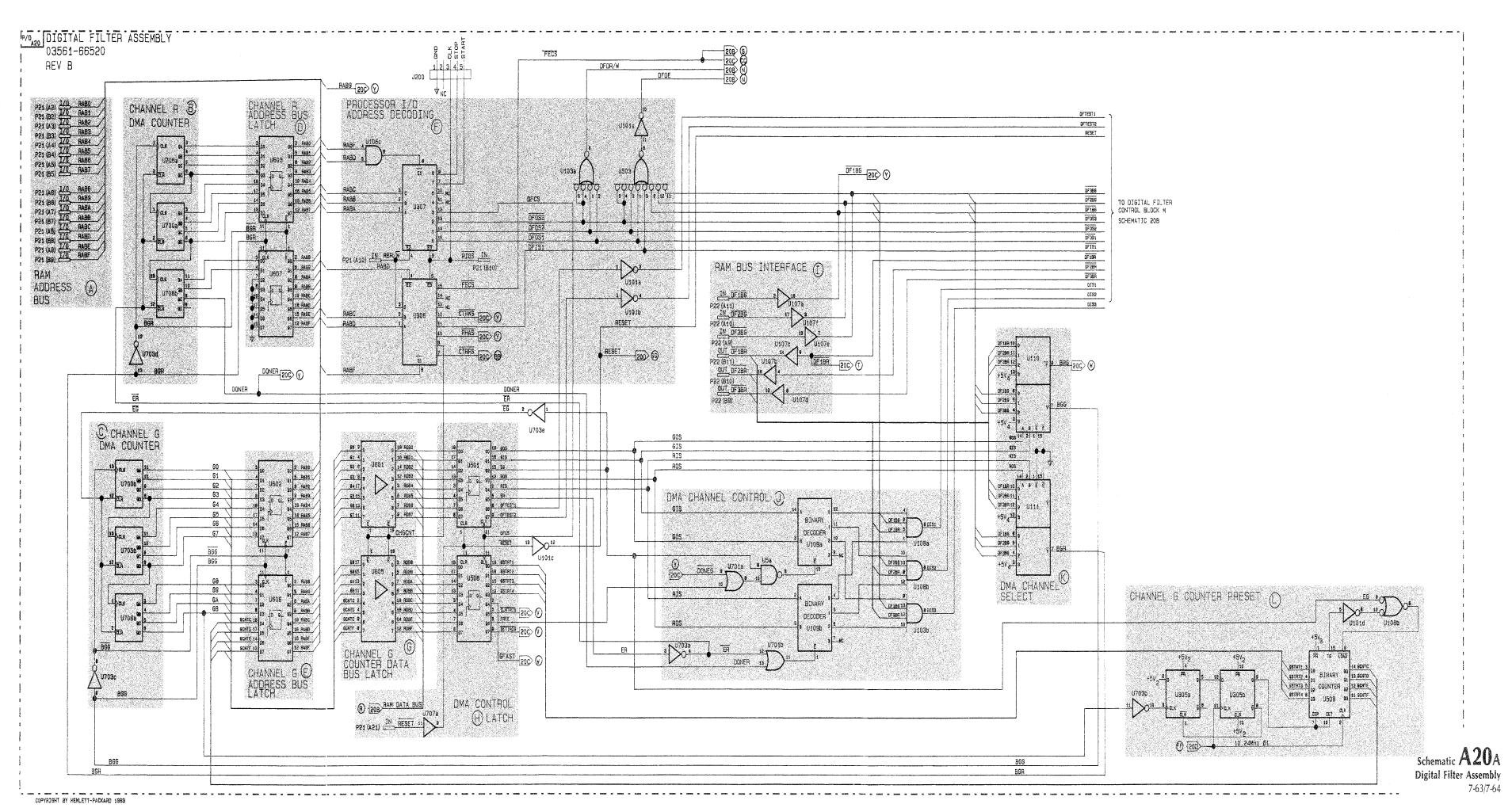


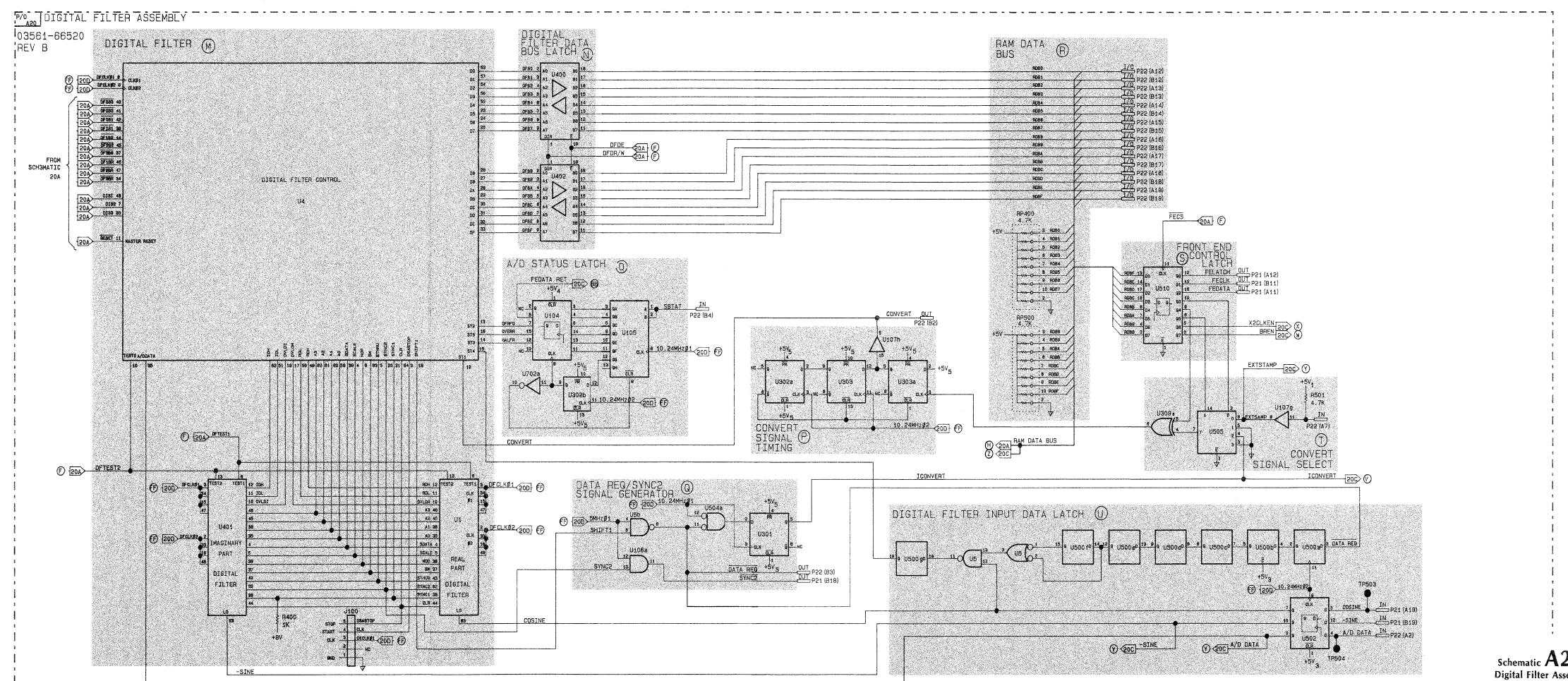
A20 Assembly

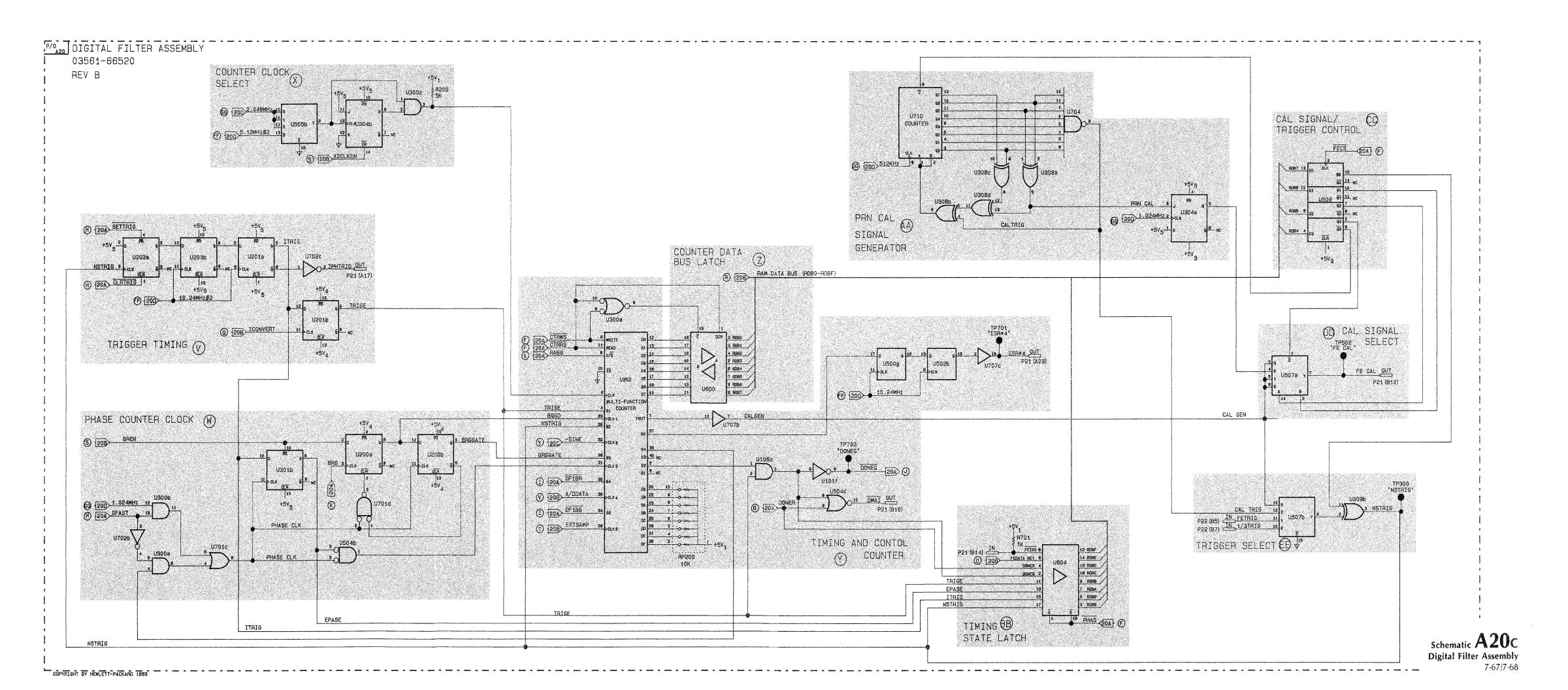
All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

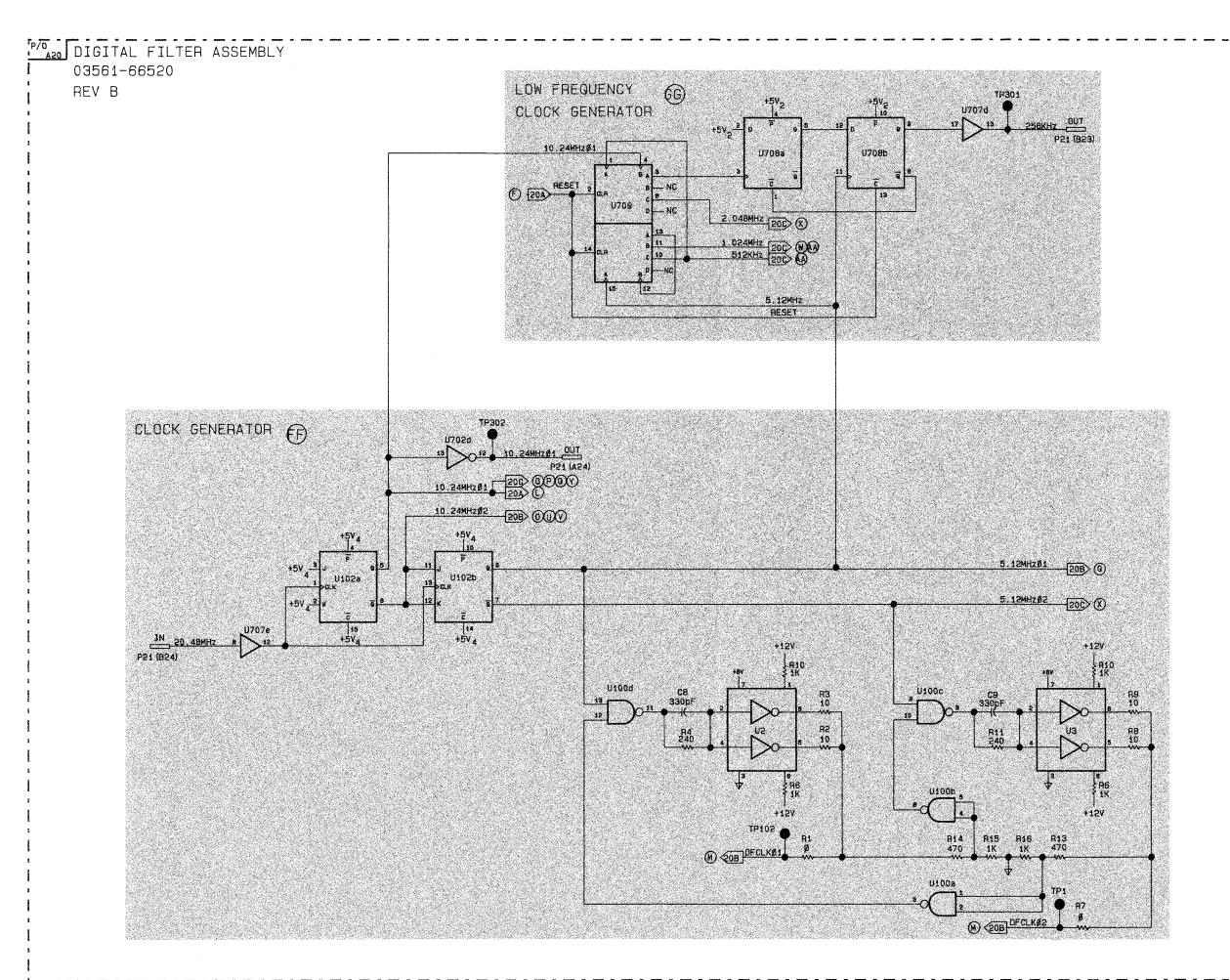


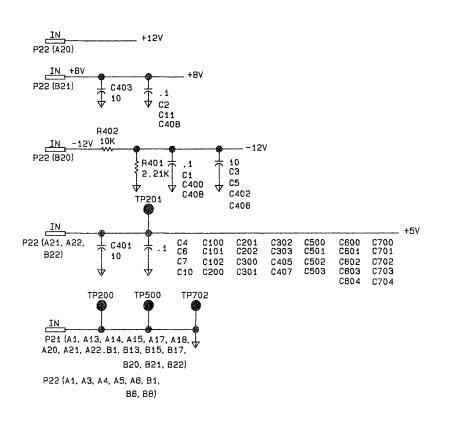
	+8V	+ 5V	-2V	GND
U1	7,9,	8,41	1	17,32,
	40,42			49,64
U2	7			3
U3	7			3
U4	2,48	22	1	58
U202		1		21
U401	7,9,	8,41	1	17,32,
	40,42			49,64











7-13 A30 FFT/RAM ASSEMBLY

7-14 FFT/RAM Circuit Description

GENERAL

The A30 Assembly contains the instrument RAM and the FFT processor. The instrument RAM is accessed for data storage by three circuits: the central processor, the FFT processor, and the digital filter. Access to the RAM bus is regulated by the RAM bus arbitrator, which prevent these three circuits from interfering with one another.

The FFT processor is an asynchronous microprocessor dedicated to performing the Fast Fourier Transform. An FFT is initialized by the main processor through the FFT RESET signal.

RAM BUS STRUCTURE

The -hp-3561A has a two bus structure for transferring data between circuits. The processor bus is controlled by the central microprocessor on the A40 Assembly and the RAM bus is controlled by the RAM bus arbitrator on the A30 Assembly. The RAM bus consists of a 16 bit data bus and a 16 bit address bus. To access the RAM bus, a circuit must issue a bus request signal to the RAM bus arbitrator. The RAM bus arbitrator then issues a bus grant to the highest priority bus request. In addition to direct RAM access, the RAM bus is used by the central processor to transfer I/O data to the A20 and A30 Assemblies.

[D] MAIN RAM

The A30 Assembly contains sixteen 64k by 1 bit RAMs. The RAM is addressed in a two step process. First, an 8 bit row address is placed on the memory address bus, which is latched by the RAM on the rising edge of RAS. Second, an 8 bit column address is placed on the memory address bus, which is latched by the RAM on the rising edge of CAS. The RAM either reads data from, or writes data to the the memory data bus on the rising edge of CAS.

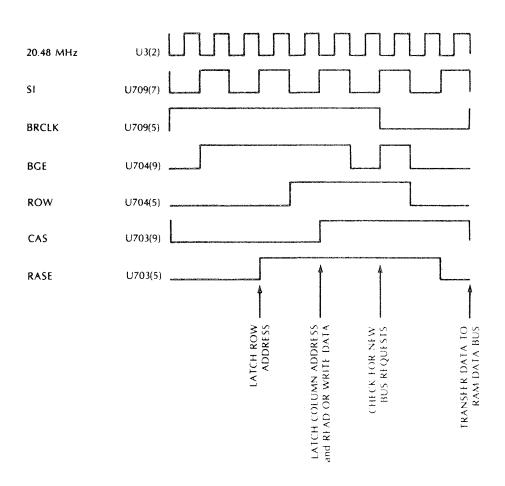
[B] RAM ADDRESS SELECTOR, [F] RAM COLUMN ADDRESS STROBE

When the ROW signal is low, the RAM address selector reads the row address from the lower 8 bits of the RAM address bus and when the ROW signal is high, the RAM address selector reads the column address from the upper 8 bits of the RAM address bus. The RAM column address strobe allows the processor to perform 8 bit or 16 bit operations by allowing access to just the lower 8 bits of RAM, just the upper 8 bits of RAM, or both.

[E] RAM ACCESS STATE MACHINE

This state machine generates all of the timing signals which control the RAM bus cycle. Figure 7-21 gives a timing diagram of the state machine outputs.

Figure 7-21 RAM Access State Machine Timing



[I] RAM BUS ARBITRATOR

The RAM bus arbitrator is a priority decoder which controls access to the RAM bus. When the RAM bus arbitrator receives a bus request signal, it compares the request against any other bus requests it has received. A bus grant signal is then issued to highest priority requester. The RAM bus arbitrator checks for new bus request signals once per RAM bus cycle on the rising edge of the BGE signal.

[G] 100 kHz REFRESH CLOCK, [J] RAM REFRESH COUNTER

The refresh clock issues a RAM bus request every ten micro seconds. If a bus grant is not received before the next ten micro second period, a higher priority bus request is issued. When a bus grant is received from the RAM bus arbitrator, the refresh counter addresses the memory location to be refreshed on the next RAM bus cycle.

[K] RAM READ/WRITE GENERATOR

This circuit determines what type of operation will occur on the next RAM bus cycle. When the PRIOS signal is high, a read from or write to RAM operation occurs and when the PRIOS signal is low, a processor I/O operation occurs.

[O] FFT PROCESSOR

When the FFT processor receives an FFT RESET signal from the main processor, it begins to execute the instructions stored in the FFT ROM. The FFT processor reads 1024 time data points from the RAM, performs an FFT on the data, and then writes the results back into RAM. When the complete 1024 point FFT is complete, the FFT processor issues an interrupt (FFTI), which indicates to the central processor that the FFT is complete, and the results can be displayed on the CRT. The FFT processor runs on its own 20.00 MHz crystal oscillator.

[U] FFT/RAM INTERFACE

When the FFT processor wishes to access RAM, it issues a RAM bus request (FFTBR) through the FFT/RAM interface. On receipt of a RAM bus grant, the FFT/RAM interface clears the bus request and latches the RAM address onto the RAM address bus. The FFT processor then uses the FFT/RAM interface to transfer data to or from the RAM.

Table 7-20 A30 Assembly Signal Descriptions

Signal	Description
BRCLK	Bus Request CLock: Clocks the RAM bus request signals into the RAM bus arbitrator once per RAM bus cycle.
CASL	Column Address Strobe Lower 8 bits (bits 0-7): On the rising edge of this signal, the lower 8 bit RAMs latch the column address from the address bus and data from the memory data bus.
CASU	Column Address Strobe Upper 8 bits (bits 8-F): On the rising edge of this signal, the upper 8 bit RAMs latch the column address from the address bus and data from the memory data bus.
DBE	Data Bus Enable: Enables data transfer between the RAM and the RAM data bus through the RAM data bus buffers.
DEN	Data input ENable: Enables Data to be input to the FFT processor from the RAM data bus.
DF1BG DF2BG DF3BG	Digital Filter Channel (1,2,3) Bus Grant: These signals go low give the digital filter access to the RAM bus for storing type one, two or three data.
DF1BR DF2BR DF3BR	Digital Filter Channel (1,2,3) Bus Request: Issued by the digital filter to request access to the RAM bus.
FAB0-FABB	FFT Address Bus (12 bit): Used by the FFT processor to address the FFT instruction ROM.
FDB0-FDBF	FFT Data Bus (16 bit): Transfers data from ROM to the FFT processor and transfers data between the FFT processor and RAM.
FFTBG	FFT Bus Grant: Grants the FFT processor access to the RAM bus.
FFTBR	FFT Bus Request: Issued by the FFT processor to request access to the RAM bus. Highest priority request.
FFTCONS	FFT CONtrol Select: Clocks FFT control data into the FFT/Processor Interface Register.
FFTI	FFT Interrupt: Signals the central processor that the FFT processor has completed an FFT on a time record.
FFTINTCLR	FFT INTerrupt CLeaR: Issued by the processor to clear the FFT interrupt.
FFT RESET	FFT RESET: Issued by the central processor to reset the FFT processor and initialize an FFT on a new time record.
MEN	Memory ENable: Issued by the FFT processor to address the FFT ROM.
NODBE	NO Data Bus Enable: Inhibits a data bus enable when the processor is tranferring I/O data over the RAM bus rather than directly accessing the RAM.
NOCAS	NO Column Address Strobe: Inhibits a column address strobe during RAM refresh

Table 7-20 A30 Assembly Signal Descriptions (Cont'd)

Signal	Description
PBG	Processor Bus Grant: This signal goes low to give the processor access to the RAM bus on the next RAM bus cycle.
PBLDS	Processor Bus Lower Data Strobe: Low when the processor is addressing the the lower 8 bits of RAM.
PBR	Processor Bus Request: Issued by the processor to request access to the RAM bus.
PRAMRE	Processor RAM REad: Low to enable data from the RAM data bus onto the processor data bus in a RAM read or I/O port read operation.
PRIOS	Processor Ram I/O Select: High when the processor is accessing RAM, low when the processor is accessing an I/O port through the RAM bus.
PBUDS	Processor Bus Upper Data Strobe: Low when the processor is addressing the upper 8 bits of RAM.
RAS	Row Address Strobe: On the rising edge of RAS the RAM latches the row address.
REFEN	REFresh ENable: Gives the refresh counter access to the RAM bus. The refresh counter address increments by one each time a REFEN is received.
REFSEL	REFresh SELect: Low to disable the refresh request issued by the 100 kHz refresh clock.
ROW	ROW: High to indicate that the column address is on the memory address bus and low to indicate that the row address is on the memory address bus.
WE	Write Enable: Issued by the FFT processor when it writes to RAM.

6-15 Troubleshooting the A30 Assembly

GENERAL

Failures in the RAM will generally be flagged by the power on test. Failures in the FFT will generally result in no data or bad data being displayed on the CRT also causing the power on test to fail. Because the FFT processor has the highest priority access to the RAM, some FFT failures will prevent the central processor from accessing RAM, and thus appear as a RAM failure.

Troubleshoot the circuits on the A30 Assembly in the order given in Table 7-21. In this table, level one circuits must be operational before level two circuits can be tested, which must be operational before level three circuits can be tested and so on.

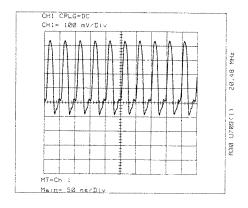
Table 7-21 A30 Circuit Troubleshooting Order

Level	Functional Blocks
1	Ram Access State Machine: E, C
	100 kHz Refresh Clock: G
2	RAM Column Address Strobe: F
	RAM Bus Arbitrator: H, I, K
3	RAM Refresh Counter: J
4	Processor Interface: L, R, U
5	RAM: D
	RAM Address Bus: B
	RAM Data Bus: A
6	FFT Processor: M, N, O, P, S, T, V

[E] RAM ACCESS STATE MACHINE

Due to the feedback in the RAM access state machine, a failure on one signal will cause all of the signals to be incorrect. The correct output waveforms are given in Figure 7-22. Check the 20.48 MHz clock and the $\overline{S1}$ signal first. $\overline{S1}$ depends only on the clock. If these signals are correct, check the remaining signals. If these remaining signals are incorrect, replace U709, U704, U703, U702, U311, and U305 one at a time until the waveforms are correct. Recheck the waveforms after each IC is replaced.

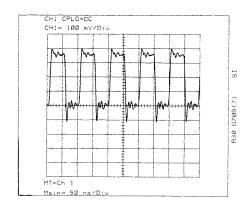
Figure 7-22 RAM State Machine Waveforms



Probe: 10:1

Ch1: Connection- A30U709(1) "20.48 MHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

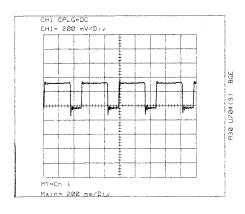


Probe: 10:1

Ch1: Connection- A30U709(7) "SI" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

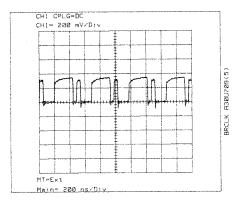


Probe: 10:1

Ch1: Connection- A30U704(9) "BGE" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

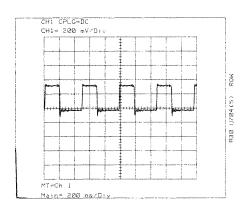


Probe: 10:1 and Trigger

Ch1: Connection- A30U709(5) "BRCLK" Coupling- dc Ground- Center Graticule

Trigger- External: A30U704(9) "BGE" Slope- Negative

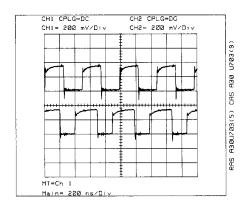
Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A30U704(5) "ROW" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive



Probe: 10:1

Ch1: Connection- A30U703(9) "CAS"
Coupling- dc
Ground- Center Graticule

Ch2: Connection- A30U703(5) "RAS" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[H] RAM BUS ARBITRATOR, [I] BUS GRANT TIMING, [G] 100 kHz REFRESH CLOCK

- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Remove the A20 Assembly and use a clip lead to short the two pins of A30W100 together.
- 3. Move test jumper A40W1 to the test position.
- 4. Turn the -hp-3561A LINE power switch ON.
- 5. When the "BLT TEST ROUTINE" message is displayed, verify that U707(3, 4, 7, 8, 13) are all at a TTL high state. If these signals are all correct, check the waveforms given in Figure 7-23. These waveforms trace the Processor bus request signal and the refresh enable signal through the RAM bus arbitrator.

NOTE

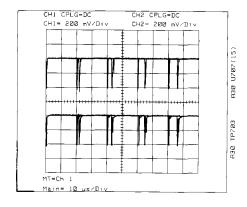
The A60 Assembly may be removed during this test to disable the beeper. However, this also disables the display so the "BLT TEST ROUTINE" will not be displayed. The waveforms and signatures will be valid when the front panel LEDs begin to blink.

- 6. Use a clip lead to short A30TP704 (DG3BR) to ground, simulating a constant digital filter bus request.
- 7. Check the signals listed in Table 7-22 and the waveforms given in Figure 7-24. While DF3BR is shorted to ground it is the highest priority bus request. The refresh enable signal and all bus grant signals except DF3BG should be inactive. This test may be repeated for DF2BG and DF1BG.
- 8. When all of the waveforms and signatures have been checked, move jumper A40W1 back to the run position, re-insert the A20 Assembly, and remove the short from A30W100.

Table 7-22 RAM Bus Arbitrator Signals With DF3BR Grounded

Signal	State
U707(2)	TTL High
U708(6)	Low
U708(7)	Low
U708(9)	TTL High
U706(4)	Low
U706(5)	TTL High
U706(6)	Low
U701(2)	Low
U701(5)	TTL High
U701(6)	Low

Figure 7-23 RAM Bus Arbitrator Waveforms



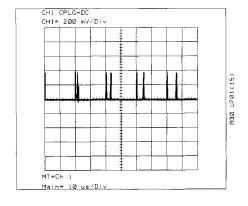
Probe: 10:1

Ch1: Connection- A30U707(14) "PBR" Coupling- dc Ground- Fourth Graticule From Top

Ch2: Connection- A30TP703 "PBG"
Coupling- dc
Ground- Second Graticule From Bottom

Trigger: Internal- Ch1 Slope- Negative

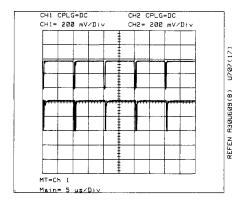
Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A30U701(15) Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive



Probe: 10:1

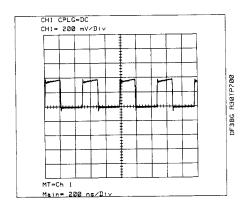
Ch1: Connection- A30U707(17)
Coupling- dc
Ground- Fourth Graticule From Top

Ch2: Connection- A30U609(8) "REFEN" Coupling- dc Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope- Negative

Bandwidth Limit: OFF

Figure 7-24 DF3BG With DF3BR Grounded



Probe: 10:1

Ch1: Connection- A30TP700 "DF3BG" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

[A] RAM DATA BUS BUFFERS, [B] RAM ADDRESS SELECTOR, [D] MAIN RAM [J] RAM REFRESH COUNTER, [L] PROCESSOR/RAM DATA BUS INTERFACE [R] FFT/PROCESSOR INTERFACE, [U] RAM TEST PORT

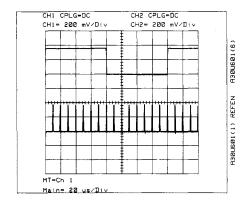
- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Remove the A20 Assembly and use a clip lead to short the two pins of A30W100 together.
- 3. Move test jumper A40W1 to the TEST position.
- 4. Turn the -hp-3561A LINE power switch ON.
- 5. When the "BLT TEST ROUTINE" message is displayed on the CRT, check the refresh counter waveforms given in Figure 7-25.

NOTE

The A60 Assembly may be removed during this test to disable the beeper. However, this also disables the display so the "BLT TEST ROUTINE" message will not appear. The wave forms and signatures will be valid when the front panel LEDs begin to blink.

- 6. Check the signatures given in Table 7-23 and 7-24 to troubleshoot the remaining RAM circuits and processor interface circuits.
- 7. When all of the waveforms and signatures have been checked, move jumper A40W1 back to the RUN position, re-insert the A20 Assembly, and remove the short from A30W100.

Figure 7-25 RAM Refresh Counter Waveforms



Probe: 10:1

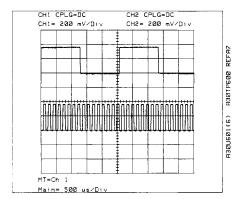
Ch1: Connection- A30U601(6)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A30U601(1) "REFEN"

Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope- Positive



Probe: 10:1

Ch1: Connection- A30TP600 "REFA7" Coupling- dc Ground- Third Graticule From Top Model 3561A

Ch2: Connection- A30U601(6)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope- Positive

Table 7-23 RAM Address and Data Bus Signatures

Signature Analyzer	Setup		
Signal	Polarity	Connection	
Clock		A30TP703 "PBG"	
Start		A40J100(5)	
Stop	~	A40J100(4)	
+5 V Signature - 5	UAH		
Processor/RAM Dat	a Bus Interface (write to	RAM) RAM Address	Selector
U502(3)	70H0	U200(4)	2525
U502(5)	0C43	U200(7)	0476
U502(7)	00A2	U200(9)	UACC
U502(9)	515U	U200(12)	P76P
U502(12)	C8H3		
U502(14)	F61C	U205(4)	265H
U502(16)	929C	U205(7)	5U5P
U502(18)	AFU0	U205(9)	2134
/	💆	U205(12)	CC17
U506(3)	AP35	0 = 30(, = ,	
U506(5)	F680		
U506(7)	HAU4		
U506(9)	F15A		
U506(12)	118F		
U506(14)	276U		
U506(16)	5165		
U506(18)	354A		
RAM Data Bus Buf	fers (write to RAM)		
U604(2)	H058		
U604(3)	2133		
U604(4)	UU2A		
U604(5)	9C1H		
U604(6)	A4UA		
U604(7)	0U28		
U604(8)	49UH		
U604(9)	PPHF		
U700(2)	U68P		
U700(3)	POP2		
U700(4)	9621		
U700(5)	H2HP		
U700(6)	518H		
U700(7)	F80A		
U700(8)	2HAH		
U700(9)	24F4		
J, 00(0)	4 · · ·		

Table 7-23 RAM Address and Data Bus Signatures (Cont'd)

Signal	Polarity	Connection	
Clock Start	/	A30TP703 "PBG" A40J100(5)	
Stop		A40J100(4)	
+5 V Signature -	5UAH		
Main RAM		Processor/Ram Bus Ir	nterface (Read from RAM)
U201(2)	6CAC	U501(2)	35H5
U202(2)	6890	U501(5)	F433
U203(2)	4168	U501(6)	A0C4
U204(2)	899A	U501(9)	C4C6
U207(2)	AAF8	U501(12)	F925
U208(2)	U6U6	U501(15)	225P
U209(2)	5216	U501(16)	H48P
U210(2)	17CF	U501(19)	027H
U300(2)	924A	U505(2)	H564
U301(2)	A44A	U505(5)	7C7C
U302(2)	49PA	U505(6)	A90C
U303(2)	04UA	U505(9)	0CHP
U306(2)	H0A2	U505(12)	182A
and the second s	6U6U	U505(15)	47FF
U307(2)			
U307(2) U308(2)	91HU	U505(16)	C894

Table 7-24 FFT/Processor Interface Signatures

Signal	Polarity	Connection
Clock Start Stop	5	A30TP601 "RIOS" A40J100(5) A40J100(4)
+5 V Signature -	Н7РС	
FFT/Processor Int	erface	
U600(2)	F6F0	
U600(3)	112C	
U600(7)	HPH1	
U600(10)	P376	
U600(14)	F6F0	
U606(15)	7F2P	

[D] MAIN RAM

If the signatures given in Table 7-23 are correct, the power on test can be used to isolate RAM failures to the component. When the power on test encounters a RAM failure, it lists return code 0 7 26 and a chip code. Table 7-25 lists the chip codes and the corresponding failed RAM.

Table 7-25 Power on Test RAM failures

Return code - 0 7 26		
Chip code	Failed RAM	
0	U201	
1	U202	
2	U203	
3	U204	
4	U205	
5	U300	
6	U301	
7	U302	
8	U303	
9	U207	
Α	U208	
В	U209	
С	U210	
D	U307	
E	U308	
F	U309	

[O] FFT PROCESSOR, [Q] FFT INSTRUCTION ROM

- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Move test jumpers A30W101 and A30W102 to the test position. Use a clip lead to short the two pins of A30W100 together.
- 3. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-26.
- 4. When all of the signatures have been checked, move jumpers A30W101 and A30W102 back to the NORM position and remove the short from A30W100.

Table 7-26 FFT Processor and ROM Signatures

Signal	Polarity	Connection	
Clock	<u> </u>	A30J1(3)	
Start		A30J1(5)	
Stop		A30J1(4)	
+5 V Signature -	7A70		
FFT Processor Ado	dress Bus	FFT Address Bus B	uffers
U100(1)	C21A	U4(3)	H62U
U100(2)	H62U	U4(5)	C21A
U100(27)	0000	U4(7)	HA07
U100(28)	8P54	U4(9)	H0AA
U100(29)	1734	U4(12)	P030
U100(34)	9635	U4(14)	4442
U100(35)	0772	U4(16)	4U2A
U100(36)	4U2A	U4(18)	0772
U100(37)	4442		
U100(38)	P030	U7(3)	9635
U100(39)	H0AA	U7(5)	1734
U100(40)	HA07	U7(7)	8P54
		U7(9)	0000
FFT Instruction Ro	MC		
U400(9)	HP00		
U400(10)	HP01		
U400(11)	HP02		
U400(13)	HP03		
U400(14)	HP04		
U400(15)	HP05		
U400(16)	HP06		
U400(17)	HP07		
U402(9)	HP08		
U402(10)	HP09		
U402(11)	HP10		
U402(13)	HP11		
U402(14)	HP12		
U402(15)	HP13		
U402(16)	HP14		
U402(17)	HP15		

Table 7-27 A30 Assembly Signal Connections

INPUTS

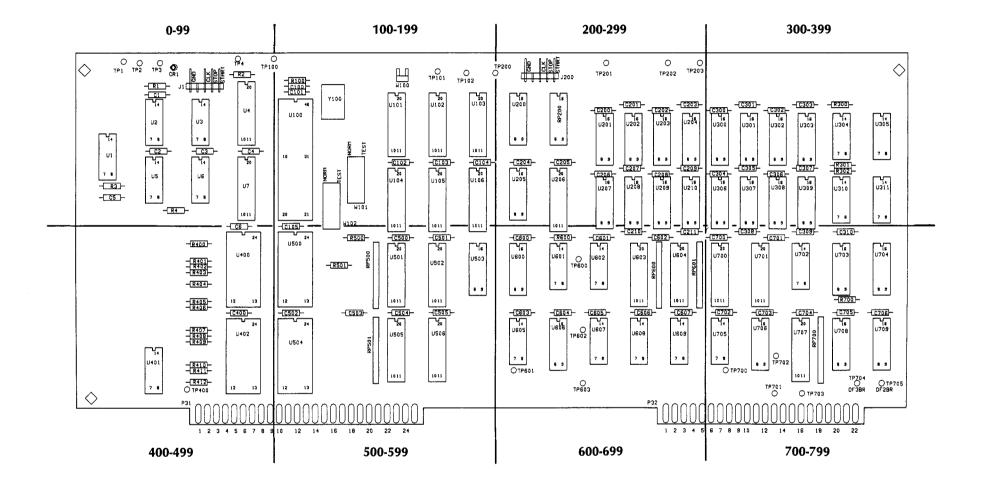
Signal Name	Functional Block	Connector Number	Origin Assembly
DF1BR	Н	P32(A12)	A20
DF2BR	н	P32(A13)	A20
DF3BR	Н	P32(A14)	A20
PBLDS	F	P31(A6)	A40
PBR	Н	P32(A16)	A40
PBR/\overline{W}	K	P32(B7)	A40
PBUDS	F	P31(B6)	A40
PRAMRE	L	P31(A7)	A40
PRIOS	1	P32(B17)	A40
RESET	R	P31(B3)	A40
100 kHz	G	P31(B2)	A40
20.48 MHz	С	P31(A2)	A40

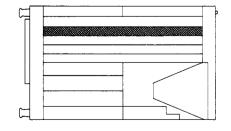
OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assembly
DF1BG		P32(B12)	A20
DF2BG	1	P32(B13)	A20
DF3BG	1	P32(B14)	A20
FFTI	S	P31(B4)	A40
FFTI PBG		P32(B16)	A40
RBR/ W	K	P31(B16)	A20
RIOS	K	P31(A16)	A20

I/O SIGNALS

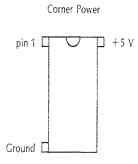
Signal Name	Functional Block	Connector Number	Destination Assembly
RAM Address Bus RAB0 - RABF	В	P31(A17 - A24) P31(B17 - B24)	A20, A40
RAM Data Bus RDB0 - RDBF	L	P32(A4 - A11) P32(B4 - B11)	A20
Processor Data Bus PDB0 - PDBF	L	P31(A8 - A15) P31(B8 - B15)	A40, A50, A60, A65/66



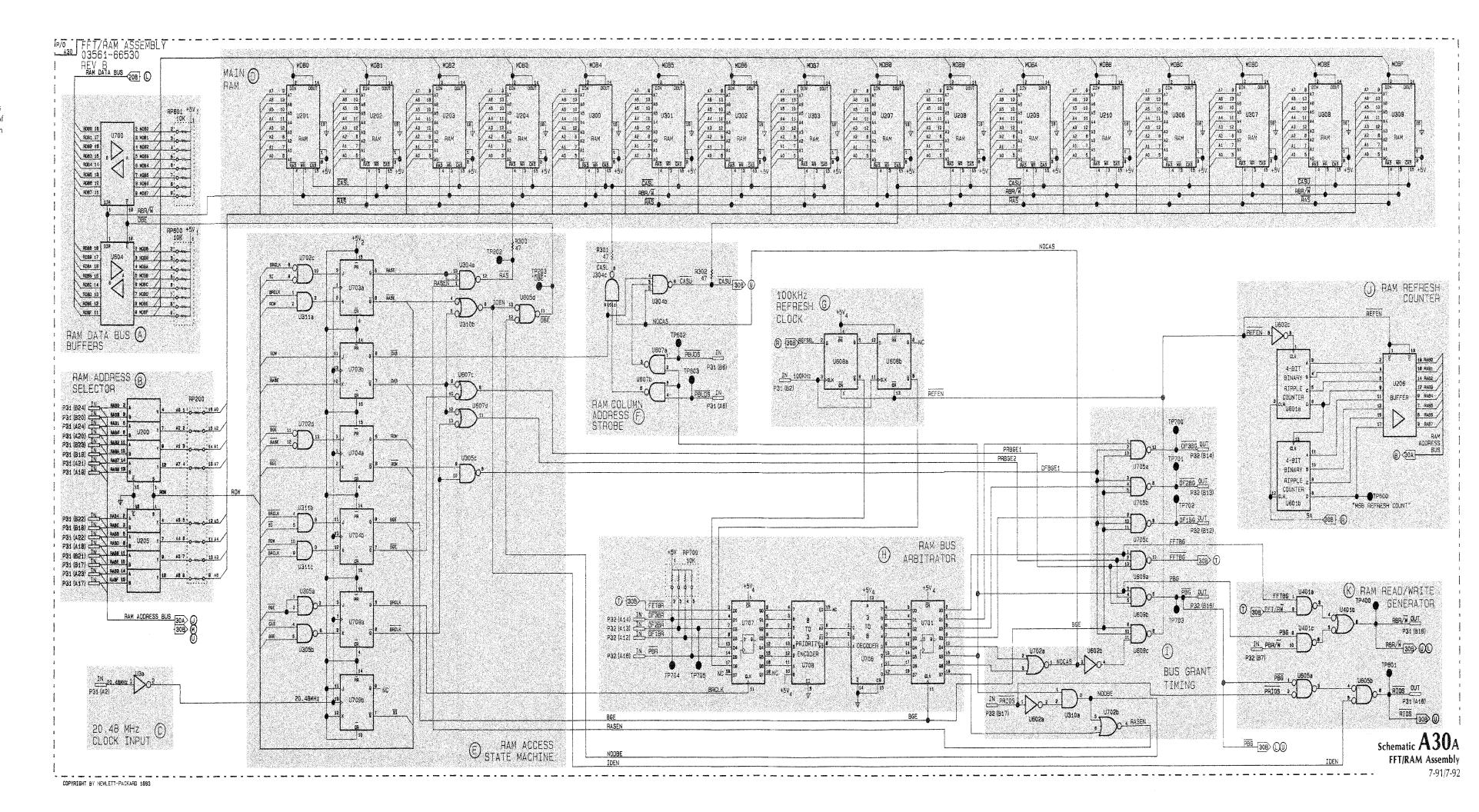


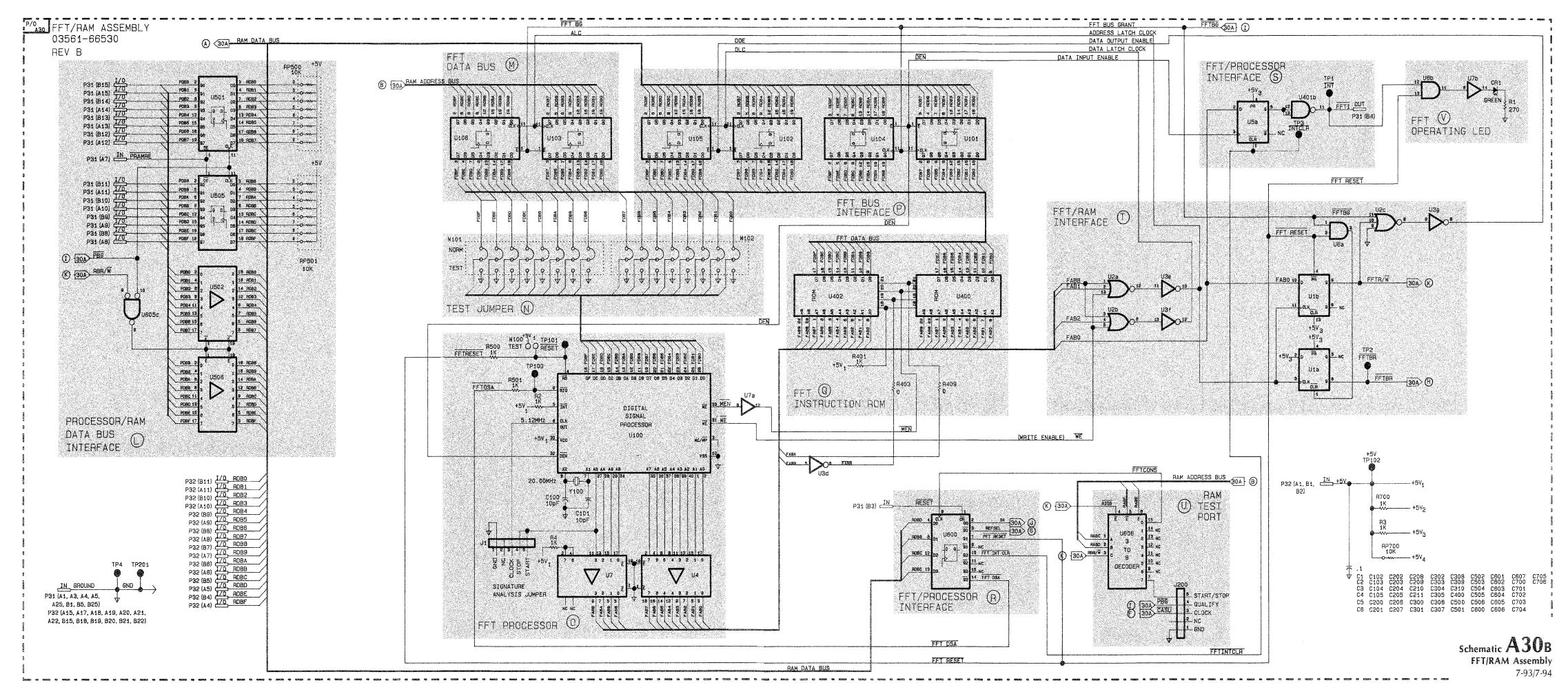
A30 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and ± 5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and ± 5 V is connected to pin 16)



	+ 5V	GND
<u> </u>		
U100	30	10
U201	8	16
U202	8	16
U203	8	16
U204	8	16
U207	8	16
U208	8	16
U209	8	16
U210	8	16
U300	8	16
U301	8	16
U302	8	16
U303	8	16
U304	8	16
U305	8	16
U306	8	16
U307	8	16
U308	8	16
U309	8	16
	1	





7-16 A40 PROCESSOR/ROM ASSEMBLY

7-17 Processor/ROM Circuit Description

GENERAL

The main function of the microprocessor assembly is instrument control. Through the processor data bus, address bus, and I/O select lines, the microprocessor sets up and controls most circuits in the -hp-3561A and through the processor interrupt lines, these circuits can access the microprocessor. Together all of these signals allow the processor to direct the activity required for the -hp-3561A to take, process, and display measurement data. In addition to the microprocessor, ROM, and I/O control circuitry, the A40 Assembly contains the master 20.48 MHz clock, which determines the frequency accuracy of the instrument.

[A] INTERRUPT PRIORITY ENCODER, [K] INTERRUPT VECTOR GENERATOR

When an interrupt is received by the priority interrupt encoder, it compares the priority of the interrupt with the priority of any other active interrupts (level 7 in U408 being the highest level and level 0 the lowest). It then issues the highest priority interrupt to the processor where an interrupt acknowledge cycle is initiated. In this cycle the processor outputs the binary interrupt level on the first three address lines PA0, PA1, and PA2, and issues an interrupt acknowledge signal, PINTA. PINTA latches the first three address lines in the interrupt vector generator. The processor next reads the vector generator to determine the location in memory of the interrupt service routine.

[I] RAM BUS INTERFACE HANDSHAKE, [B] RAM BUS INTERFACE BUFFER

To access the instrument RAM, the processor must issue a bus request (PBR) to the RAM bus arbitrator. If the processor bus request is the highest priority request, the RAM bus arbitrator will issue a bus grant to the processor. On receipt of a bus grant, the processor places an address and data onto the RAM address and data bus respectively. The RAM bus interface then clears the bus request, and issues a RAMH signal to complete the RAM bus cycle.

[D] MICROPROCESSOR

The central microprocessor is a 68000, 16 bit processor. It communicates with peripheral circuits through the processor address bus and processor data bus, using the address strobe, data strobe, and the data acknowledge signals to coordinate the data transfer. Address strobe, AS, goes low to indicate that the address is valid on the processor address bus. Upper data strobe, PUDS, and lower data strobe, PLDS, go low to indicate that data is valid on the upper 8 bits and lower 8 bits of the data bus respectively. A processor bus cycle is terminated by the data acknowledge signal, DTACK.

[H] ADDRESS STROBE TIMING DELAY, [J] DATA ACKNOWLEDGE GENERATOR

The address strobe timing delay circuit delays the address strobe signal to account for address delays through the bus buffers. Delayed address strobe, DAS is delayed by one clock cycle, and is used for addressing circuits on the A40 Assembly. The address strobe signal is further delayed to account for the communication time to the ROM, noise source, and front panel.

The delayed address strobe signals are used by the data acknowledge generator to determine the length of a bus cycle to any particular peripheral. The data acknowledge generator reads the address bus to determine which peripheral the processor is talking to. This address is then used to select the appropriate delayed address strobe to generate the DTACK signal. All bus cycle times are fixed by the delayed address strobe signals except RAM access and display access. The data acknowledge generator depends on a response from these two circuits to generate a DTACK. RAMH indicates that the RAM bus cycle is complete and DSPH indicates that a display bus cycle is complete.

[M] I/O ADDRESS DECODING, [L] CONTROL AND ADDRESS BUS BUFFER

The processor address bus is partially decoded on the A40 Assembly by the I/O address decoder. This circuit generates a select signal for each major circuit in the instrument. The processor address bus and the data bus strobe are buffered through the control and address bus buffer and sent to the peripheral circuits where the address is further decoded to a particular device within the selected circuit.

[Q] POWER-ON RESET

The LOW+5 signal from the power supply holds the processor in reset until the +5 volt supply is fully operational at power on. The RESET and HALT signals are bidirectional and can be driven by either the processor or the power on reset circuit to reset the -hp-3561A. The two pins of the RESET test point (TP2) may be shorted together to manually reset the processor.

[T] WATCH DOG TIMER

This circuit will reset the processor if the processor does not access the front panel every ten micro seconds. This should only occur in the case of a failure. The watch dog timer may be disabled by jumper A40W3.

[P] ROM, [O] ROM ADDRESS DECODING

The processor executes the instructions stored in the ROM. The ROM address consists of two parts, the ROM chip select signals address a ROM chip while the address bus addresses the location within the selected ROM. The power on self test is stored in ROMS #1 and #2 (U502, U106) If these ROMs have failed, the power on test will not run. Using the power up test program stored in ROM #1, the processor can check the integrity of the other ROMs.

[R] CLOCK GENERATOR, [S] CLOCK DIVIDE $\div 10 \div 100$

In addition to the microprocessor circuits, this oscillator provides a clock signal to the following circuits: Noise Source (A50), CMOS and Bubble Memory (A66/65).

[U] 20.48 MHz CRYSTAL OSCILLATOR, [V] CLOCK OUTPUT BUFFER

This oscillator provides a clock signal for the following circuits: RAM (A30), Digital Filter (A20), Power Supply (A70), A/D Converter (A15). The accuracy of this oscillator determines the overall frequency accuracy of the instrument.

Table 7-28 A40 Assembly Signal Descriptions

Signal	Description
ĀS	Address Strobe: This signal goes low once per processor bus cycle to indicate that data is valid on the processor address bus.
BERR	Bus ERRor: This signal goes low to abort the current bus cycle. The BERR signal is activated if the bus cycle takes longer than expected.
BUBI	BUBble memory Interrupt: The bubble memory uses this signal to request service from the processor.
CMOSS	CMOS memory Select: Addresses the CMOS memory on the A65/66 Assembly for processor access.
DAS	Delayed Address Strobe: Address strobe delayed by one 8 MHz clock cycle.
DINT	Data acknowledge INTerrupt: Forces a DTACK to indicate to the processor that the interrupt vector has been latched.
DMAI	Direct Memory Access Interrupt: Tells the processor that the digital filter has processed a complete time record and stored the result in RAM.
DSPH	DiSPlay Holdoff: This signal holds off the DTACK signal until the display access is complete.
DSPS	DiSPlay Select: Addresses the display for processor access.
DTACK	DaTa ACKnowledge: This signal goes low to indicate to the processor that the current bus cycle is complete.
FFTI	FFT Interrupt: The FFT uses this signal to indicate that the FFT is complete, and the results are available for further processing or display.
FIOH	Fast I/O Holdoff: This signal holds off the DTACK signs by four 8 MHz clock cycles for all fast I/O port bus cycles.
FPS	Front Panel Select: Addresses the front panel for processor access.
HALT	Processor HALT: This signal goes low to indicate that the processor is not executing instructions. The red LED, CR2, illuminates when HALT is low. This signal may be driven low by either the processor or the reset circuit.
HPCI	HP-IB Control Interrupt: Used for all HP-IB activity except binary data transfer.
HPDI	HP-IB Data Interrupt: A faster interrupt used for binary data transfer only.
HPIBS	HP-IB Select: Addresses the HP-IB circuit on the A50 Assembly for processor access.

Table 7-28 A40 Assembly Signal Descriptions (Cont'd)

Signal	Description
IOPORT#7	I/O PORT Number 7: The processor addresses this port to clear the interrupt vector generator.
LOS	Local Oscillator Select: Addresses the local oscillator on the A50 Assembly for processor access.
LOW + 5	LOW ± 5 Volt Supply: At power on this signal is held low until the ± 5 V signal is fully operational.
PA0 - PAF	Processor Address bus 0-F (16 bit hex): Buffered processor address bus.
PA17 PA18 PA19	Processor Address Bus: Address lines used only for circuits on the A40 Assembly.
PD0 - PDF	Processor Data Bus 0-F (16 bit hex): Buffered processor data bus.
PINTA	Processor INTerrupt Acknowledge: This signal goes low at the start of an interrupt acknowledge bus cycle to latch the interrupt vector.
PLDS	Processor Lower 8 bit Data Strobe: Indicates that the lower 8 bits (PD0 - PD7) of the processor data bus are valid.
PRAMRE	Processor RAM REad: Goes low to tell the RAM that the current bus cycle is a read operation.
PRIOS	Processor Ram I/O Select: High when the processor is accessing the RAM and low when the processor is accessing an I/O port through the RAM bus.
PUDS	Processor Upper 8 bit Data Strobe: Indicates that the upper 8 bits (PD8 - PDF) of the processor data bus are valid.
PWRFAIL	PoWeR FAIL Interrupt: Indicates a power fail condition to the processor.
RESET	RESET: This signal is goes low to reset the processor and the entire instrument. RESET can be controlled by either the processor or the reset circuit.
RAB0 - RABF	RAM Address Bus $0 - F$ (16 bit hex): Addresses the RAM and I/O ports tied to the RAM bus when a \overline{PBG} is issued from the RAM bus arbitrator.
RCS0 - RCS11	ROM Chip Select 0 through 11: These signals select the ROM Chip to be addressed by the address bus.
SINT	Noise Source INTerrupt: This signal goes low when the noise source needs to be re-armed.
TINT	Timer INTerrupt: Indicates to the processor that the watch dog timer is about to issue a RESET.

7-18 Troubleshooting the Processor/ROM

GENERAL

Failures on the A40 Assembly will generally cause the instrument to fail the power up test in some way. It is useful to separate these failures into the two categories listed below.

- 1) Instrument "hangs up" and does not complete the power up test.
- 2) Instrument completes the power up test with a return code.

Troubleshoot the circuits on the A40 Assembly in the order given in Table 7-29. In this table, level one circuits must be operational before level two circuits can be tested and so on. Instrument "hang up" failures usually indicate level one through four circuits, while return code failures usually indicate level five or six failures.

NOTE

To disable the beeper, the A60 Assembly can be removed while troubleshooting the A40 Assembly. Removing the A60 Assembly also disables the display.

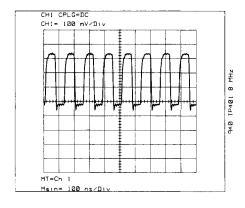
LEVEL	Functional Blocks	
1	Clock: R	
	Power on Reset: Q	
2	Clock Divider: S	
3	Interrupt Priority Encoder: A	
4	Microprocessor: D	
	Address Strobe Delay: H	
	Data Acknowledge Generator: J	
	Processor Data Bus: G	
	Bus Error Detector: E	
5	Processor Address Bus: C, B	
	Power Up Test ROMs: P	
6	All other circuits on the A40 Assembly	

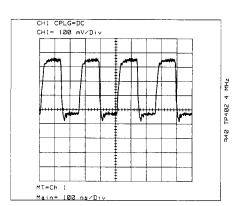
Table 7-29 A40 Circuit Troubleshooting Order

[R] CLOCK

Check the clock waveforms at test point A40TP401 and test point A40TP402 given in Figure 7-26.

Figure 7-26 A40 Clock Waveforms





Probe: 10:1

Ch1: Connection- A40TP401 "8 MHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A40TP402 "4 MHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

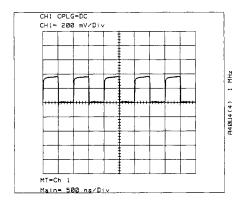
[Q] POWER ON RESET

- 1. Move test jumper A40W3 to the test position.
- 2. Short the two pins of the reset test point (TP2) together.
- 3. Check the RESET signal and the HALT signal at U6(18) and U6(17). Both of these should be TTL low.
- 4. Remove the short from the reset test point (TP2) and re-check RESET and HALT signals. These signals should now be TTL high.
- 5. Move test jumper A40W3 to the normal position.

[S] CLOCK DIVIDER, [A] INTERRUPT PRIORITY ENCODER

- 1. Turn the -hp-3561A LINE power switch OFF and move test jumper A40W2 to the test position.
- 2. Turn the -hp-3561A LINE power switch ON and check the waveforms given in Figure 7-27.
- 3. Move test jumper A40W2 to the normal position.

Figure 7-27 Clock Divider and Interrupt Waveforms

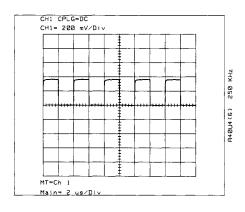


Probe: 10:1

Ch1: Connection- A40U4(4) "1 MHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



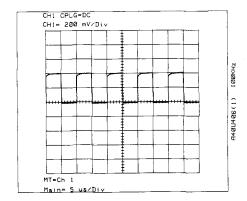
Probe: 10:1

Ch1: Connection- A40U4(6) "250 kHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Service

Model 3561A

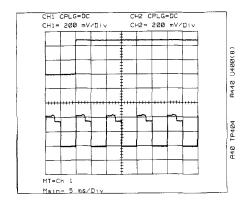


Probe: 10:1

Ch1: Connection- A40U406(1) "100 kHz" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



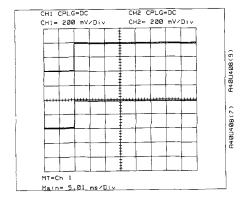
Probe: 10:1

Ch1: Connection- A40U400(8) "TINT" Coupling- dc Ground- Third Graticule From Top

Ch2: Connection- A40TP404 "100 Hz"
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope- Negative

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A40U408(9)
Coupling- dc
Ground- Third Graticule From Top

Ch2: Connection- A40U408(7)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal- Ch1
Slope- Negative

[D] MICROPROCESSOR, [H] ADDRESS STROBE TIMING DELAY, [J] DATA ACKNOWLEDGE GENERATOR, [E] BUS ERROR DETECTOR

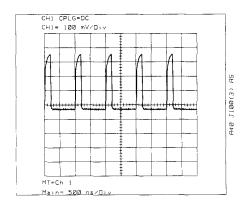
These circuits form the basic processor bus cycle loop. A failure in any one of these circuits will cause the the processor to lock up and all of the signals will go to a static state. The basic processor loop consists of U3, U4, U8, U9, U405, U409 and the microprocessor itself U6.

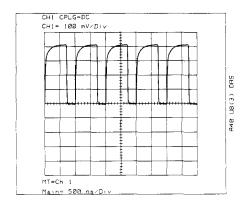
- 1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.
- 2. Turn the -hp-3561A LINE power switch ON and check the processor input signals listed in Table 7-30. All of these signals must be correct before proceeding with the next step.
- 3. Check the waveforms given in Figure 7-28.
- 4. If all of these signals are stuck in a static state, replace U3 and re-check the waveforms given in Figure 7-28. Repeat this process for U4, U8, U9, U405, and U409. If the processor loop test is still failing, the failure is most likely in the processor itself, replace U6.

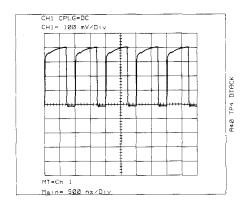
Table 7-30 Processor Loop Test Input Signals

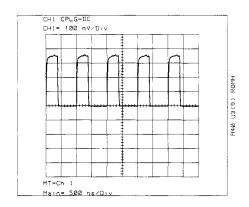
Signal Name	Signal Position	Signal State (TTL Level)
	U402(8)	high
	U401(11)	low
	U403(11)	high
BERR	U6(22)	high
HALT	U6(17)	high
RESET	U6(18)	high
D0	U6(5)	low
D1	U6(4)	high
D2	U6(3)	high
D3	U6(2)	high
D4	U6(1)	high
D5	U6(64)	high
D6	U6(63)	high
D 7	U6(62)	high
D8	U6(61)	low
D9	U6(60)	high
D10	U6(59)	high
D11	U6(58)	high
D12	U6(57)	high
D13	U6(56)	high
D14	U6(55)	high
D15	U6(54)	low

Figure 7-28 Processor Loop Test Waveforms









Probe: 10:1

Ch1: Connection- A40J100(3) "AS" A40U6(8) "PLDS" A40U6(7) "PUDS"

Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A40U8(3) "DAS" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A40TP4 "DTACK" Coupling- dc Ground- Center Graticule

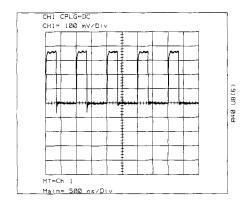
Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A40U3(9) "ROMH" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive



Probe: 10:1

Ch1: Connection- A40U8(6) "FIOH" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF

[C] PROCESSOR ADDRESS BUS, [O] ROM ADDRESS DECODERS, [P] POWER UP TEST ROM, [G] PROCESSOR DATA BUS

The power up test software is stored in the first two ROMs, U106 and U502. These ROMs must be operational before the power up test can be run. This test checks all of the circuits used to address and read data from the first two ROMs. All other ROM failures are detected through return codes in the power up test.

- 1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.
- 2. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-31.

Table 7-31 A40W2 Test Signatures

Signature Analyzer Setup			
Signal	Polarity	Connection	
CLOCK START STOP	Ź	J100(3) "AS" J100(5) J100(4)	
+5 V Signature -	00UP		
Processor Address	Bus	Processor Address Bu	s Buffers
U6(29) U6(30) U6(31) U6(32) U6(33) U6(34) U6(35) U6(36) U6(37) U6(38) U6(39) U6(40) U6(41) U6(42) U6(43) U6(44) U6(45) U6(46) U6(47) ROM Address Dec U605(7) U605(9) U605(10) U605(11) U605(12) U605(13) U605(14) U605(15)	60FF 3700 6935 3PC9 FO9A 6U02 H369 7F70	U500(3) U500(5) U500(7) U500(9) U500(12) U500(14) U500(16) U500(18) U503(3) U503(5) U503(7) U503(9) U503(12) U503(14) U503(16) U503(18)	PPP1 H42C 000U 0055 0033 UUUU 4074 89F1 P625 U540 9C51 PC1A 7U42 15HU 31PC 34C1
U606(10) U606(11) U606(12) U606(13) U606(14) U606(15)	9A8F FU6U 30P7 9C01 341C 9UHH		

Table 7-31 A40W2 Test Signatures (Cont'd)

Power on Test ROMs (U106, U502) and Processor Data Bus Signature Analyzer Setup				
CLOCK START STOP		TP501 "RCS0" J100(5) J100(4)		
+5 V Signature -	1180			
U106(11) U106(12) U106(13) U106(15) U106(16) U106(17) U106(18) U106(19)	1H75 4PP8 1180 AC06 H161 AP7C A6CP	U502(11) U502(12) U502(13) U502(15) U502(16) U502(17) U502(18) U502(19)	1PU7 A506 47CF 01P8 3C9C 9C3A 771A A33F	

[P] ROM

If all tests to this point have passed, the -hp-3561A power up test will be operational. To check the remaining ROMs run the power up test. The return codes and corresponding failed ROMs are listed in Table 7-32.

Table 7-32 Power-on Test ROM Return Codes

Return Code	Failed ROM
0 1 01	U502
0 1 02	U106
0 1 03	U600
0 1 04	U200
0 1 05	U601
0 1 06	U201
0 1 07	U602
0 1 08	U202
0 1 09	U603
0 1 10	U203
0 1 11	U700
0 1 12	U302
0 1 13	U701
0 1 14	U303
0 1 15	U702
0 1 16	U304
0 1 17	U703
0 1 18	U305
0 1 19	U704
0 1 20	U306
0 1 21	U301
0 1 22	U300
0 1 23	U708
0 1 24	U707

[B] RAM ADDRESS BUS INTERFACE BUFFER, [G] DATA BUS BUFFERS, [L] CONTROL AND ADDRESS BUS BUFFER, [I/O ADDRESS DECODING

This test uses signature analysis to check most of the A40 Assembly I/O signals. Because this test depends only on the power supply and the processor assembly itself, any of the other assemblies can be removed without affecting the test results. If the test fails, assemblies A20, A30, A50, A60, and A65 can be removed and the test re-run to determine if one of these assemblies is loading down the A40 I/O signals.

- 1. Turn the -hp-3561A LINE power switch OFF and move test jumpers A40W2 and A40W3 to the test position.
- 2. Turn the -hp-3561A LINE power switch ON and check the signatures given in Table 7-33.
- 3. Turn the -hp-3561A LINE power switch OFF. Move test jumpers A40W2 and A40W3 back to the run position, and move test jumper A40W1 to the test position.
- 4. Turn the -hp-3561A LINE power switch ON. When the front panel LEDs begin to blink (≈10 seconds after power-on), check the signatures given in Table 7-34.

Table 7-33 Processor I/O and Address Bus Signatures

Signature Analyzer Setup			
Signal	Polarity	Connection	
CLOCK START STOP		J100(3) "AS" J100(5) J100(4)	
+5 V Signature - 0	DOUP		
I/O Decoding		Processor Address	Bus
U504(7)	9СОН	U501(3)	0000
U504(9)	5108	U501(5)	H42C
U504(10)	6A18	U501(7)	000U
U504(11)	HU98	U501(9)	0055
U504(12)	1U5P	U501(12)	0033
U504(13)	U4UC	U501(14)	UUUU
U504(14)	HFA1	U501(16)	4074
U504(15)	488H	U501(18)	0000

Table 7-34 Processor Data Bus and RAM Address Bus Signatures

Signature Analyze	r Setup		
Signal	Polarity	Connection	
CLOCK		TP500 "FPS"	
START	$\overline{}$		thode of Green LED)
STOP	>		thode of Green LED)
+5 V Signature -	5UAH		
Processor Data Bu	ıs		
U105(2)	AHC7	U102(2)	U549
U105(3)	UPA8	U102(3)	7P9A
U105(4)	U81U	U102(4)	750U
U104(5)	6F50	U102(5)	C11U
U105(6)	33PP	U102(6)	9FH6
U105(7)	2887	U102(7)	F8AP
U105(8)	4949	U102(8)	H51A
U105(9)	P6F9	U102(9)	5PU4
Signature Analyze	er Setup		
Signal	Polarity	Connection	
CLOCK		A40TP406 "PBG"	
START		J100(5)	
STOP		J100(4)	
		NOTE	
	e signatures require an A30 ator installed in the -hp-35	Assembly with a properly ope 61A.	rating RAM bus
+5 V Signature -	5UAH		
RAM Address Bus			
U705(3)	U92U	U706(3)	C8F3
U705(5)	H5CC	U706(5)	7P99
U705(7)	C78P	U706(7)	00U3
· · · · · · ·	H18F	U706(9)	79U0
U705(9)		U706(12)	P4CA
U705(9) U705(12)	34H8		
U705(12)	34H8 P931		
U705(12) U705(14)	P931	U706(14)	A516
U705(12)			

Table 7-35 A40 Assembly Signal Connections

INPUTS

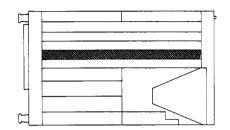
Signal Name	Functional Block	Connector Number	Origin Assembly
BUBI	A	P41(A5)	A65
DMAI	A	P41(A7)	A20
DSPH	J	P41(B5)	A60
FFTI	A	P41(A8)	A30
HPCI	A	P41(B7)	A50
HPDI	A	P41(B6)	A50
LOW + 5	Q	P42(B13)	A70
PBG	Ĺ	P42(B16)	A30
PWR FAIL	A	P41(B4)	A71
SINT	A	P41(B12)	A50

OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assembly
BUBS	М	P41(A10)	A65
CMOSS	M	P41(B10)	A65
DSPS	M	P41(A9)	A60
FPS	M	P41(B8)	A81
HPIBS	M	P41(B11)	A50
LOS	M	P41(A11)	A50
PBLDS	L	P41(A12)	A30
PBR	i	P42(A16)	A30
PBUDS	L	P41(A13)	A30, A50
PRAMRE	1	P41(A4)	A30
PRIOS	Į.	P42(B17)	A30
RESET	Q	P41(B3)	A20, A30, A50,
			A60, A66/65, A81
100 kHz	S	P41(A3)	A30
4 MHz	R	P41(B2)	A50, A66/65
20.48 MHz	V	P41(A2)	A15, A20, A30

I/O SIGNALS

Signal Name	Functional Block	Connector Number	Destination Assembly
Processor Address			
Bus	L	P41(A14 - A16)	A50, A60, A66/65
PABO - PAB5		P41(B14 - B16)	
Processor Data Bus	G	P41(A17 - A24)	A30, A50, A60,
PDB0 - PDBF		P41(B17 - B24)	A65/66
RAM Address Bus	В	P42(A4 - A11)	A20, A30
RABO - RABF		P42(B4 - B11)	



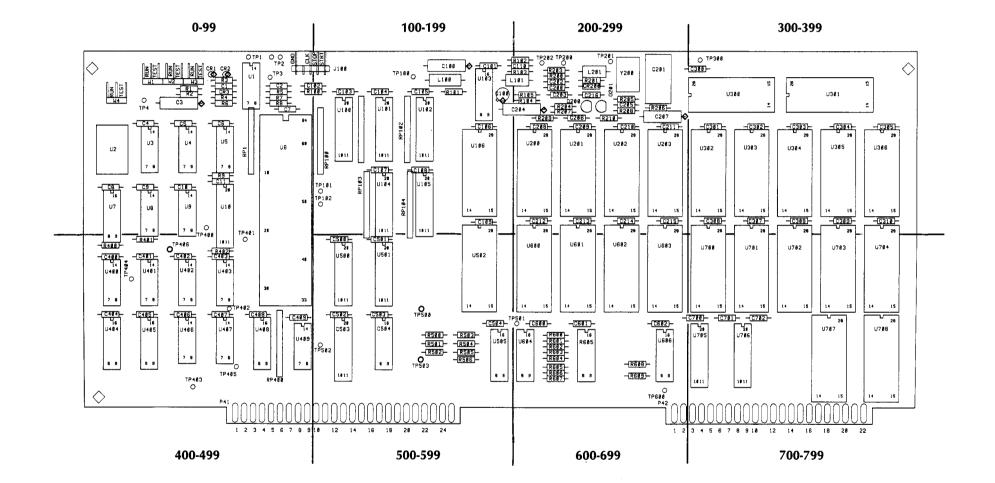
A40 Assembly Test Jumpers W1, W2, W3, and W4



Test Position

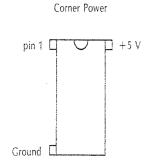


Run Position

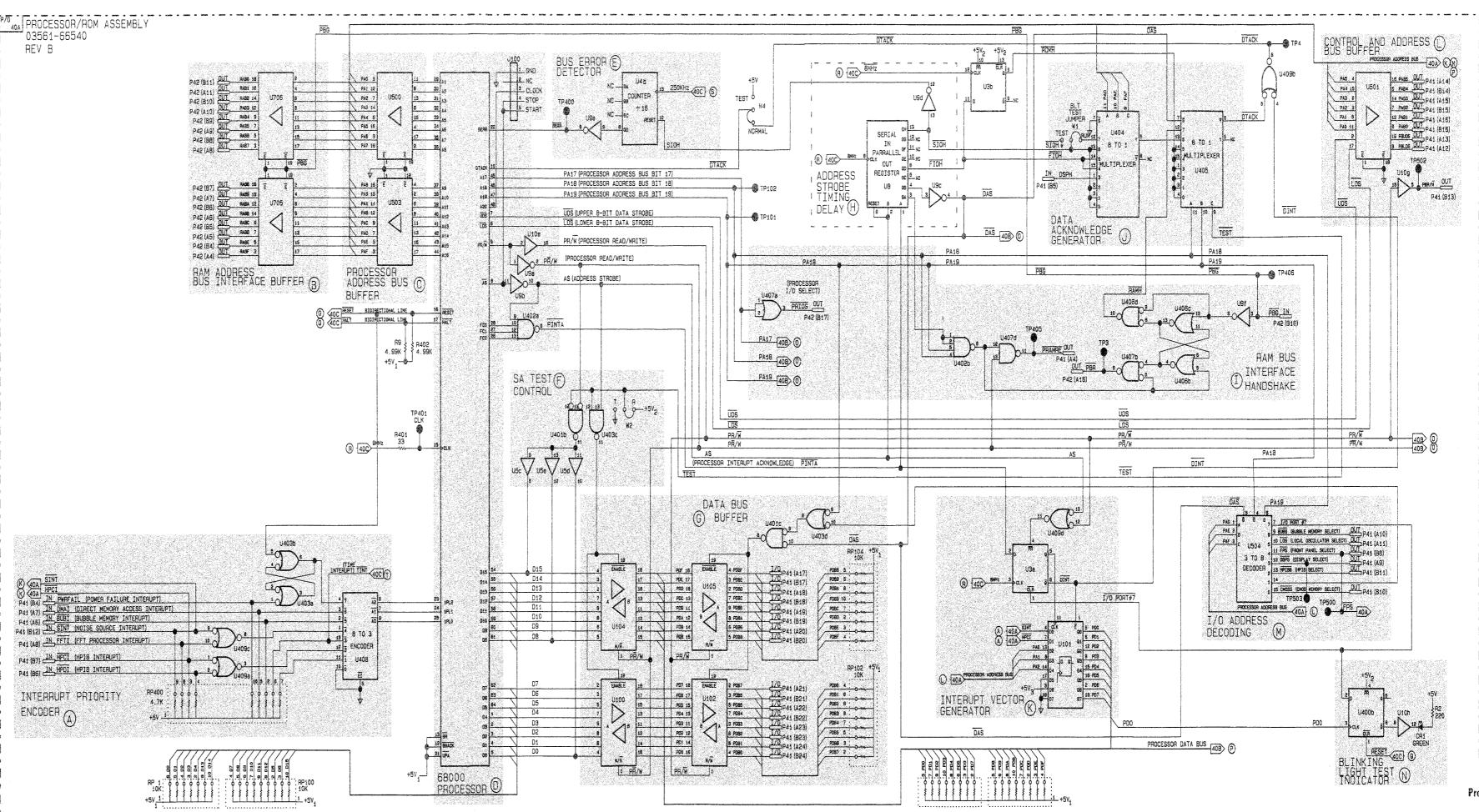


A40 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)

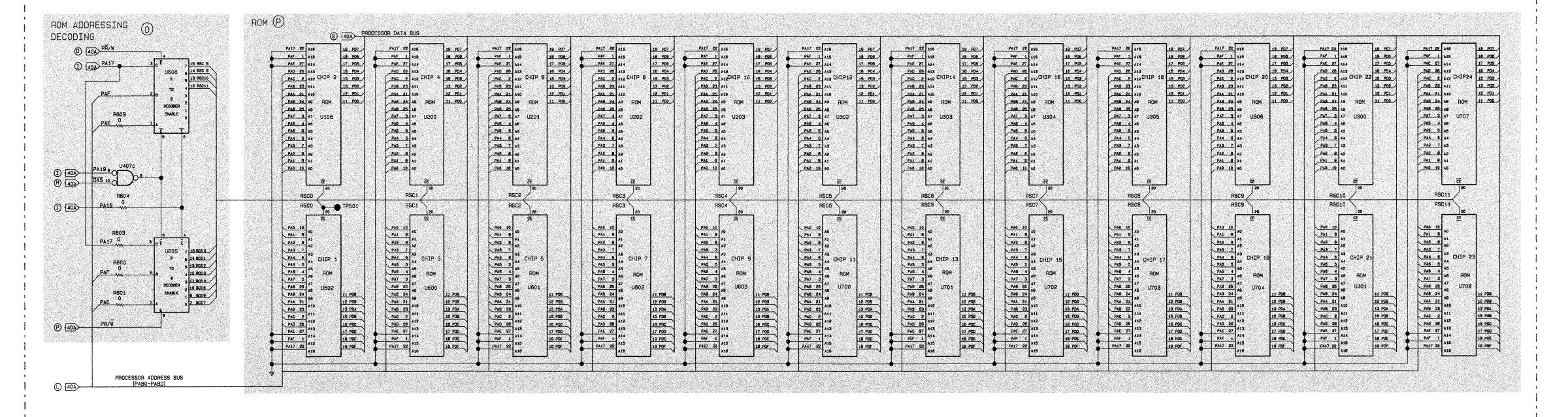


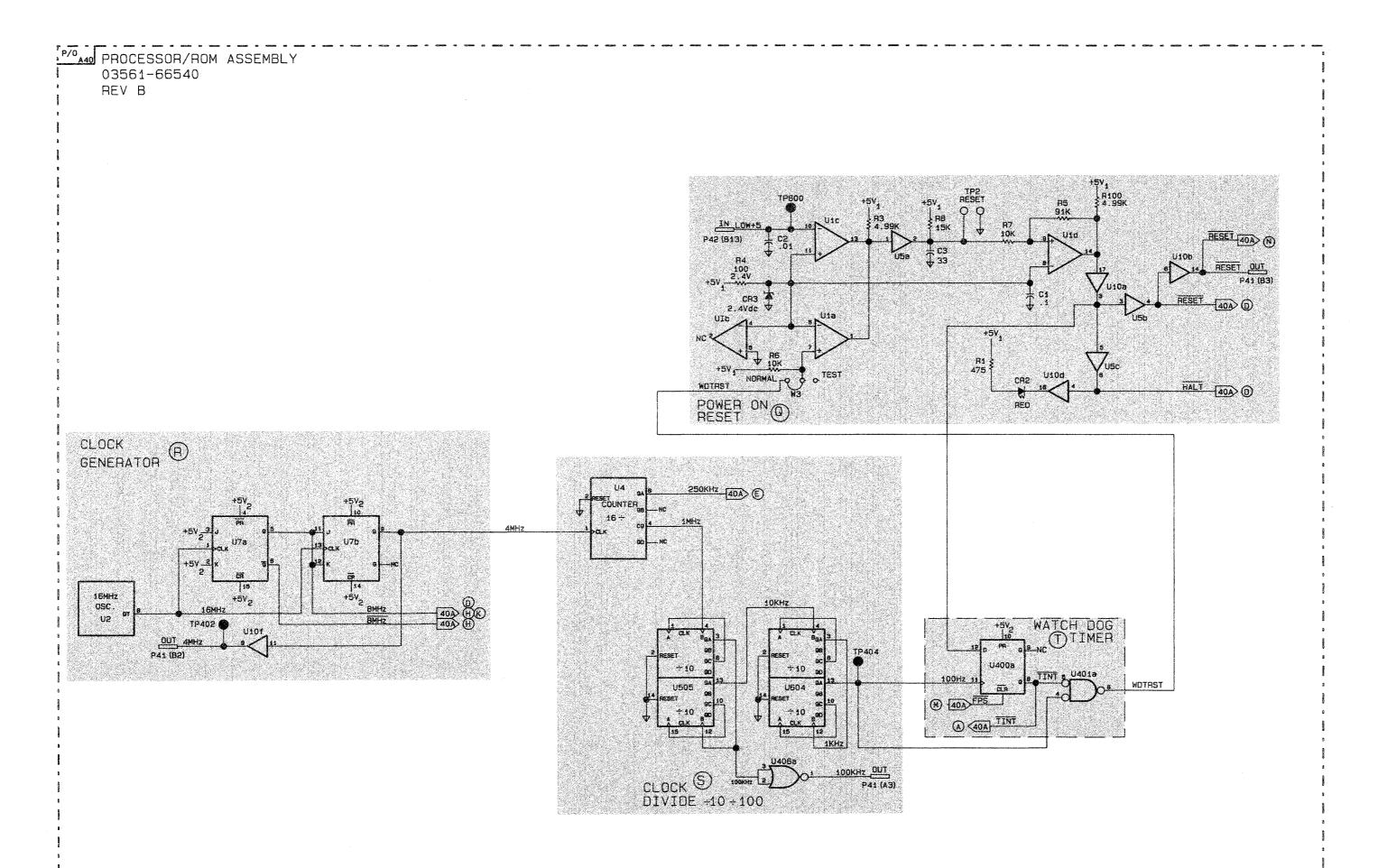
	+5V1	+ 5V4	GND
U1		5	12
U6 U103	14,49	16,53 16	7



Schematic A40A
Processor/ROM Assembly

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Schematic A40D Processor/ROM Assembly 7-121/7-122

7-19 A50 LOCAL OSCILLATOR/NOISE SOURCE ASSEMBLY

7-20 Local Oscillator/Noise Source Circuit Description

GENERAL

The A50 Assembly contains three separate operational circuits. They are:Local Oscillator, Noise Source and HP-IB. These circuits are described in general in the following three paragraphs and in detail after that.

The Local Oscillator is used when measuring in the zoom mode. It is set to the center frequency value of the zoom measurement and mixed with the incoming signal. The generated result is then FFTed and displayed. It is also used to shift the frequency band of the noise source so the resulting frequency content of the noise will track that of the measurement span.

The Noise Source generates random, periodic random and impulse signals which are band limited as determined by the frequency span of the measurement. The output is connected to the rear panel SOURCE BNC.

The HP-IB circuitry uses an Integrated Circuit to interface the -hp-3561A with the IEEE-488-1978 interface bus.

The theory that follows describes the functional blocks of each of the three previously mentioned operational circuits. Table 7-36 identifies and describes the signals used on this assembly.

[A] PHASE LATCH

The Phase Latch loads and stores the desired Local Oscillator frequency from the processor data bus. The data is actually a phase increment where 360 degrees equals 256kHz.

[B] PHASE CORRECTION

The Phase Correction contains the phase information of the local oscillator signal. This information is read by the processor so it can determine the phase of the input signal being measured.

[C] PHASE INCREMENT ADDER

This circuit adds the phase increment with the prior phase to calculate the new current phase with the increment ROM. The increment ROM performs a modulus 125 conversion of the lower 7 bits of the phase.

[D] ANGLE ACCUMULATOR

The Angle Accumulator latches the current phase angle which is fed back to the input of the Phase Increment Adder [C], to the Interpolator [J] and to the Sine Table [C].

[E] TIMING STATE MACHINE

The Timing State Machine generates the clock signals which control the timing of the A50 Assembly.

[F] QUADRANT SHIFTER

The Quadrant Shifter keeps track of which of the four quadrants (90 degrees each) the Local Oscillator is in. The states of AP18 and AP19 determine which quadrant and LOSM1 determines Sine or Cosine.

[G] SINE TABLE

These two ROMs contain both the 15 bit Sine/Cosine values for angles at increments of about 0.09 degrees, and the 8 bit slope numbers which allow the Local Oscillator to compute values for in-between angles. U507 contains the LSB bits for the sine values and U506 contains the MSB bits for the sine values along with the 8 bit slope numbers.

[H] SLOPE DATA REGISTER

This circuit is a parallel-in serial-out register which loads the Slope information from the Sine Table circuit and shifts it out serially to the Interpolator [J].

[I] SINE DATA REGISTER

This is a parallel-in serial-out circuit which loads in the sine data from the sine table and shifts it out to the Interpolator [J].

[J] INTERPOLATOR

The Interpolator circuit takes the slope information and the quadrant information and calculates the sine values for the 250 points between the sine points stored in the sine table ROMs. The interpolated result is output to the Local Oscillator Output [L].

[K] GCLOCK GENERATOR

The GCLOCK signal is the main A50 Assembly clock. In normal operation, it runs at 10.24 MHz. When the -hp-3561A operates in External Sample Rate, GCLOCK becomes a pulse train of 40 pulses, each train comprising one complete Local Oscillator cycle. Each train is started by a rising edge of SYNC2. SYNC2 may not exceed 256kHz.

[L] LOCAL OSCILLATOR OUTPUT

The Local Oscillator Output circuit has three data outputs: +COSINE, -SINE and Local Oscillator Output. The +COSINE and -SINE are used to set the center frequency of a zoom measurement. The Local Oscillator Output is used to shift the frequency band of the Noise Source such that the noise source frequency content falls within the bandwidth of the zoom measurement.

[M] I/O CONTROL PORT

This circuit latches processor data bits 0 through 7 which are then used by the A50 Assembly as control signals.

- [N] CLOCK
- [O] SERIAL FEEDBACK REGISTERS
- [P] NOISE SOURCE ROM ADDRESS REGISTERS

In random mode, the Serial Feedback Registers and the Noise Source Address Registers form a 36 bit shift register. Input bits are generated by Exclusive ORing bits 13 and 33 and inverting the result. In effect, the circuit is a digital tapped delay line.

In Pseudo-random and Impulse modes, the Noise Source ROM Address Registers form a 12 bit counter which steps through the 4096 baseband or 2048 zoom points.

[Q] RANDOM NOISE ROM [R] PERIODIC NOISE ROM

ROM U700 takes the fourteen address bits and filters them by doing a weighted sum. Bits 6 and 7 weigh most heavily, bits 0 and 13 are weighted the least. U700 contains the sequences for a random signal. U701 contains the sequences for periodic random and impulse signals but does not act as a filter.

[T] CLOCK SYNCHRONIZING LATCH

This circuit latches the data from the noise ROMs and at the correct time, shifts the data out to the mixer circuitry.

[W] LOCAL OSCILLATOR/NOISE SOURCE MIXER [X] LOCAL OSCILLATOR INTERFACE

U201 takes the parallel Local Oscillator data and shifts it out serially to U704 where it is multiplied by the noise data. In Zoom, the Local Oscillator data shifts the frequency spectrum of the noise data so it is centered around the measurement's center frequency.

[AA] SERIAL TO PARALLEL CONVERTER [CC] D TO A CONVERTER [FF] PROGRAMMABLE LOG ATTENUATOR

The noise data is converted from serial to parallel by U306 and latched by U307. The digital parallel output is then converted to an analog signal by U402 and buffered by U403. The analog output is then fed to a log programmable attenuator U400.

Table 7-36 A50 Assembly Signal Descriptions

Signal	Description
BBS	BaseBand Sync: Indicates the end of a baseband record.
BB/ZOOM	BaseBand/ZOOM: Signal from the processor used to setup the A50 Assembly for Baseband or Zoom measurements.
CSR1 THROUGH CSR4	Chip Select Read 1 through 4: Processor Address signals used to enable various ports to output their data.
CSW1 THROUGH CSW4	Chip Select Write 1 through 4: Processor Address signals used to enable various ports to input data.
ESR*4	Effective Sample Rate multiplied by 4: Used by the A50 Assembly as a clock. The effective sample rate is the ADC sample rate clock.
GCLOCK	Gated CLOCK: This is the main processing clock for the A50 Assembly. It is a 40 pulse clock train running at 256kHz.
TOS	Local Oscillator Select: Processor Address signal used to access the A50 Assembly input and output ports.
LOSM1 THROUGH LSOMB	Local Oscillator State Machine 1 through 8: 8 Clocks generated by the A50 State Machine which provide the timing for the A50 Assembly.
NB0 THROUGH NB7	Noise Bit 0 through 7: 8 Data bits output by the two noise ROMs.
PER/IMP	PERiodic/IMPulse: Processor setup signal used in conjunction with the RANDOM signal to enable either the periodic or the impulse noise output.
RANDOM	RANDOM: Processor setup signal used to enable the A50 Assembly to be in the random or periodic/impulse mode of operation.
SB0 THROUGH SBD	Source Bits 0 through D: 14 Address bits which are generated by the ROM Address Counter circuit and are used to address the data locations within the Noise ROMs U700 and U701.
SYNC2	SYNC2: Sample rate clock from the A20 Assembly. A rising edge triggers one cycle of the Local Oscillator. When cycled, the A50 Assembly outputs one complex value to the Digital Filters and one real value to the source.
TRIG0 TRIG1	TRIGger0 and TRIGger2: Processor signals which determine which trigger source the -hp-3561A will use. This circuit function runs independently of the rest of the A50 Assembly.
ZPH TRIGGER	Zoom PHase TRIGGER: Processor signal used to latch information into the phase correction latches.
ZS	Zoom Sync: Used in the Zoom mode to indicate the end of a record. This signal has the same function the BBS signal has in Baseband measurements.

7-21 Troubleshooting The Local Oscillator/Noise Source

GENERAL

Level

1

2

3

4

5

Although there are only three major operational circuits, there are eight separate subcircuits. The troubleshooting procedure will be to verify proper operation of particular subcircuits, one at a time, in order of dependency. Table 7-37 lists the order of dependency. In this table, level one circuits must be operational before level two circuits can be checked, etcetera. Test Routines 150, 151, 152, 153 and 154 will be used to troubleshoot this assembly. Troubleshooting consists of verifying waveforms with an oscilloscope and Digital Signature Analysis. Also, some user-programmable parameters entered via the front panel keys are used to preset circuit conditions.

Processor Address Decoding: S
I/O Control Port: M
GCLOCK Generator: K
Timing State Machine: E
Local Oscillator Circuitry: A, B, C, D, E, F, G, H, I, J, K, L
Local Oscillator Interface: X

Noise Source Circuitry: N, O, P, Q, R, T, U, V, W, Y, Z, AA, BB, CC, EE, FF, HH, II

Table 7-37 A50 Circuit Troubleshooting Order

[S] PROCESSOR ADDRESS DECODING

HP-IB I/O Circuitry: DD, GG

Troubleshoot this circuit using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U501 while running or starting and stopping the diagnostic test.

1. Program the -hp-3561A in Test Routine 150 by pressing the following front panel keys:

- 2. Initiate continuous testing by pressing the START CONT TST softkey.
- 3. Use the logic probe and verify that U501(12,13,14,15) are toggling. If they are not, replace U501.
- 4. Stop the test by pressing the softkey STOP TEST.
- 5. Place the logic probe on U501(10, 11) one at a time and press the soft key START SNGL TST. These pins should pulse low when the test routine is initiated. If they do not, replace U501.

[M] I/O CONTROL PORT

Troubleshoot this circuit using the Signature Analyzer as a logic probe. The procedure will be to monitor U602(6,9,12,16) while initiating particular measurement parameters.

- 1. Press the front panel PRESET key.
- Press the front panel TRIG SEL key to display the trigger selection menu on the CRT.
- 3. Use the logic probe to verify that U602(6,9) are low.
- 4. Press the softkey FREE RUN/TRIGGER so TRIGGER is highlighted.
- 5. Probe U602(6,9) and press the softkey EXTERNAL TRIGGER and verify that they go high. Press the softkey INTERNAL TRIGGER and verify that they go low. If not, replace U602.
- 6. Press the front panel PRESET key.
- 7. Press the front panel SOURCE key to display the source selection menu on the CRT.
- 8. Use the logic probe to verify that U602(12) is high and U602(16) is low.
- 9. Probe U602(12,16) and press the softkey IMPULSE and verify that they change state. Pin 12 should go low and pin 16 should go high. If not, replace U602.

[K] GCLOCK GENERATOR

Troubleshoot this circuit by using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U500 and U505 for a toggling condition with the -hp-3561A running in the PRESET state.

- 1. Press the front panel PRESET key.
- 2. Use the logic probe and verify that U500(1,3,6) and U505(1,6,9,11) are toggling.
- 3. If U500(1) is not toggling, check U807(1) for a toggling condition. If it is not toggling, there may be a failure in the Timing State Machine. Troubleshoot that circuit.
- 4. If any of the pins are not toggling, replace the suspected IC.

[E] TIMING STATE MACHINE

Troubleshoot this circuit by using the Signature Analyzer as a logic probe. The procedure will be to monitor the pins of U606 for a toggling condition while the -hp-3561A is operating in the PRESET state.

- 1. Press the front panel PRESET key.
- 2. Use the logic probe and verify that U606(6,7,8,9 and 12 through 19) are toggling.
- 3. If any are not, replace the suspected IC. Also note that the outputs of U606 (LOSM1 through LOSM8) clock other functional circuits which may be holding these output lines low or high.

LOCAL OSCILLATOR CIRCUITRY

Troubleshooting this circuitry consists of verifying signatures with a Signature Analyzer while running a diagnostic test routine. The Local Oscillator Functional Circuits are listed below along with the table which contains their correct signatures.

[A] Phase Latch	Table 7-38
[B] Phase Correction	Table 7-38
[C] Phase Increment Adder	Table 7-38
[D] Angle Accumulator	Table 7-38
[F] Quadrant Shifter	Table 7-38
[G] Sine Table	Table 7-39
[H] Slope Data Register	Table 7-40
[I] Sine Data Register	Table 7-40
[J] Interpolator	Table 7-40
[L] Local Oscillator Output	Table 7-40

1. Program the -hp-3561A into Test Routine 150 by pressing the following front panel keys:

- 2. Initiate continuous testing by pressing the START CONT TST softkey.
- 3. Check the signatures given in Table 7-38 to troubleshoot those functional circuits listed.
- 4. Check the signatures given in Table 7-39 to troubleshoot the Sine Table ROMs. Note that there are two setups for the Signature Analyzer Clock. Both setups must be checked.
- 5. Check the signatures given in Table 7-40 to troubleshoot those functional circuits listed.

Table 7-38 Local Oscillator Signatures For Functional Circuits [A], [C], [D] And [F]

Signature Analyzer Setup				
Signal	Polarity	Connection		
Clock	<i>{</i>	A50 J1 "LOSM1"		
Start		A50 J100 "STRT"		
Stop	~	A50 J100 "STOP"		
+5 V Signature -	5C1C			
[A] Phase Latch C	ircuit	[C] Phase Increme	nt Adder Circuit	
U504(2)	8UA8	U6(1)	15F1	
U504(5)	6P45	U6(4)	H2A1	
U504(6)	9231	U6(10)	HFUC	
U504(9)	F7H4	U6(13)	1FP8	
U504(12)	41C4			
U504(15)	CU8P	U8(1)	486U	
U504(16)	157F	U8(4)	U914	
U504(19)	564F	U8(10)	4949	
		U8(13)	7098	
U600(2)	46U9			
U600(5)	5H83	U9(1)	40AP	
U600(6)	CF6P	U9(4)	5A19	
U600(9)	U0AC	U9(10)	4894	
U600(12)	A54P	U9(13)	<i>7</i> 1 <i>77</i>	
U600(15)	232P			
U600(16)	HH14	U106(1)	FFU2	
U600(19)	77P6	U106(4)	84AP	
		U106(10)	HOFP	
U601(2)	2951	U106(13)	C804	
U601(5)	8ACP			
U601(6)	2C26	U107(1)	UC4H	
U601(9)	5C1C	U107(4)	3PHC	
U601(12)	5C1C (HIGH)	U107(10)	00F9	
		U107(13)	199C	

Table 7-38 Local Oscillator Signatures for Functional Circuits [A], [C], [D] and [F] (Cont'd)

[D] Angle Accumulator Circuit		[F) Quadrant Shifter Circuit		
U1(2)	384F	U5(1)	3C12	
U1(5)	24A4	U5(4)	H56U	
U1(7)	6950	U5(10)	5C1C	
U1(10)	8AP0	U5(13)	7F80	
U1(12)	8P74			
U1(15)	PP7H			
U102(2)	F257			
U102(5)	5A27			
U102(6)	FOUA			
U102(9)	U125			
U102(12)	C715			
U102(15)	F785			
U102(16)	HAA1			
U102(19)	AU52			
U105(2)	AH0F			
U105(5)	2057			
U105(7)	38CC			
U105(10)	A44A			
U105(12)	UF8A			
U105(15)	A437			

Table 7-39 Local Oscillator Signatures For Functional Circuit [G]

There are two Signature Analyzer setups necessary to check the ROMs. Both setups are given along with the signatures. If there is a signature mismatch in either setup, replace the defective ROM.

Signature Analyzer Setup #1

	·	Connection		
Clock		A50 J1 "LOSM6"		
Start		A50 J100 "STRT"		
Stop	~	A50 J100 "STOP"		
+5 V Signature - 75	576			
U506(9)	4209	U507(9)	UPPC	
U506(10)	111H	U507(10)	330P	
U506(11)	2C70	U507(11)	34FA	
U506(13)	C1AP	U507(13)	9CP5	
U506(14)	45FH	U507(14)	UP0F	
U506(15)	HC46	U507(15)	C525	
U506(16)	H148	U507(16)	06U3	
U506(17)	0000	U507(17)	3AU3	
• •				

Signal	Polarity	Connection
Clock Start Stop	>-	A50 J1 "LOSM6" A50 J100 "STRT" A50 J100 "STOP"

+5 V Signature - 7576

U506(9)	C941	U507(9)	UPPC
U506(10)	3H95	U507(10)	330P
U506(11)	41HP	U507(11)	34FA
U506(13)	11 U5	U507(13)	9CP5
U506(14)	H401	U507(14)	UP0F
U506(15)	05F7	U507(15)	C525
U506(16)	49P9	U507(16)	06U3
U506(17)	UH5A	U507(17)	3AU3

Table 7-40 Local Oscillator Signatures For Functional Circuits [H], [I], [J] And [L]

There are two Signature Analyzer setups necessary to fully check functional circuit [J] Interpolator. The first setup is used to check all four functional circuits while the second setup is only used as a second check for functional circuit [J]. Signature Analyzer Setup #1 Signal **Polarity** Connection A50 J100 "CLK" Clock A50 J100 "STRT" Start A50 J100 "STOP" Stop +5 V Signature - C21U [H] Slope Data Register [L] Local Oscillator Output U200(3) C97H U7(2) **UFAA CUPA** U200(7) 5220 U7(12) 1HAH U200(8) [I] Sine Data Register U200(9) PO96 C3F0 6P07 U502(13) U200(10) 5P3U U502(15) **AUC8** U200(11) U200(13) 717C []] Interpolator U200(14) A75H U101(6) 3UAU U200(15) U8C3 0460 U4(3) U4(10) 0813 The following Signature Analyzer setup is for functional circuit [J] Interpolator only. Signature Analyzer Setup #2 Signal **Polarity** Connection A50 J100 "CLK" Clock A50 J100 "STRT" Start A50 J100 "STOP" Stop +5 V Signature - C21U [J] Interpolator

U3(2)

U3(9)

2F80

49C5

[X] LOCAL OSCILLATOR INTERFACE

Troubleshoot this circuit by verifying the signatures with a Signature Analyzer while running Diagnostic Test Routine 150.

1. Program the -hp-3561A into Test Routine 150 by pressing the following front panel keys:

- 2. Initiate the continuous testing by pressing the START CONT TST softkey.
- 3. Check the signatures given in Table 7-41 to troubleshoot Functional Circuit [X].

Table 7-41 Local Oscillator Interface Signatures For Functional Circuit [X]

Signature Analyzer Setup					
Signal	Polarity	Connection			
Clock		A50 J100 "CLK"			
Start		A50 J100 "STRT"			
Stop	$\overline{}$	A50 J100 "STOP"			
[X] Local Oscillato	r Interface				
[X] Local Oscillato	r Interface				
U201(12)	6P58				
U302(8)	5220				
U302(11)	0000				

NOISE SOURCE CIRCUITRY

There are two techniques used to troubleshoot the Noise Source circuitry. The first is to use an oscilloscope to check analog waveforms while running Diagnostic Test Routine 151. This Test Routine programs the Noise Source to output a 250 Hz Sinewave and is used to troubleshoot the analog portion of the Noise Source circuitry. The second technique is to use a Signature Analyzer to verify the proper operation of the digital portion of the Noise Source. Test Routines 150, 152 and 153 are used for Signature Analysis troubleshooting.

The Noise Source Functional Circuits are listed below in the order in which they should be checked. Also listed is the table or figure which contains their correct signatures or waveforms.

Note that the troubleshooting order does not match the table order. Instead, the tables are organized as determined by the Signature Analyzer Setup.

[O] Serial Feedback Registers	Table 7-42
[P] Noise Source ROM Address Counters	Table 7-42
[Q] Random Noise ROM	Table 7-43
[R] Periodic Noise ROM	Table 7-42
[T] Clock Synchronizing Latch	Table 7-42
[W] Local Oscillator/Noise Source Mixer	Table 7-44
[AA] Serial To Parallel Data Converter	Table 7-44
[CC] D/A Converter	Figure 7-29
[FF] Programmable Log Attenuator	Figure 7-30
[HH] 100kHz Lowpass	Figure 7-31
[II] Output	Figure 7-32
[EE] Noise Source Sync Generator	Table 7-43
[Y] Trigger Select	Table <i>7-</i> 43

1. Program the -hp-3561A into the proper Test Routine, as determined by the table, by pressing the following front panel keys:

MODE TEST SELECT..... xxx ENTER

Where xxx is the Test Routine Number (150, 151, 152 or 153).

- 2. Before checking signatures or waveforms, initiate continuous testing mode by pressing the START CONT TST softkey.
- 3. Check the signatures or the waveforms given in the appropriate table to troubleshoot the functional circuits indicated by that table.

Table 7-42 Noise Source Signatures For Functional Circuits [O], [P], [R], And [T]

The following sign	natures are valid with the	-hp-3561A running Diagnostic	Test Routine 152.
Signature Analyze	er Setup		
Signal	Polarity	Connection	
Clock	<i>5</i> -	A50 J200 "CLK"	
Start	_	A50 J100 "STRT"	
Stop	~	A50 J100 "STOP"	
+5 V Signature -	5C1C		
[O] Serial Feedbac	ck Register	[P] Noise Source	ROM Address Counters
U100(7)	36U6	U204(11)	1C7C
		U204(12)	36U6
U202(3)	PH8H	U204(13)	6HPH
U202(4)	U6F6	U204(14)	36U6
U202(13)	4C81	U204(15)	0000 (LOW)
U203(13)	FFFC	U205(11)	C1C7
		U205(12)	636U
U300(10)	F3UU	U205(13)	F6HP
		U205(14)	8HCH
U302(6)	2P72	U205(15)	0000 (LOW)
U801(4)	6НРН	U206(11)	HC1C
		U206(12)	C636
		U206(13)	6F6H
		U206(14)	H8HC
		U206(15)	0000 (LOW)
[R] Periodic Noise	ROM	[T] Clock Synchronizing Latch	
U701(11)	26FP	U702(2)	97AP
U701(12)	U1U8	U702(5)	A5H9
U701(13)	HP35	U702(6)	A4H9
U701(15)	8U6H	U702(9)	U0F0
U701(16)	P180	U702(12)	47C6
U701(17)	A49P	U702(15)	998F
U701(18)	4CC3	U702(16)	78UF
U701(19)	F270	U702(19)	65U1
		U806(11)	0000 (LOW)
		U807(8)	5C1C (HIGH)

Table 7-43 Noise Source Signatures For Functional Circuits [O], [Y] And [EE]

Signature Analyze	r Setup		
Signal	Polarity	Connection	
Clock Start Stop	5	A50 J200 "CLK" A50 J200 "STRT" A50 J200 "STOP"	
+5 V Signature - [Q] Random Noise		[Y] Trigger Select	
[Q] Kandoni Noise	KOM	[1] Higger Select	
U700(11) U700(12)	P103 518P	U808(7)	F748
U700(13) U700(15)	A3AP 0402	[EE] Noise Source	Sync Generator
U700(16) U700(17)	H977 UUFP	U304(9)	F748
U700(18) U700(19)	7979 H918	U305(8)	99H4
0,00(13)	11310	U500(8)	7A70 (HIGH)
		U803(6)	P3A4

Table 7-44 Noise Source Signatures For Functional Circuits [W] And [AA]

The following signatures are valid with the -hp-3561A running Diagnostic Test Routine 150. Note there are two Signature Analyzer setups for checking Functional Circuit [AA]. Signature Analyzer Setup #1 **Polarity** Connection Signal A50 J100 "CLK" Clock Start A50 J100 "STRT" Stop A50 J100 "STOP" +5 V Signature - C21U [W] Local Oscillator/Noise Source Mixer U704(6) 0AFF [AA] Serial To Parallel Data Converter PP76 U306(3) U306(4) 1F2C U306(5) P505 U306(6) 1992 U306(10) P7H9 U306(11) 18UF U306(12) P76P U306(13) 18A7 U806(6) **AH88** Signature Analyzer Setup #2 Signal **Polarity** Connection A50 J100 "CLK" Clock Start A50 J100 "STRT" Stop A50 J100 "STOP" +5 V Signature - C21U [AA] Serial To Parallel Data Converter U307(2) 42UA U307(12) 3PCP U307(5) C5P8 8P5P U307(15) U307(6) FU52 U307(16) 0AA3 U307(9) CU5A U307(19) 4U63 U801(8) C8H3

NOISE SOURCE TROUBLESHOOTING WAVEFORMS FOR FUNCTIONAL CIRCUITS [CC], [FF], [HH] AND [II].

The following troubleshooting information is valid with the -hp-3561A running Diagnostic Test Routine 151.

[CC] D/A CONVERTER

Verify the waveform at TP DAC OUT with that shown in Figure 7-29. If the waveform is incorrect, use a Logic Probe to verify that U402(5,6,7,8,9,10,11,12) are toggling. If they are, replace U402 and U403 or the analog elements around them. If they are not, troubleshoot Functional Circuit [AA].

[FF] PROGRAMMABLE LOG ATTENUATOR

Verify the waveform at U401(6) with that shown in Figure 7-30. If the waveform is incorrect, use the logic probe to verify that U400(2,3,4,5,6,7) are all low. If they are not, replace U303. If they are, replace U400 and U401.

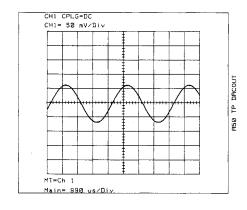
[HH] 100kHz LOWPASS

Verify the waveform at U404(6) with that shown in Figure 7-31. If the waveform is incorrect, troubleshoot this circuit.

[II] OUTPUT

Verify the waveform at U901(4) with that shown in Figure 7-32. If the waveform is incorrect, troubleshoot this circuit.

Figure 7-29 Correct Waveform At A50 TP DAC OUT.

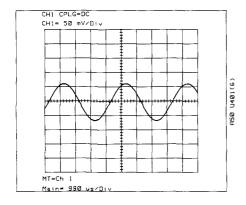


Probe: 10:1

Ch1: Connection- A50 TP DACOUT Coupling- dc Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

Figure 7-30 Correct Waveform At A50U401(6).



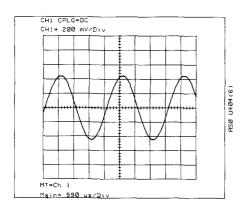
Probe: 10:1

Ch1: Connection- A50 U401(6) Coupling- dc

Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

Figure 7-31 Correct Waveform At A50U404(6).

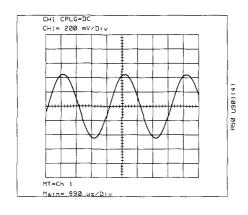


Probe: 10:1

Ch1: Connection- A50 U404(6) Coupling- dc Ground- Center Graticule

Trigger: Internal Ch1 Slope- Positive

Figure 7-32 Correct Waveform At A50U901(4).



Probe: 10:1

Ch1: Connection- U901(4)
Coupling- dc
Ground- Center Graticule

Trigger: Internal Ch1
Slope- Positive

HP-IB I/O CIRCUITRY

Test Routine 154 is used to troubleshoot the HP-IB circuitry. This test routine allows the processor to monitor the I/O pins of the HP-IB connector and display their status on the -hp-3561A CRT. While the test is running, the HP-IB connector pins must be shorted to ground one at a time. When this is done, the CRT display will so indicate. The HP-IB connector is located on the rear panel of the instrument.

Use the following procedure to initiate and operate Test Routine 154:

1. Program the -hp-3561A to run the test by pressing the following front panel keys:

PRESET		
MODE	TEST SELECT	154 ENTER
	START CONT TST	

The CRT should indicate that Test 154 is in progress and to press the STOP TEST key to abort the test. The STOP TEST key must be pressed to exit this test! Failure to do this will result in -hp-3561A operating errors. The CRT should also display the HP-IB I/O connector signal names, pin numbers and pin state in six columns as shown next:

DIO1	1	0	0	13	DIO5
DIO2	2	0	0	14	D106
DIO3	3	0	0	15	DIO7
DIO4	4	0	0	16	DIO8
EOI	5	0	0	1 <i>7</i>	REN
DAV	6	0	0	18	GND
NRFD	7	0	0	19	GND
NDAC	8	0	0	20	GND
IFC	9	0	0	21	GND
SRQ	10	0	0	22	GND
ATN	11	0	0	23	GND
SHLD	12	0	0	24	IGND

Columns one and six identify the signal names, columns two and five identify the connector pin numbers and columns three and four identify the state of the pins (O indicates high, # indicates low).

2. Short the I/O pins to chassis ground one at a time. The shorted pin will cause the CRT to display a # instead of an O next to the corresponding pin number.

For example: Short connector pin number 1 to chassis ground. This will cause the CRT to display

DIO1 1 # 0 13 DIO5

No other pins should be affected. If any other pins are affected, ground U900(19). If the CRT indicates correctly, there is a short in the I/O connector, cable or U900. If other pins are still affected, the problem may be in U805.

3. Perform step 2 for the remaining signal pins with the exception of pin 11 ATN. Proceed to step 4 for this pin.

Note that the grounding of the IGND, GND and SHLD pins will not affect the CRT display. If there is a problem with all of the pins, U805 and/or U804 may be defective.

4. When pin 11, ATN, is grounded, the CRT will display the following:

DIO1	1	Ś	,	13	DIO5
DIO2	2	Ś	?	14	DIO6
DIO3	3	Ś	?	15	DIO7
DIO4	4	Ś	;	16	DIO8
EO1	5	?	?	1 <i>7</i>	REN
DAV	6	?	Ο	18	GND
NRFD	7	?	Ο	19	GND
NDAC	8	?	Ο	20	GND
IFC	9	Ş	Ο	21	GND
SRQ	10	?	Ο	22	GND
ATN	11	#	Ο	23	GND
SHLD	12	Ο	0	24	IGND

If not, ground U805(28). If the CRT display is correct, replace U903. If the CRT is still incorrect, the problem may be U805 and/or U804.

Table 7-45 A50 Assembly Signal Connections

INPUTS

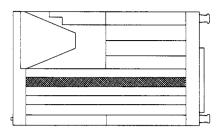
Signal Name	Functional Block	Connector Number	Origin Assembly
ESR*4	N	P51(B3)	A20
EXT TRIG	Υ	P51(A8)	A82
HPIBS	GG	P51(A11)	A40
LOS_	S	P51(A10)	A40
PBR/W	GG	P51(A13)	A40
PBUDS	GG	P51(B13)	A40
RESET	GG	P51(A3)	A40
SYNC2	Κ	P51(A5)	A20
ZPHTRIG	В	P51(A9)	A20
4 MHz	GG	P51(A2)	A40
10.24 MHz	K	P51(B2)	A20

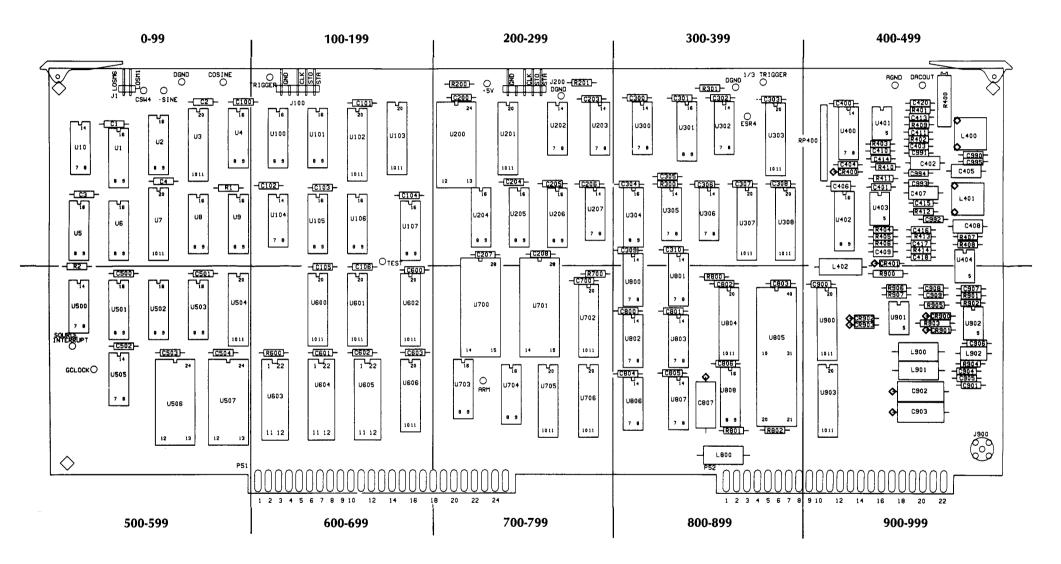
OUTPUTS

Signal Name	Functional Block	Connector Number	Destination Assemblies		
COSINE	L	P51(B8)	A20		
HPCI	GG	P51(A7)	A40		
HPDI	DD	P51(A6)	A40		
NOISE	11	P52(B21)	A82		
PRN SYNC	EE	P52(A21)	A82		
SINT	EE	P51(A12)	A40		
-SINE	L	P51(A8)	A20		

I/O SIGNALS

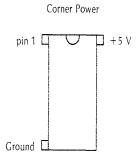
Signal Name	Functional Block	Connector Number	Destination Assembly A82		
HPIB Data Bus	GG	P52(A11 - A14)			
DIO1 - DIO8 HPIB I/O Control signals		P52(B11 - B14)			
ATN	GG	P52(A18)	A82		
DAV	GG	P52(B16)	A82		
EOI	GG	P52(B15)	A82		
IFC	GG	P52(A16)	A82		
NDAC	GG	P52(B18)	A82		
NRFD	GG	P52(B17)	A82		
REN	GG	P52(A15)	A82		
SRQ	GG	P52(A17)	A82		
Processor Address Bus	GG	P52(A16,B15,B16)	A40, A60, A66/65		
PAB0 - PAB2					
Processor Data Bus	Α	P51(A17 - A24)	A30, A40, A60,		
PDB0 - PDBF		P51(B17 - B24)	A66/65		



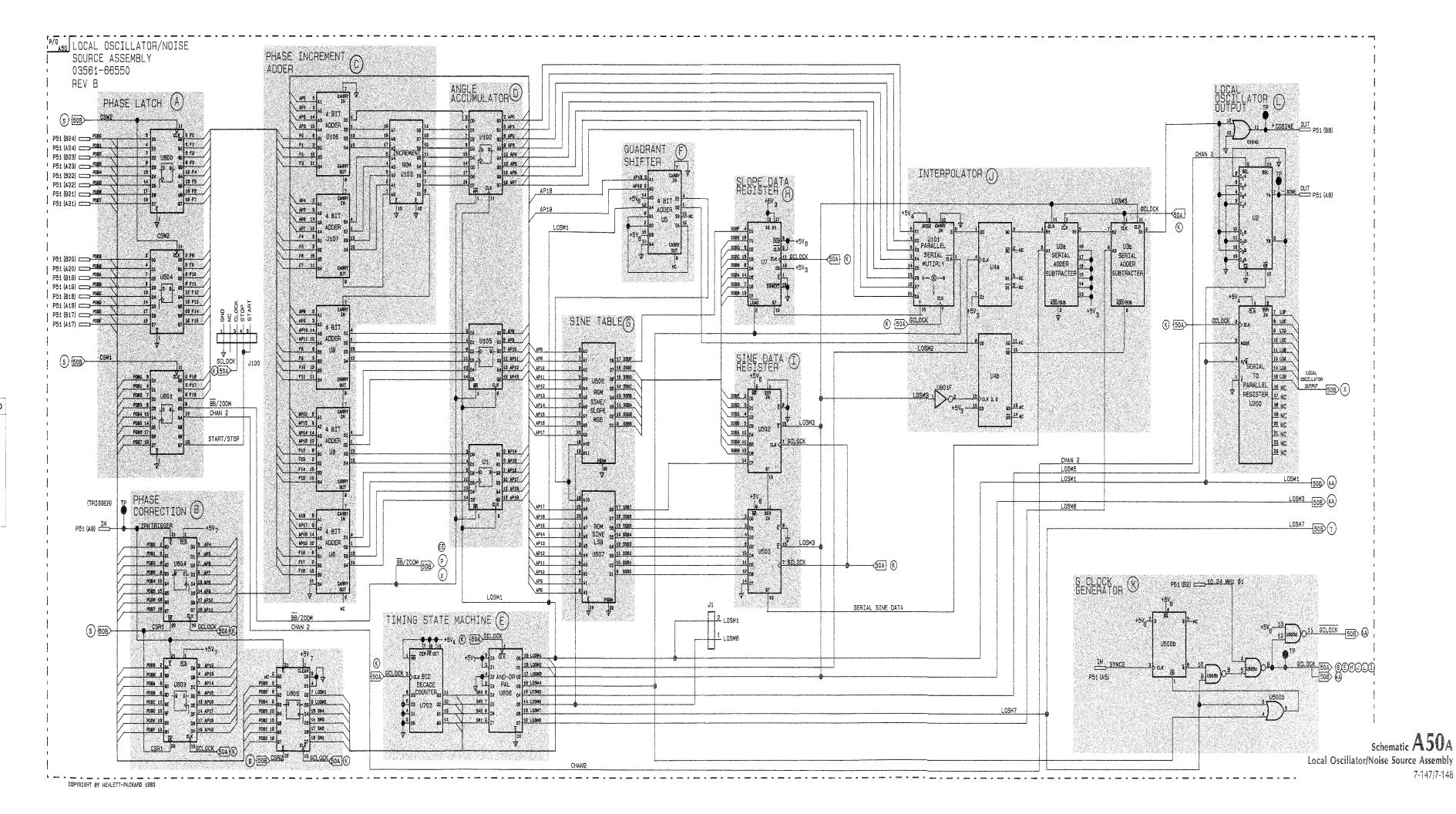


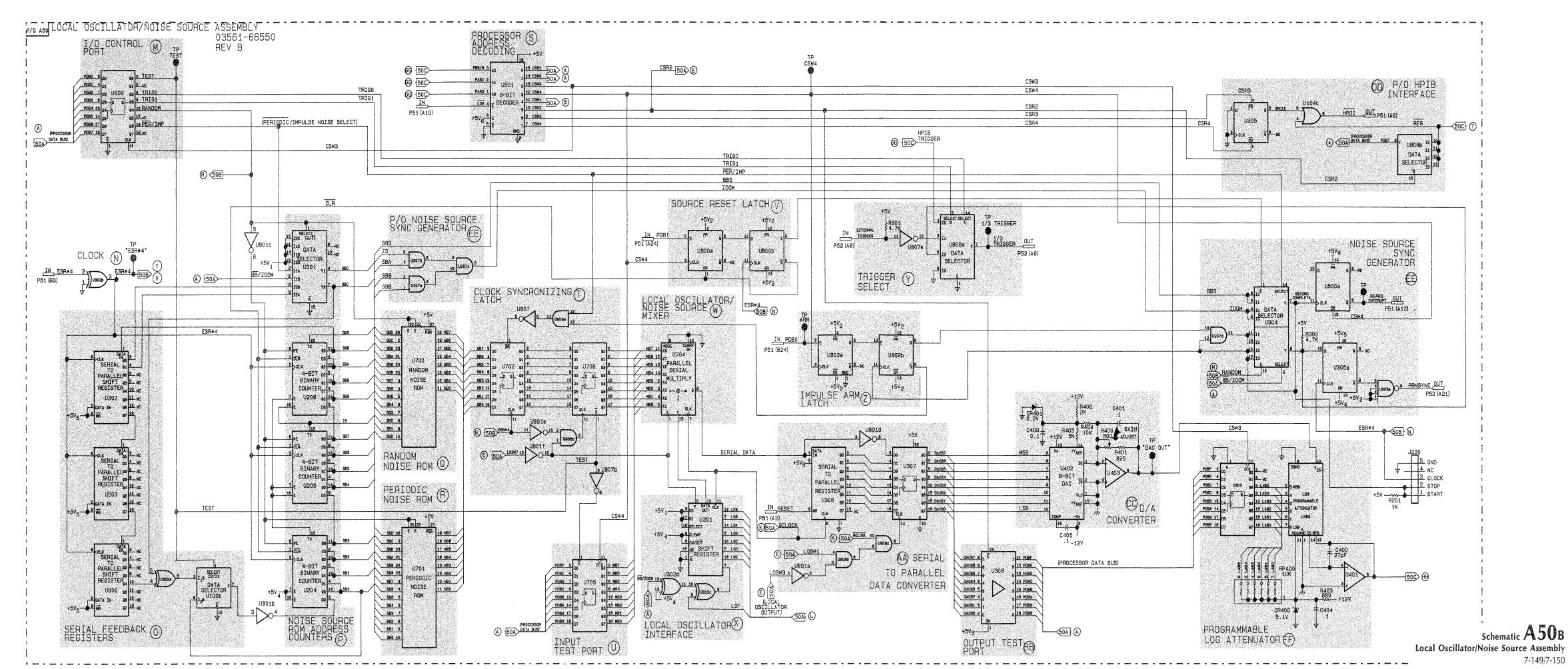
A50 Assembly

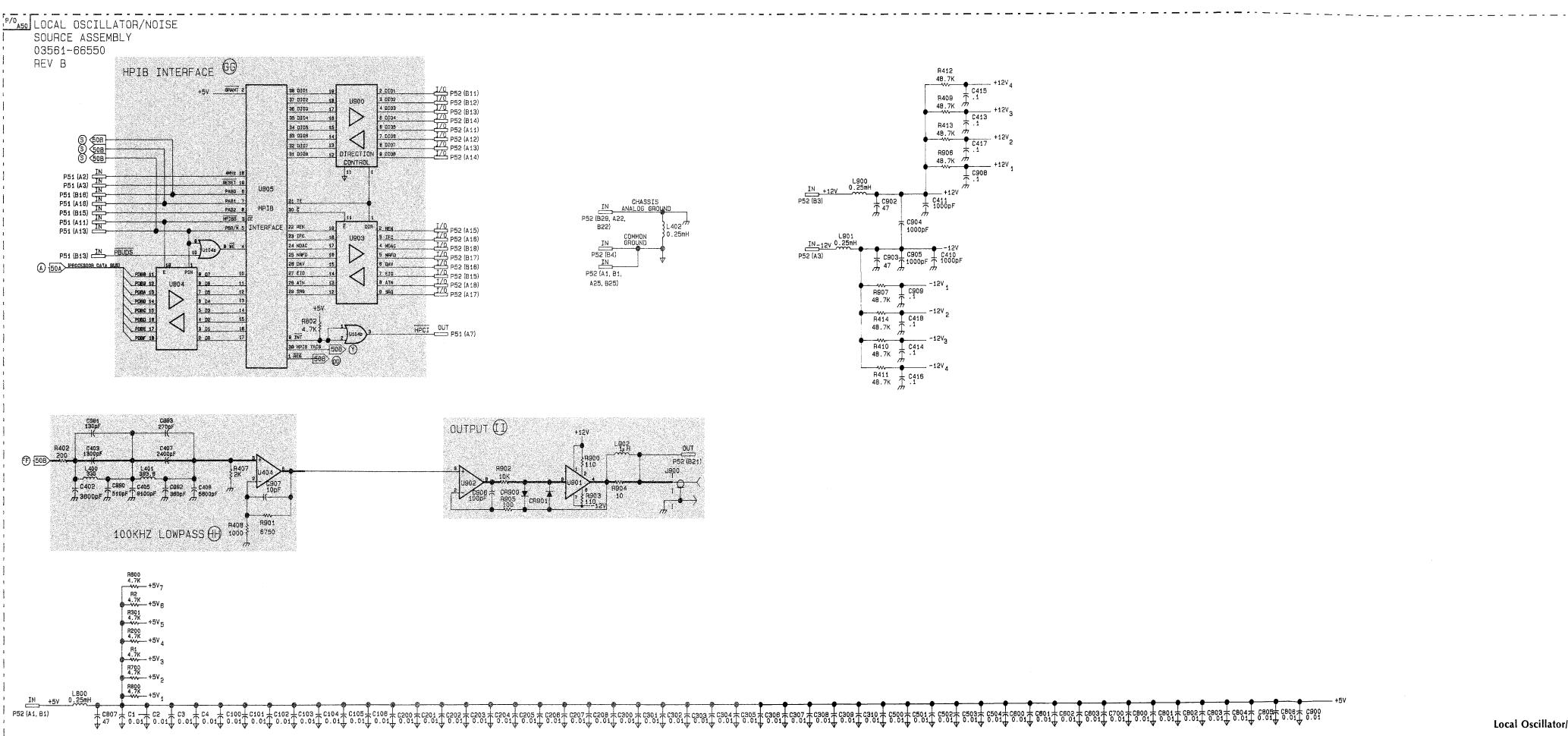
All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)



	+12V	+12V ₁	+12V ₂	+12V ₃	+12V ₄	-12V	-12V ₁	-12V ₂	-12V ₃	-12V ₄	+5V	GND
U401				7					4			
U402	13					3						
U403					7					4		
U404			7					4				
U506								i r :			24,21	12
U507								1			24,21	12
U805											40	1
U901	1					7						
U902		7					4					







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Schematic A 50C Local Oscillator/Noise Source Assembly 7-151/7-152

7-22 A60 DIGITAL DISPLAY DRIVER ASSEMBLY

7-23 Digital Display Driver Circuit Description

GENERAL

The -hp-3561A uses a raster scan CRT with a 512 horizontal (X), by 256 vertical (Y) grid screen. (128K total positions). Each grid position is called a pixel, and can be turned on or off by the display driver circuits. The digital display driver contains two 128k bit arrays of RAM; one array for the full bright display and one for the half bright display. Both the full bright display RAM and the half bright display RAM contain one memory location for each pixel on the CRT screen. A "1" stored in the memory location turns the pixel on and a "0" turns the pixel off. Graphics data is written into the display RAM as a series of lines. For each line the processor loads an X and Y axis start address, an X and Y axis increment value and a line length into the A60 Assembly. The A60 Assembly then uses these three values to generate all points of the line, and the addresses needed to store the line in RAM. Alpha-numeric data is directly stored into the RAM through the character writer circuit. Once data has been written into the display it remains there until the processor erases the display or writes new data over it. Display RAM bus cycles alternate between reading data out of RAM to update the CRT screen and writing new data from the processor into RAM. In this way the CRT screen is continuously updated.

[A] INCREMENT REGISTER, [C] POSITION ADDRESS ADDER, [D] POSITION ADDRESS REGISTER

When the processor writes a line to the display RAM these circuits generate the position address for each pixel of the line. The position address for successive points in the line is obtained by adding the X-increment and Y-increment values to the current X and Y position address.

[B] RAM BYTE ADDRESS REGISTER, [F] RAM BIT ADDRESS REGISTER

These circuits convert the position address register output into a RAM byte address and a RAM bit address. The bit address bus selects one of the eight RAMs in the selected RAM plane and the byte address bus addresses the specific location within the RAM. The byte address consists of two parts: a row address and a column address. The column address is taken from the upper seven bits of the position address register; the row address is taken from the next seven bits. The bottom three bits of the position address register are decoded to form the bit address bus.

[G] MODE CONTROL LATCH, [I] RAM DATA WRITER, [J] CHARACTER WRITER

These circuits generate the data which is stored into the memory location selected by the position address register. Data can be stored into RAM from five different sources. The data source is selected by the processor through the mode control signals M0, M1, and M2. The character writer is selected only when the processor is writing alphanumeric data directly into the display RAM.

Mode Control Signals		Data Source Selected U804			
М0	M1	M2	Pin#	Description	
0	0	0	4	Write a "0" into RAM; erases the CRT screen at the selected address.	
0	0	1	3	Copy the current RAM data at the selected address.	
0	1	0	2	Invert the current RAM data at the selected address.	
0	1	1	1	Write a "1" into RAM; turns the CRT screen on at the selected address.	
1	х	X	12 13 14 15	Write data from the character register into the selected address.	

[K] FREE RUN/LINE SYNC TIMING, [L] COLUMN ADDRESS COUNTER, [M] ROW ADDRESS COUNTER

These circuits access the display RAM on every other bus cycle to continuously refresh and update the pattern on the CRT screen. The rate at which the CRT screen is updated is determined by the free run/line sync circuit. When A60J200 is in the sync position the refresh rate is determined by the LSYNC signal, which is locked to the power line frequency. When A60J200 is in the free run position, the refresh rate is fixed at 62.8 Hz. The row address counter and the column address counter cycle through all memory locations for each pattern refresh.

[N] RAM PLANE 1, [O] RAM PLANE 2

Each RAM is a 16k by 1 bit dynamic RAM. The RAM is addressed in a two step process. In the first step, a seven bit row address is latched into the RAM, and in the second step, a seven bit column address is latched into the RAM. The RAM then internally combines these addresses to obtain the location address.

[S] RAM DATA READER

To refresh the CRT screen, the RAM data reader transfers data from the display RAM to the CRT cathode drive circuit. The data is read from the RAM address generated by the row and column address counters. At each address, the BYTE WRITE signal is used to read one bit of data from each of the eight RAMs in plane 1 to generate the VIDF signal, and one bit of data from each of the RAMs in plane 2 to generate the VIDH signal.

[R] FSYNC/SSYNC TIMING

This circuit uses the address counter outputs to generate the CRT vertical and horizontal sweep signals. The slow sync signal (SSYNC) triggers a horizontal sweep and the fast sync signal (FSYNC) triggers a vertical sweep. A new vertical sweep is generated each time the row address counter reaches a count of 38. A new horizontal sweep is generated each time the column address counter reaches its highest count.

[P] COPY/COMPLIMENT DATA FEEDBACK, [Q] PROCESSOR DATA REGISTER

Through these registers, the data in RAM can be read out and transferred back to the RAM data writer. The RAM data writer can then either copy the data directly back into RAM or compliment the data before writing it back into RAM. Through the processor data register, the processor may read the data stored in the display RAM. This is used only for the the display RAM test at power on.

[T] LINE LENGTH COUNTER

This counter determines the length of the line to be written to the CRT screen. The processor loads the counter with a value equal to the full count minus the line length. When the counter reaches full count a carry is generated (CDONE). The CDONE signal clears the position address and stops the line write timing generator.

[W] TIMING GENERATOR, [U] LINE WRITE TIMING GENERATOR [X] RAM ROW AddRESS STROBE TIMING

These circuits generate all of the timing signals used to generate a line and store it in the display RAM. The line write timing generator starts a sequence when the processor loads the Y increment register and stops when the line length counter issues a CDONE signal.

Table 7-46 A60 Assembly Signal Descriptions

Signal	Description		
BIT/BYTE	Low when only one bit of data is being written to or read from the RAM. High to write identical data to all eight RAMs in a plane.		
BITCLK	BIT CLock: Clocks the RAM data into the analog display driver through the RAM data reader.		
CDONE	Counter DONE: Issued by the line length counter to indicate that the line is complete.		
CAS	Column Address Strobe: Clocks the column address into the RAM.		
CLK	Character CLocK: High to enable a read from RAM and low to enable a write to RAM.		
CRTON	Low to turn the CRT on.		
CTSEL	CounTer SEL: Loads the line length data into the line length counter.		
DDBCLK	Display Data FeedBack CLocK: Latches the RAM output data into the feedback register.		
DNCLK	DowN CLock: Increments the line length counter and the position address counter by one.		
DSPH	DiSPlay Holdoff: Indicates to the processor that the current data transfer is complete. This signal also starts the line length timing generator.		
DSPS	DiSPlay Select: Used by the processor to address the A60 Assembly.		
FSYNC	Fast Sweep SYNCronizer: Syncronizes the CRT vertical sweep with the horizontal sweep and the CRT video data.		
LSYNC	Line SYNCronizer: Syncronizes the CRT refresh rate to the power line frequency.		
PW1, PW2	Plane 1 Write, Plane 2 Write: Programmed by the processor to indicate which RAM plane the data should be written to. Only one of these lines is active at a time.		
R/C	Row/Column Address: Low to select the RAM row address on the byte address bus.		
R/C	Row/Column Address: Low to select the RAM column address on the byte address bus.		
RAS1 RAS2	Ram Address Strobe PLANE1: Clocks the row address into RAM (PLANE1 or PLANE2).		
SSYNC	Slow SYNCronizer: Syncronizes the CRT horizontal sweep to the vertical sweep and to the video data.		
SSYNCE	Slow SYNCronizer Enable: Enables a SSYNC signal when the column address counter reaches its highest count.		

Table 7-46 A60 Assembly Signal Descriptions (Cont'd)

VIDF	VIDeo Full Bright Data: Full bright (PLANE1) RAM data to drive the CRT cathode.
VIDH	VIDeo Half Bright Data: Half bright (PLANE2) RAM data to drive the CRT cathode.
XINC	X-axis INCrement: Loads data into the X-axis increment register.
XSEL	X-axis SELect: Enables data to be clocked into the X-axis increment register.
YINC	Y-axis INCrement: Loads data into the Y-axis increment register, and triggers the line write timing generator to start writing a line to RAM.
YSEL	Y-axis SELect: Enables data to be clocked into the X-axis increment register.

7-24 Troubleshooting the Digital Display Driver

GENERAL

All of the circuits on the A60 Assembly, except the processor interface circuits and the RAM, can be tested with the A60J100 jumper test. The A60J100 jumper test can be run with only the power supply and the A60 Assemblies installed in the the -hp-3561A. The A40W1 jumper test is used to troubleshoot the processor interface circuits, and the power-on test is used to troubleshoot the RAM. These two tests require an operational A40 Assembly to be installed in the -hp-3561A. Failures occurring on the alpha-numerics only are most likely the character writer.

Troubleshoot the circuits on the A60 Assembly in the order given in Table 7-47. In this table, level one circuits must be operational before level two circuits can be tested, etcetera.

Table 7-47 A60 Circuit Troubleshooting Order

Level	Functional Blocks
1	Test Control Circuit: H
	Timing Circuits: U, V, W, X
2	RAM Address Generation Circuits: C, D, E, F
	CRT Refresh Timing Circuits: K, L, M, R
3	RAM: N, O
4	RAM Data Reader: S
5	Processor Interface Circuits: A, B, G, J, T, Y

[H] Test Control

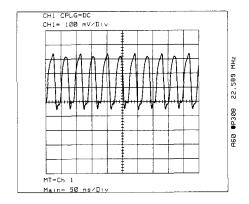
- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Move the A60J100 test jumper to the PLANE1 test position and place the A60 Assembly on an extender board.
- 3. Turn the -hp-3561A LINE power switch ON.
- 4. Check the following signals.

U1(8)	TTL high
U205(10)	0 V
U304(3,6,8)	TTL high
U305(5)	TTL high
U401(6)	0 V
U304(3)	TTL high
U805(3)	TTL high
U900(5,9)	TTL high

[U] LINE WRITE TIMING GENERATOR, [V] DISPLAY CLOCK, [W] TIMING GENERATOR, [X] RAM ROW ADDRESS STROBE TIMING

To troubleshoot these circuits move the A60J100 test jumper to the PLANE1 test position and check the waveforms given in Figure 7-33.

Figure 7-33 Clock and Timing Waveforms

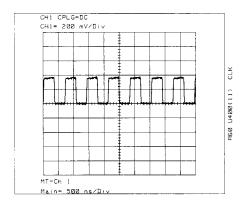


Probe: 10:1

Ch1: Connection- A60 TP308 "22.589 MHz" Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

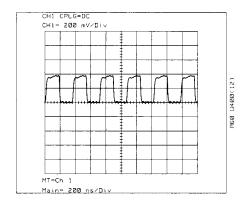


Probe: 10:1

Ch1: Connection- A60 U400(11) "CLK" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

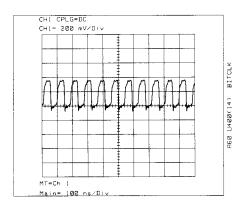


Probe: 10:1

Ch1: Connection- A60 U400(12) Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope-Positive

Bandwidth Limit: ON

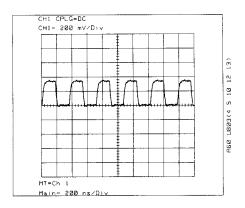


Probe: 10:1

Ch1: Connection- A60 U400(14) "BITCLK" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope-Positive

Bandwidth Limit: OFF



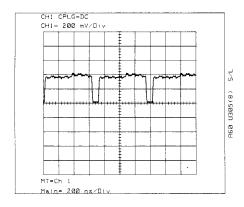
Probe: 10:1

Ch1: Connection- A60 U803(4) A60 U803(5) "R/C" A60 U803(10) A60 U803(12) "R/C"

A60 U803(13) "CAS"

Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope-Positive

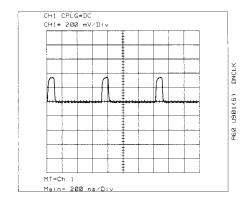


Probe: 10:1

Ch1: Connection- A60 U305(8) "S/L" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

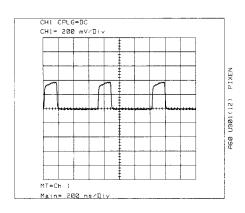


Probe: 10:1

Ch1: Connection- A60 U901(6) "DNCLK" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

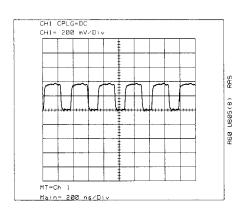


Probe: 10:1

Ch1: Connection- A60 U901(12) "PIXEN" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

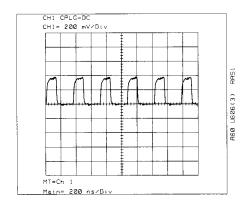


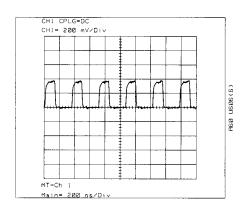
Probe: 10:1

Ch1: Connection- A60U805(8) "RAS" Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive





Probe: 10:1

Ch1: Connection- A60U606(3) "RAS1" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A60U606(6) "RAS2" Coupling- dc Ground- Center Graticule

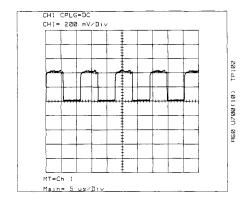
Trigger: Internal- Ch1 Slope- Positive

[C] POSITION ADDRESS ADDER, [D] POSITION ADDRESS REGISTER, [E] RAM BYTE ADDRESS REGISTER, [F] RAM BIT ADDRESS REGISTER

Move the A60J100 test jumper to the PLANE1 test position and check the waveforms given in Figure 7-34. These waveforms should be checked starting with the least significant bit (PXB0) and proceeding to the most significant bit (PXB16).

If these waveforms are correct, check the signatures given in Table 7-48.

Figure 7-34 Position Address Waveforms

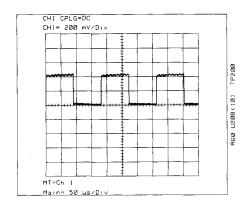


Probe: 10:1

Ch1: Connection- A60 TP102 "PXB3" A60 U700(10) Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



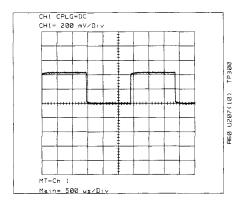
Probe: 10:1

Ch1: Connection- A60 TP200 "PXB7" A60 U208(10) Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

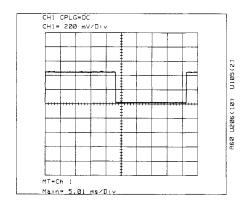
Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 TP300 "PBX11" A60 U207(10) Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive





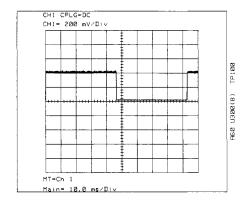
Ch1: Connection- A60 U105(2) "PXB15" A60 U206(10)

A60 U206(10 Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

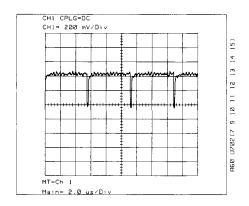
Ch1: Connection- A60 TP100 "PXB16" A60 U300(8)

Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 U702(7, 9, 10, 11, 12,

13, 14 ,15)

A60 U600(3, 6, 8, 11)

A60 U601(3, 6, 8, 11)

Coupling- dc

Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Table 7-48 RAM Byte Address and Bit Address Signatures

Signal	Polarity	Connection	
Clock		A60 U106(1) "CLK"	
Start		A60 TP100 "PXB16"	
Stop		A60 TP100 "PXB16"	
+5 V Signature -	0003		
RAM Byte Addres	ss Register		
U104(3)	7791		
U104(5)	0356		
U104(7)	U759		
U104(9)	6F9A		
U104(13)	P763		
U104(15)	1UP5		
	8484		

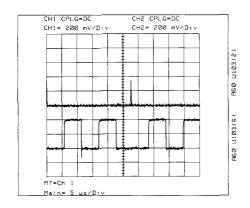
[K] FREE RUN/LINE SYNC TIMING, [L] COLUMN ADDRESS COUNTER, [M] ROW ADDRESS COUNTER, [R] FSYNC/SSYNC TIMING

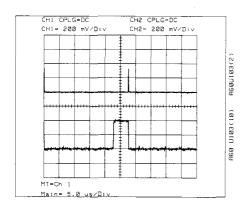
Move the A60J100 test jumper to the PLANE1 test position and the A60J200 test jumper to the 60 Hz position. Check the waveforms given in Figure 7-35. These waveforms should be checked starting with the least significant bit of the row address counter (U103(3)) and proceeding to the most significant bit of the column address counter (U200(10)).

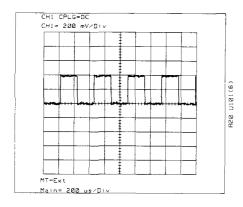
Move the A60J200 test jumper back to the SYNC position.

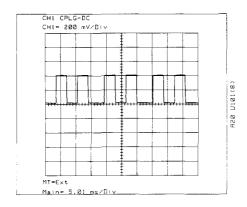
If all of the waveforms given in Figure 7-35 are correct, check the signatures given in Table 7-49.

Figure 7-35 Row and Column Address Counter Waveforms









Probe: 10:1

Ch1: Connection- A60 U103(2) Coupling- dc Ground- Center Graticule

Ch2: Connection- A60 U103(6) Coupling- dc

Ground-Second Graticule from Bottom

Trigger: Internal- Çh1 Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A60 U103(2) Coupling- dc Ground- Center Graticule

Ch2: Connection- A60 U103(10)
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A60 U101(6) Coupling- dc Ground- Center Graticule

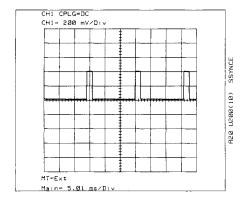
Trigger: External- A60 U101(2) Slope- Positive

Bandwidth Limit: OFF

Probe: 10:1

Ch1: Connection- A60 U101(8) Coupling- dc Ground- Center Graticule

Trigger: External- A60 U101(2) Slope- Positive

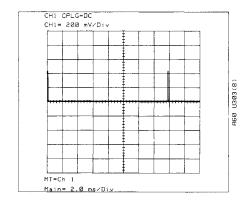


Probe: 10:1

Ch1: Connection- A60 U200(10) "SSYNCE" Coupling- dc Ground- Center Graticule

Trigger: External- A60 U101(2) Slope- Positive

Bandwidth Limit: OFF

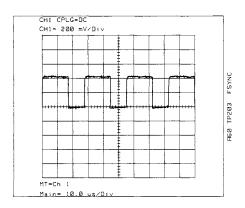


Probe: 10:1

Ch1: Connection- A60 U303(8) Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

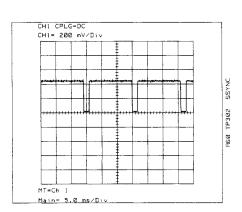


Probe: 10:1

Ch1: Connection- A60 TP203 "FSYNC" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: OFF



Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Table 7-49 RAM Address Signatures

Signal	Polarity	Connection
Clock		A60 U100(19) "CLK"
Start	_	A60 U200(10) "SSYNCE"
Stop		A60 U200(10) "SSYNCE"
+5 V Signature -	5F52	
U100(3)	AF98	
U100(5)	C74H	
U100(7)	AF1C	
U100(9)	8641	
U100(13)	CH3C	
U100(15)	<i>77</i> H9	
U100(17)	4H8U	

[N] RAM PLANE1 (FULL BRIGHT), [O] RAM PLANE2 (HALF BRIGHT)

Troubleshoot the RAM circuits using the -hp-3561A power-on test. The A60J100 test jumper should be in the run position for this test. Table 7-50 lists the power-on test return codes and the corresponding failed RAM. If the power-on test indicates a failure in several RAMs, the most likely cause of the failure is the copy compliment data feedback registers or the processor data register.

Table 7-50 Power Or Test Return Codes for the Display RAM

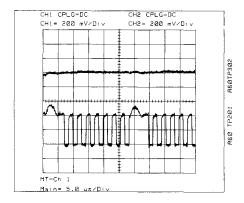
Return Code	Chip Code	Failed RAM
0 7 28	G	U507
0 7 28	Н	U505
0 7 28	J	U503
0 7 28	K	U501
0 7 28	Ĺ	U9
0 7 28	М	U7
0 7 28	N	U5
0 7 28	Р	U3
0 7 28	R	U506 ,
0 7 28	Т	U504
0 7 28	U	U502
0 7 28	V	U500
0 7 28	W	U8
0 7 28	X	U6
0 7 28	Y	U4
0 7 28	Z	U2
	1	

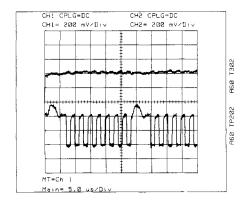
[S] RAM DATA READER

1. Move the A60J100 test jumper to the PLANE1 test position and the A60J200 test jumper to the 60 Hz position. Check the waveform at A60TP201 as shown in Figure 7-36.

- 2. Move the A60J100 test jumper to the PLANE2 test position and check the waveform at A60TP202 as shown in Figure 7-36.
- 3. Move the A60J200 test jumper back to the SYNC position.

Figure 7-36 RAM Data Reader Waveforms





Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC" Coupling- dc Ground- Center Graticule

Ch2: Connection- A60 TP201 "VIDF" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A60 TP302 "SSYNC" Coupling- dc Ground- Center Graticule

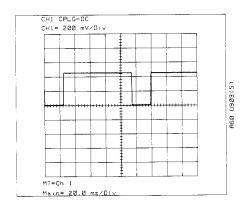
Ch2: Connection- A60 TP202 "VIDH" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

[A] INCREMENT REGISTER, [B] ADDRESS DECODER, [G] MODE CONTROL LATCH [J] CHARACTER WRITER, [T] LINE LENGTH COUNTER, [Y] BEEPER TIMING

- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Move test jumper A40W1 on the A40 Assembly to the test position.
- 3. Move test jumper A60J100 on the A60 Assembly to the run position.
- 4. Turn the -hp-3561A LINE power switch ON. When the front panel LEDs begin to blink (approximately seconds after power-on), check the signatures given in Table 7-51 and the waveforms given in Figure 7-37.

Figure 7-37 Beeper Timing Waveforms

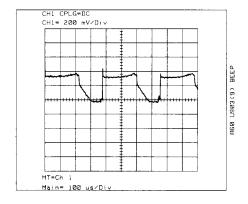


Probe: 10:1

Ch1: Connection- A60 U903(5)
Coupling- dc
Ground- Center Graticule

Trigger: Internal- Ch1 Slope- Negative

Bandwidth Limit: ON



Probe: 10:1

Ch1: Connection- A60 U903(9) "BEEP" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Positive

Bandwidth Limit: ON

Note: This waveform will appear to jitter.

Table 7-51 A60 Processor Interface Signatures

ignature Analyze Signal	Polarity	Connection	
Clock		A60 U806(4) "DSPS"	
Start	~	A40CR1 (Cathode of	
Stop	<u></u>	A40CR1 (Cathode of	
+5 V Signature -	AU96		
Address Decoder		Increment Registe	er
U303(3)	АР3Н	U209(2)	9747
U303(6)	C232	U209(5)	59F5
U806(7)	4304	U209(6)	A8A2
U806(9)	9FU5	U209(9)	3052
U806(10)	A205	U209(12)	UPUP
U806(11)	PA07	U209(15)	H938
U806(12)	C23H	U209(16)	456H
U806(13)	FP6H	U209(19)	9H2P
U806(14)	U7A3		
U806(15)	C396	U302(5)	A36U
Mode Control La	tch	U304(3)	A171
U800(2)	P852	U701(2)	4HUP
U800(5)	H766	U701(5)	F5U2
U800(6)	5967	U701(6)	6504
U800(9)	A1AA	U701(9)	A171
U800(12)	9P18	U701(12)	CF35
U800(15)	06P3	U701(15)	0A70
U800(16)	6520	U701(16)	P800
U800(19)		U701(19)	2142
U304(6)	H766		
U304(8)	5967		

Table 7-52 A60 Assembly Signal Connections

INPUTS

Signal Name	Functional Block	Connector Number	Origin Assembly
DSPS	В	P61(A8)	A40
LSYNC	K	P62(B9)	A71
PBR/W	Q	P61(A13)	A40
RESET	Н	P61(A3)	A40

OUTPUTS

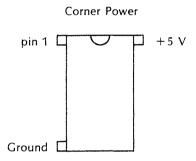
Signal Name	Functional Block	Connector Number	Destination Assembly
BEEP	Υ	P62(B8)	A72
DSPH	U	P61(A7)	A40
FSYNC	R	P61(B4)	A90
SSYNC	R	P61(B5)	A90
VIDF	S	P61(B3)	A90
VIDH	S	P61(B2)	A90

I/O SIGNALS

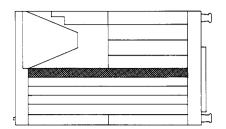
Signal	Functional	Connector	Destination
Name	Block	Number	Assemblies
Processor Address Bus PAB0 - PAB2	В	P61(A16,B15,B16)	A40, A50, A66/65 A81
Processor Data Bus	A,Q	P61(A17 - A24)	A30, A40, A50
PDB0 - PDBF		P61(B17 - B24)	A66/65, A80

A60 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)



	+ 5V	GND
U2	8	16
U3	8	16
U4	8	16
U5	8	16
U6	8	16
U7	8	16
U500	8	16
U501	8	16
U502	8	16
U503	8	16
U504	8	16
U505	8	16
U506	8	16
U507	8	16



A60 J100



PLANE1 POSITION (Full Bright)



PLANE2 POSITION (Half Bright)



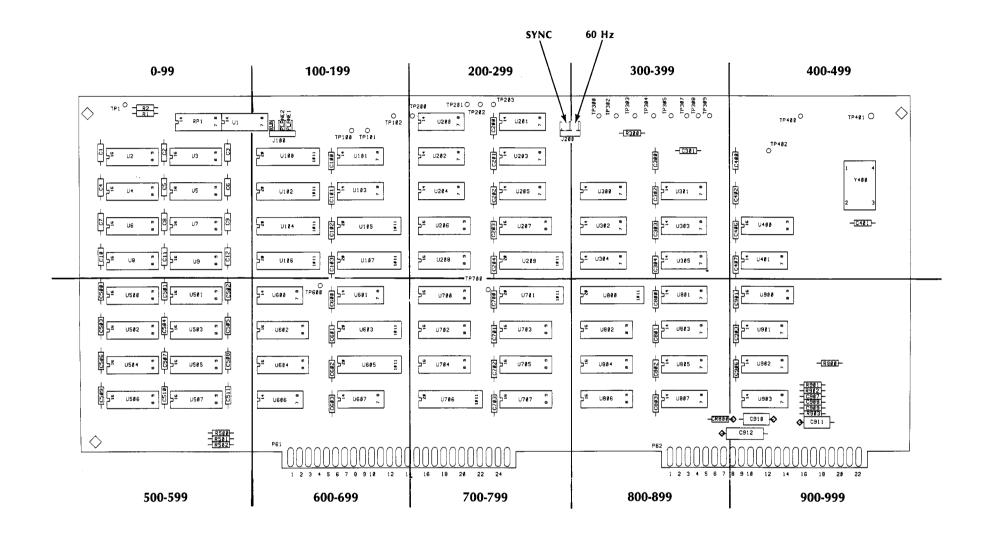
A60 J200

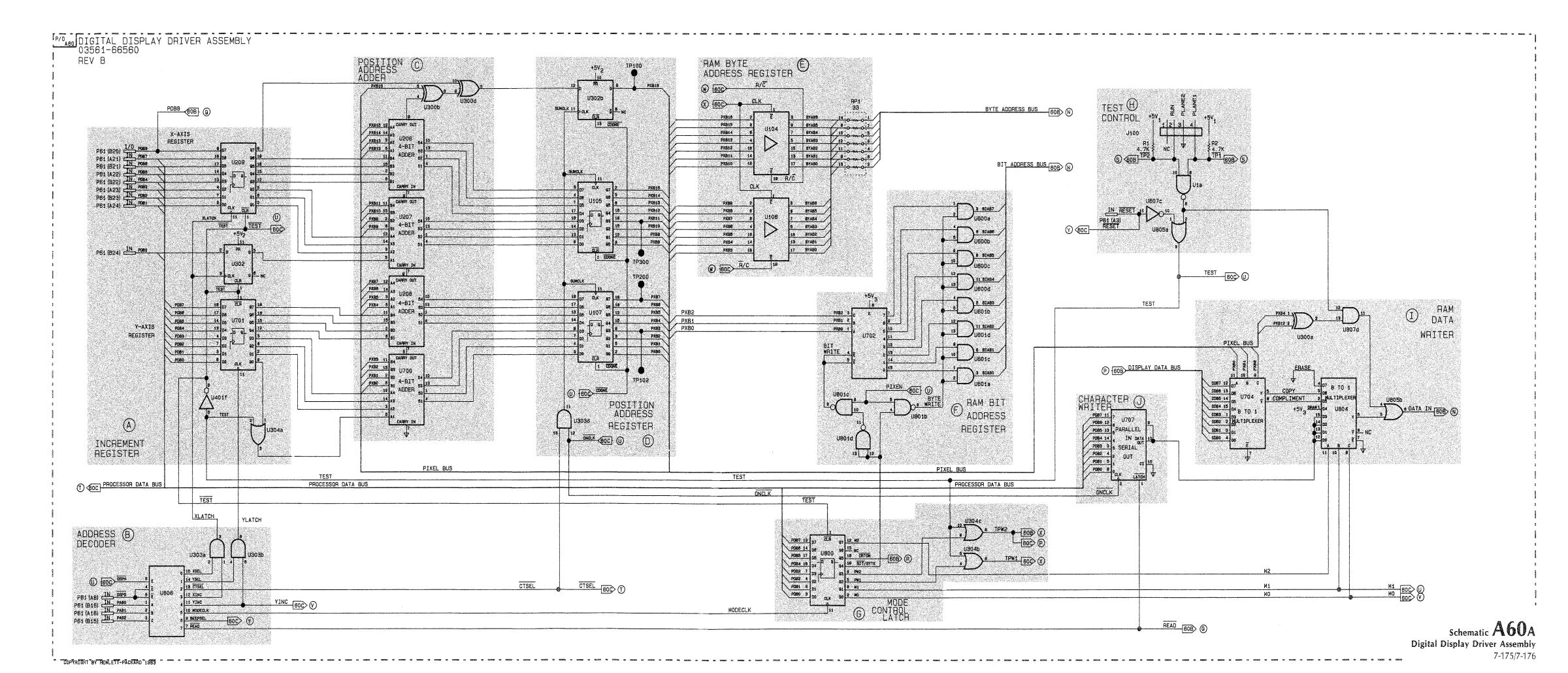


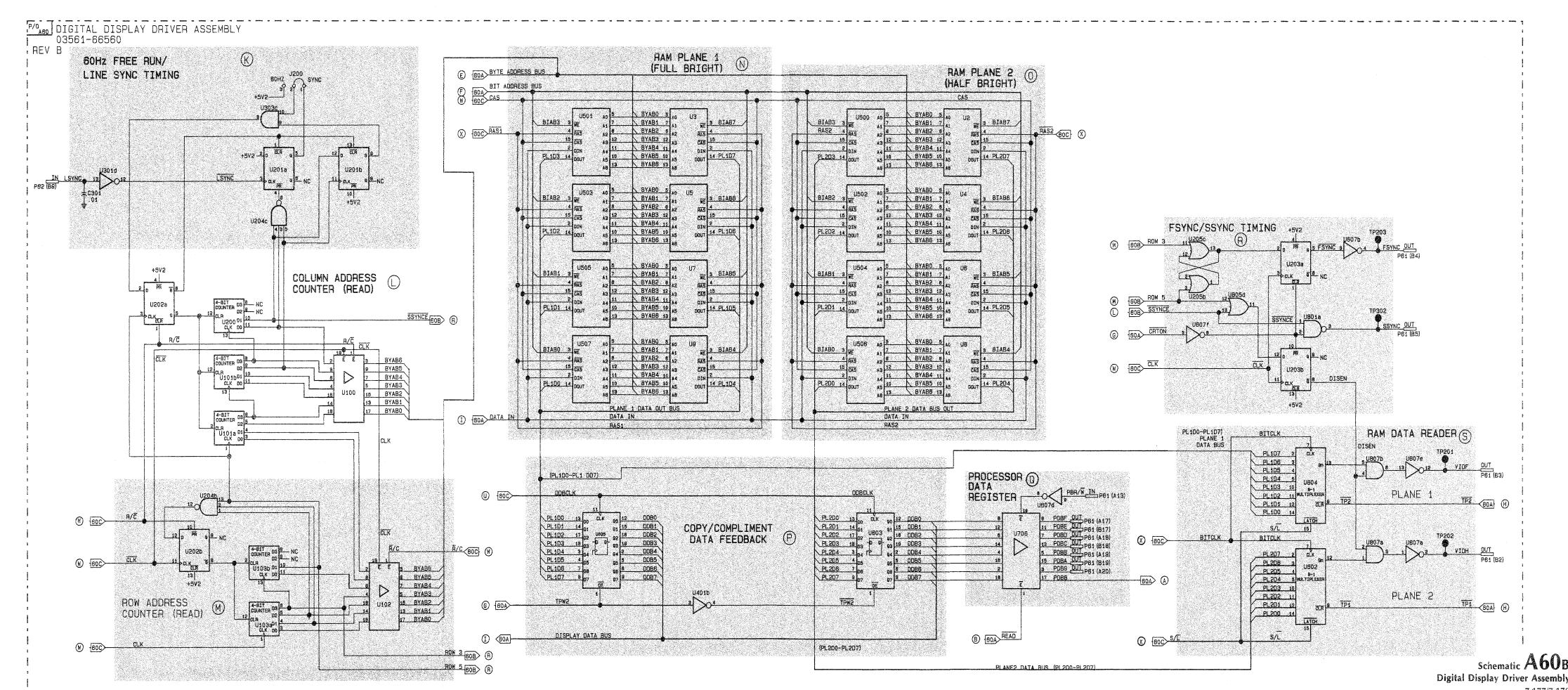
60 Hz Position

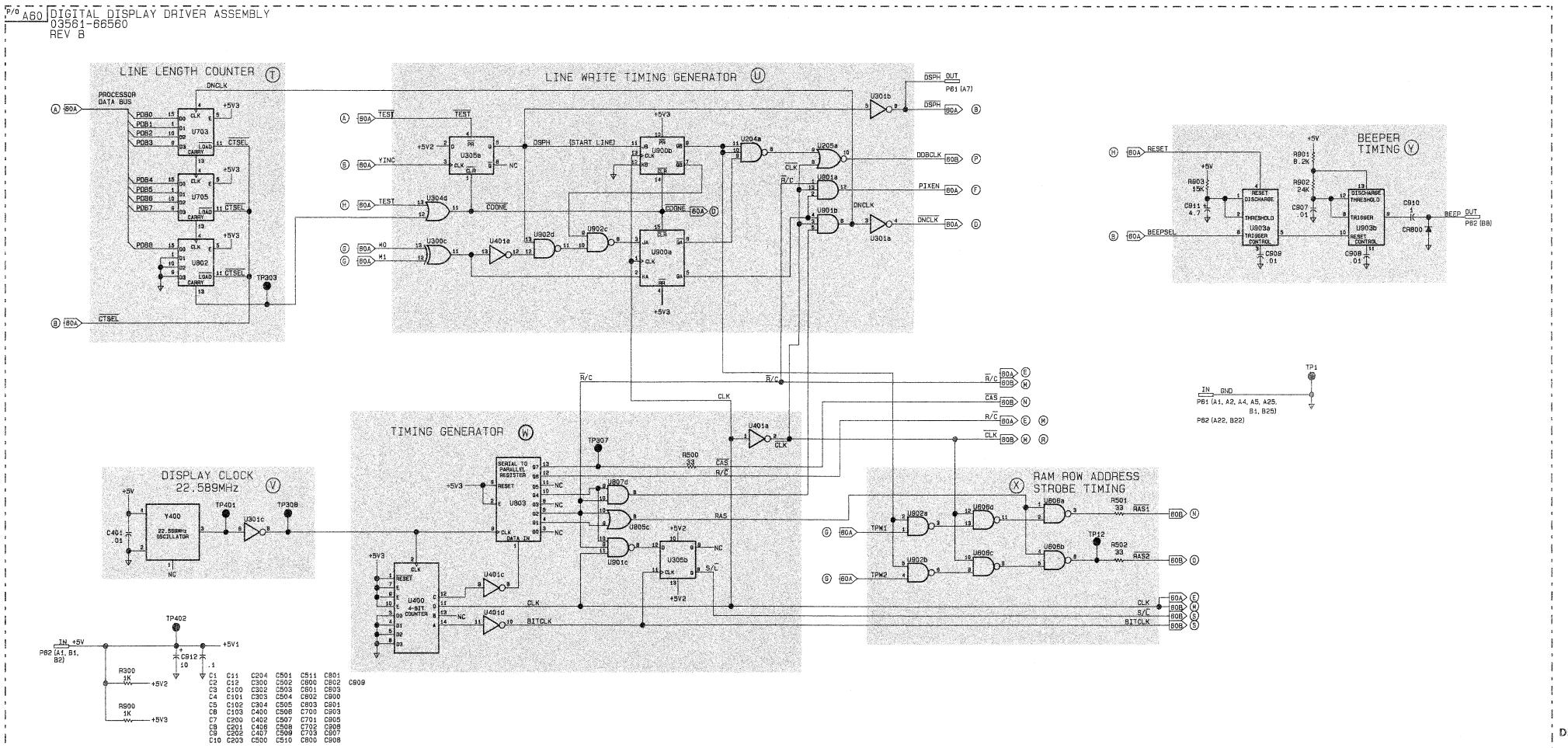


SYNC Position









Schematic A60C Digital Display Driver Assembly 7-179/7-180

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7-25 A65/A66 CMOS BUBBLE MEMORY ASSEMBLY

7-26 Circuit Description: CMOS Bubble Memory

GENERAL

The purpose of these assemblies is to store data in non-volatile memory. The A66 Assembly is standard and contains an 8k-byte CMOS RAM with battery backup. The optional A65 Assembly contains the same CMOS RAM with an additional 128k-byte Bubble memory module. The following information will concentrate on the optional A65 CMOS/Bubble Memory Assembly since it also contains the standard CMOS memory circuitry. The following theory will be to the circuit function level. Those circuits which are located on both the A65 and the A66 assemblies will be in (parenthesis). Table 7-53 identifies and describes the signals used on these assemblies.

[A] BUBBLE ON/OFF

When the Bubble Memory is addressed to read or write and the reset is not active, the Bubble On/Off circuit controls the Bubble Power Down circuit [H].

[B] CONTROL SIGNAL BUFFER

The Control Signal Buffer isolates the control signals which determine the read and write operation and whether the data is for the CMOS or the Bubble Memory.

[C] (BUS DRIVERS)

The Bus Drivers control the flow of data and address lines to and from the A65/66 Assemblies.

[D] (CMOS MEMORY)

This is the 8k-byte CMOS Memory and Page Select ICs. U203 selects which 256-bit page will be addressed.

[E] BUBBLE INTERRUPT

This circuit controls the interrupt from the Bubble Memory Controller circuit [1].

[F] BUBBLE READ/WRITE

This circuit controls the read and write operations of the Bubble Memory circuit by decoding the processor signals.

[G] (BATTERY AND CMOS POWER DOWN)

This circuit supplies either +5V or the battery to the CMOS IC to prevent data loss or corruption in the case of a power failure. When the instrument is turned on, +5V is supplied. When the instrument is turned off, the battery is smoothly switched in to prevent data loss.

[H] BUBBLE POWER DOWN

The Bubble Power Down holds the Bubble circuits in the power down state during the time that data transfer is not occurring. This method is used to prevent data loss or corruption in the case of a power failure.

[I] BUBBLE CONTROLLER

The Bubble Controller interfaces the Bubble circuits with the processor. It provides all the control and timing functions needed to operate the Bubble Circuitry.

[J] BUBBLE COIL DRIVERS

This circuit transforms the TTL inputs from the Bubble Controller [I] to high voltage drive signals. These drive signals then drive the coils internal to the Bubble Memory module U4. These coils generate the magnetic fields which move the bubbles within the module.

[K] BUBBLE MEMORY

There are three LSI devices in this circuit. They are as follows:

A Current Pulse Generator which contains individual current sinks that supply the proper currents when enabled by the respective TTL inputs.

A Sense Amplifier which reads and latches the bootloop from the Bubble Memory module. It then controls the address where data is to be read from or written to. This IC also contains an Error Correction circuit which detects and corrects data errors during both read and write operations.

The Magnetic Bubble Memory Module is a 128k-byte non-volatile solid state memory.

[L] (CMOS CONTROL)

This circuit controls the Battery and CMOS Power Down circuit [G] enabling it during a read or write operation and disabling it all other times.

Table 7-53 Signal Descriptions

Signal	Description
BUBS	Bubble Select: Signal from the A40 Processor Assembly used enable the Bubble memory circuits to perform a read or write operation.
CMOSS	CMOS Select: Signal from the A40 Processor Assembly used to clock data into the CMOS memory.
MAB0 through MABC	Memory Address Bus: These are the 12 Memory Address lines derived from the processor data bus lines 0-7 and processor address bus lines 0-4. They are used on this assembly only.
MDB0 through MDB7	Memory Data Bus: These are the 8 Memory Data Bus lines derived from the processor data bus. They are used on this assembly only.
PAB0 through PAB4	Processor Address Bus: These are five lines of the Processor Address Bus.
PAB5	Processor Address Bus: Bit 5 is used on this assembly to enable the CMOS Control circuit and Bubble Controller.
PBR/W	Processor Bus Read/Write: This is the buffered processor R/W signal which programs the memory circuits to perform a read or write operation.
PDB0 through PDBF	Processor Data Bus: These are the 16 Processor Data bus lines.
4MHz	This clock is from the A40 Processor Assembly and is used by the A65/66 Assemblies as the main clock.

7-27 Troubleshooting The A65/66 Assemblies

GENERAL

Failures in the CMOS/Bubble memory may or may not be detected by the power-up test routine. If the processor is not able to talk to the assembly, the processor will display "NONVOLATILE MEMORY ERROR: FORMAT REQUIRED" on the CRT display. If, however, there are memory location errors, error messages will be displayed during a store or recall operation.

If any of the following three failures occur on the optional Bubble Memory Assembly (03561-66565), the assembly will require formatting.

- 1. Replacement of the battery BT1
- 2. Replacement of IC U4.
- 3. Replacement of IC U103.

Format the assembly by pressing the following front panel keys:

The following built-in diagnostic routines can be used to determine if a failure exists in the CMOS or the Bubble portion and then to troubleshoot the defective circuit. Test 19 CMOS Memory test which writes and reads a known pattern to the A66/A65 Assembly.

Test 20 Bubble Memory test which writes and reads a known pattern to the A65 Assembly.

Test 167 Bubble Memory Read DSA test used to troubleshoot the Bubble memory in the read mode.

Test 170 Memory Format Routine used to initilize the CMOS memory on the A65 Bubble Memory Assembly.

Two troubleshooting procedures are given. The first procedure is for the standard A66 CMOS Memory assembly. The second is for the optional A65 CMOS/Bubble Memory assembly.

A66 CMOS TROUBLESHOOTING

WARNING

Having the A66 cover removed exposes the power supply assemblies. These assemblies contain exposed ± 170 primary voltage. Exercise extreme caution when troubleshooting since contact with these voltages can cause personal injury.



Always stop the diagnostic test routine from running before turning the instrument LINE power OFF! Otherwise, damage to the memory circuits will occur!

Troubleshoot the circuits on the A66 Assembly in the order given in Table 7-54. In this table, level one circuits must be operational before level two circuits can be checked, etcetera. Test Routine 19, CMOS Memory Test, will be used to troubleshoot the A66 Assembly. To enter into self test routine 19, press the following -hp-3561A front panel keys in the order given:

PRESET
MODE 19 ENTER

Table 7-54 A66 Circuit Troubleshooting Order

Level	Functional Blocks
1	Bus Drivers: C
2	CMOS Control: L
3	Battery And CMOS Power Down: G
4	CMOS Memory: D

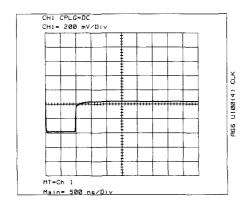
[C] BUS DRIVERS

With test routine 19 running continuously, check that the output pins of U101(3,5,7,9,12,14,16,18) are toggling. If any of the pins are not, replace U101.

[L] CMOS CONTROL

With test routine 19 running continuously, verify the signals on the output of U100 with those shown in Figure 7-38. If either do not match, replace U100.

Figure 7-38 Correct Waveforms At A66U100(4,5)

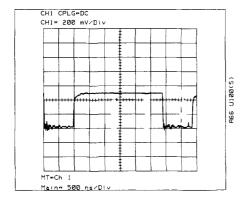


Probe: 10:1

Ch1: Connection- U100(4) Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative



Probe: 10:1

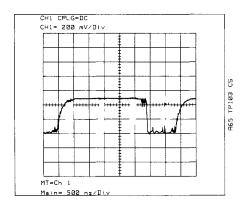
Ch1: Connection- U100(5)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1 Slope- Negative

[G] BATTERY AND CMOS POWER DOWN

With test routine 19 running continuously, verify that TP102 is +5Vdc. Verify the signal at TP103 with that shown in Figure 7-39. Also, with test routine 19 stopped, turn the instrument power off and verify that the voltage on TP102 is greater than +2Vdc. If any measurements are incorrect, troubleshoot this functional circuit.

Figure 7-39 Correct Waveform At A66 TP103



Probe: 10:1

Ch1: Connection- TP103

Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

[D] CMOS MEMORY

The troubleshooting for this circuit is to first replace U203. If the the failure remains, replace U103.

A65 BUBBLE MEMORY TROUBLESHOOTING

If at power-on, the CRT displays the message "NONVOLATILE MEMORY ERROR: FORMAT REQUIRED," perform the formatting routine by running Diagnostic Test Routine 170 located in Section VI. If after running this routine, the format message is still displayed, proceed with the following troubleshooting information.



Having the A65 cover removed exposes the power supply assemblies. These assemblies contain exposed ± 170 Vdc primary voltage. Exercise extreme caution when troubleshooting in this area since contact with these voltages can cause personal injury.



Always stop the test routine from running before turning the instrument LINE power OFF! Otherwise, damage to the memory circuits will occur!

This troubleshooting procedure is for the Bubble Memory circuitry only. Troubleshooting information for the CMOS circuitry is given in Paragraph A66 CMOS Troubleshooting.

Use the failure isolation chart in Figure 7-40 to determine if the problem is in the Bubble or CMOS portion of the assembly.

Use the following flowchart to determine if the A65 failure is in the CMOS or Bubble portion of the circuitry. This flowchart will also determine if there is a hardware or a Bubble firmware failure (lost Seed or Bootloop).

All possible errors are listed in Table 7-55. Included in the list is the error number, a description of the failure and probable defective components or functional circuits which may have caused the error.

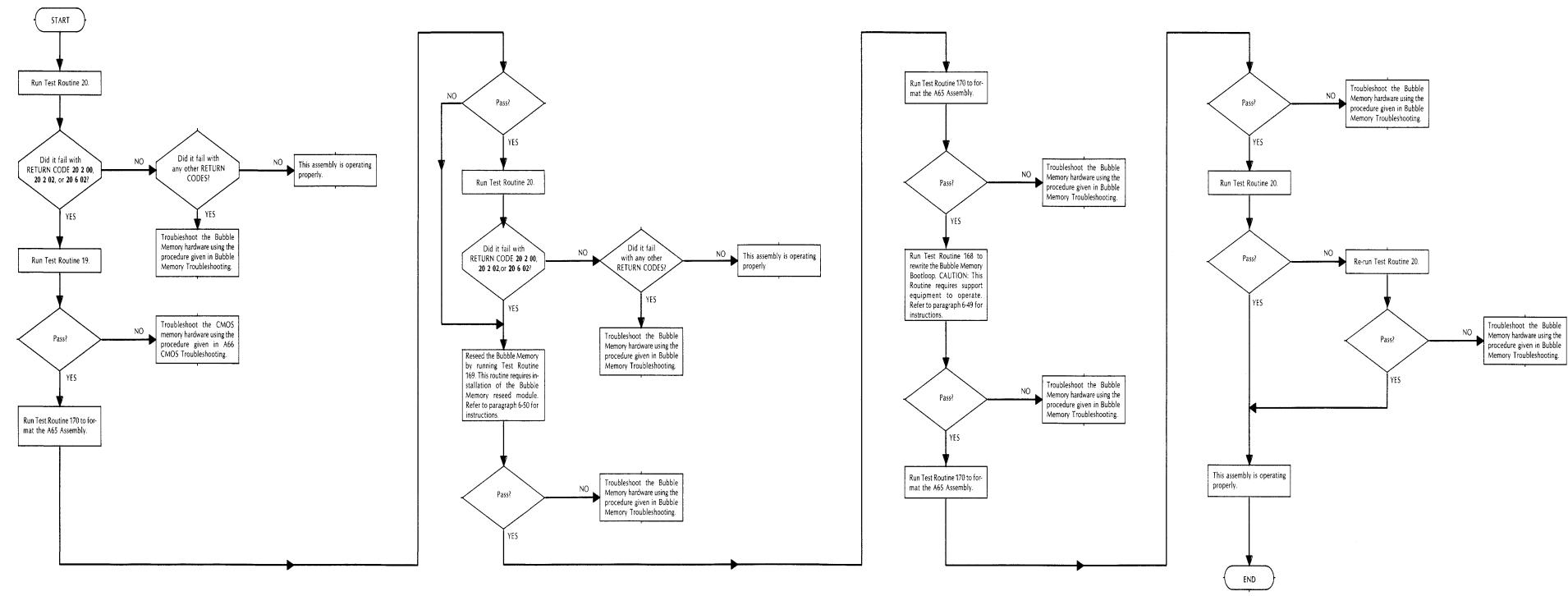


Figure 7-40 A65 Failure isolation Chart

Table 7-55 Test 20 RETURN CODE Descriptions

Error	Description	Probable Cause
20 1 00	No Bubble is present or bad communication between the A40 Processor and A65 Bubble Memory Controller.	Usually caused by the Bus Driver U202. Verify its operation using the CMOS troubleshooting procedure.
20 2 00	The Bubble circuitry failed during a read operation.	Both errors 20 2 00 and 20 2 01 may be caused by either a defective Bubble module U4 or
20 2 01	The Bubble circuitry failed during a write operation.	Current Pulse Generator U102. Verify using the K Bubble Memory troubleshooting procedure.
20 2 02	Both errors 20 2 00 and 20 6 03 occured.	
20 2 03	Both errors 20 2 01 and 20 6 03 occured.	
20 6 00	The FIFO in the Controller U200 is failing.	Usually caused by the Bus Driver U202 and/or the Controller U200.
20 6 01	The Bootloop Register in the Sense Amplifier U3 is not communicating with the Controller U200.	Usually caused by a failure in the Sense Amplifier U3.
20 6 02	The Bubble cannot be initialized.	Usually caused by a failure in the CMOS Memory or the coil driver circuitry of the Bubble memory.
20 6 03	Data read from the Bubble Memory at initialization does not match the stored fixed pattern. The first time this test is per- formed, this failure will occur since the fixed pattern has not yet been written into memory. However, Test 20 writes and checks twice. If it fails the second time also, error 20 6 04 will occur.	Usually caused by a failure in the Bubble Coil Drivers J or the Bubble Memory K circuits.
20 6 04	Data pattern read from the Bubble memory does not match the stored fixed pattern. See also error 20 6 03.	
20 6 05	Both errors 20 2 00 and 20 2 01 occured.	

The Bubble troubleshooting is performed with the -hp-3561A running in Test Routine 167. Troubleshoot the functional circuits in the order given in Table 7-56. In this table, level one circuits must be operational before level two circuits can be

checked, etcetera. To enter into Test Routine 167, press the following -hp-3561A front panel keys in the order given:

PRESET		
MODE	TEST SELECT	

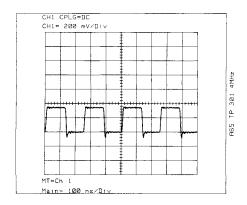
Table 7-56 A65 Circuit Troubleshooting Order

Level	Functional Blocks	
1	Control Signal Buffer: B	
2	Bubble On/Off: A	
3	Bubble Power Down: H	
4	Bubble Read/Write: F	
5	Bus Drivers: C	
6	Bubble Controller: 1	
7	Bubble Coil Drivers: J	
8	Bubble Memory: K	

[B] CONTROL SIGNAL BUFFER

Verify that the outputs of U306(9,11,13) are toggling. Also check the waveforms at TP301 and TP302 with those shown in Figure 7-41. If any of these signals are not present, troubleshoot this functional block.

Figure 7-41 Correct Waveforms At A65 TP301 And TP302.

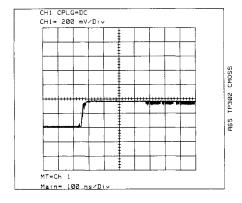


Probe: 10:1

Ch1: Connection- TP301 Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive



Probe: 10:1

Ch1: Connection- TP302 Coupling- dc

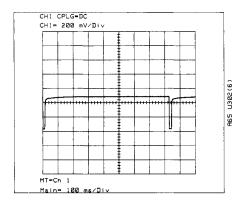
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope-Negative

[A] BUBBLE ON/OFF

Verify the waveform at U302(6) with that shown in Figure 7-42. If it does not match, troubleshoot this functional block.

Figure 7-42 Correct Waveform At A65 U302(6).



Probe: 10:1

Ch1: Connection- U302(6)
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

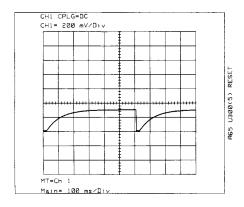
[H] BUBBLE POWER DOWN

Verify the waveform at U300(5) with that shown in Figure 7-43. If it does not match, troubleshoot this functional block.

[F] BUBBLE READ/WRITE

Verify the waveforms at U201(8,11) with those shown in Figure 7-44. If they do not match, troubleshoot this functional block.

Figure 7-43 Correct Waveform At A65 U300(5).



Probe: 10:1

Ch1: Connection- U300(5)

Coupling- dc

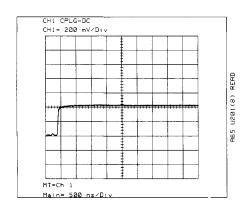
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1

Slope- Negative

BW Limit: On

Figure 7-44 Correct Waveforms At A65 U201(8,11).



Probe: 10:1

Ch1: Connection- U201(8)

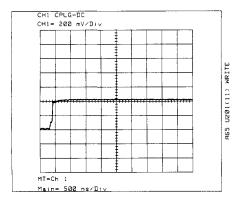
Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1

Slope- Negative

BW Limit: On



Probe: 10:1

Ch1: Connection- U201(11)

Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1

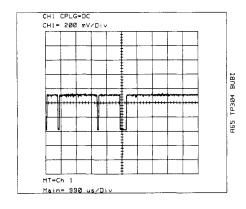
Slope- Negative

BW Limit: On

[E] BUBBLE INTERRUPT

Verify the waveform at TP304 with that shown in Figure 7-45. If it does not match, troubleshoot this functional block.

Figure 7-45 Correct Waveform At TP304.



Probe: 10:1

Ch1: Connection- TP304
Coupling- dc
Ground- 3rd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

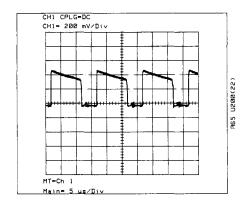
[C] BUS DRIVERS

Verify that all outputs of U202(2 through 9) are toggling. If any are not, replace U202.

[I] BUBBLE CONTROLLER

Verify the seven waveforms on the outputs of U200 with those shown in Figure 7-46. If any do not match, replace U200.

Figure 7-46 Correct Output Waveforms At A65 U200.



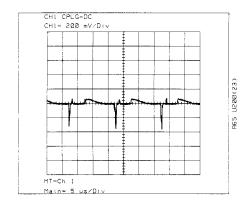
Probe: 10:1

Ch1: Connection- U200(22) Coupling- dc Ground- Center

Trigger: Int- Ch1 Slope- Negative

BW Limit: Off

HF REJ: On



CH1 CPLG=DC CH!= 200 mV/Div U200(24) MT=Ch i us/Div

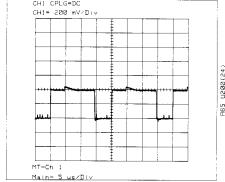
Probe: 10:1

Ch1: Connection- U200(23) Coupling- dc Ground- 3rd graticule from the bottom

Trigger: Int- Ch1 Slope-Positive

BW Limit: Off

HF REJ: On

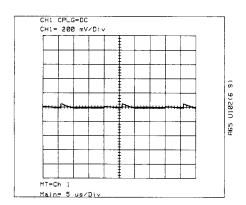


Probe: 10:1

Ch1: Connection- U200(24) Coupling- dc Ground- 3rd graticule from the bottom

Trigger: Int- Ch1 Slope- Negative

BW Limit: On



Probe: 10:1

Ch1: Connection- U200(30,31) or U102(6,9) Coupling- dc Ground- 3rd graticule from the bottom

Trigger: Int- Ch1 Slope- Negative

BW Limit: Off

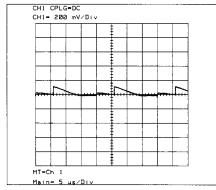
CHI CPLG=DC CH1 = 200 mV/Div U102C3 MT=Ch 1 Main= 5 us/Div

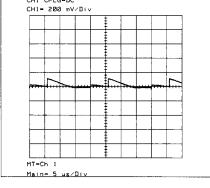
Probe: 10:1

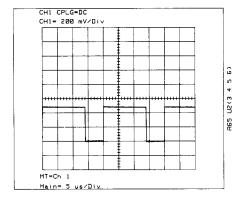
Ch1: Connection- U200(32,34) or U102(3,10) Coupling- dc Ground- 3rd graticule from the bottom

Trigger: Int- Ch1 Slope-Positive

BW Limit: On







Probe: 10:1

Ch1: Connection- U200(33)

Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1

Slope- Negative

BW Limit: On

Probe: 10:1

Ch1: Connection- U200(36, 37, 38, 39) or

U2(3, 4, 5, 6)

Coupling- dc

Ground- 3rd graticule from the bottom

Trigger: Int- Ch1

Slope-Positive

BW Limit: On

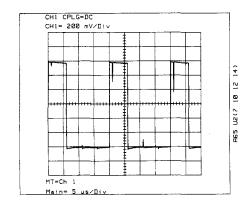
[J] BUBBLE COIL DRIVERS [K] BUBBLE MEMORY

Verify the waveforms on the outputs of U2(7, 9 through 15) with those shown in Figure 7-47. If any do not match, replace U2.

Verify the waveform on the outputs of U1 and U100 at test points TP1, TP2, TP4 and TP104 with those shown in Figure 7-48. If any do not match, replace the appropriate IC.

If the above waveforms are correct, replace U4.

Figure 7-47 Correct Waveform At A65 U2.



Probe: 10:1

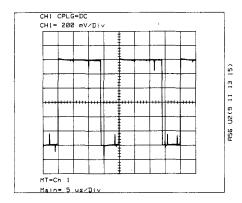
Ch1: Connection- U2(7,10,12,14)

Coupling- dc

Ground- 2nd graticule from the bottom

Trigger: Int- Ch1
Slope- Positive

BW Limit: On



Probe: 10:1

Ch1: Connection- U2(9,11,13,15)

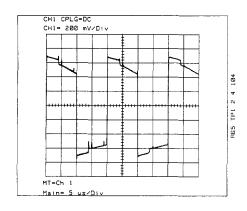
Coupling- dc

Ground- 2nd graticule from the bottom

Trigger: Int- Ch1
Slope- Negative

BW Limit: On

Figure 7-48 Correct Waveform At A65 U1 and U100 (TP1, 2, 4, 104).



Probe: 10:1

Ch1: Connection- TP1, TP2, TP4, TP104

 ${\sf Coupling-}\ dc$

Ground- 2nd graticule from the bottom

Trigger: Int- Ch1

Slope- Positive

BW Limit: On

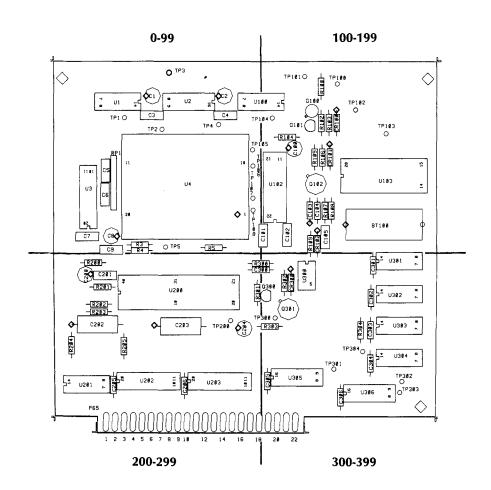
Table 7-57 A66/65 Assembly Signal Connections

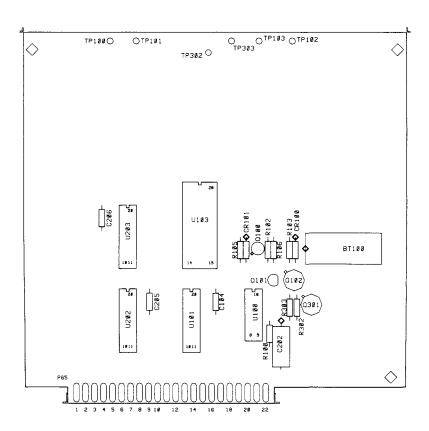
INPUTS

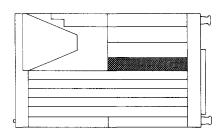
Signal	Functional	Connector	Origin	
Name	Block	Number	Assembly	
BUBS	В	P65(B16)	A40	
CMOSS	В	P65(B18)	A40	
PBR/W	В	P65(B15)	A40	
RESET	A	P65(B17)	A40	
Processor Address Bus	С	P65(A12 - A14)	A40	
PABO - PAB5	С	P65(B12 - B14)	A40	
PDB8	E	P65(A8)	A40	
PDBF	Α	P65(B11)	A40	

I/O SIGNALS

Signal	Functional	Connector	Destination
Name	Block	Number	Assemblies
Processor Data Bus	С	P65(A4 - A7)	A30, A40, A50,
PDB0 - PDB7		P65(B4 - B7)	A60, A80

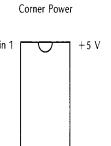




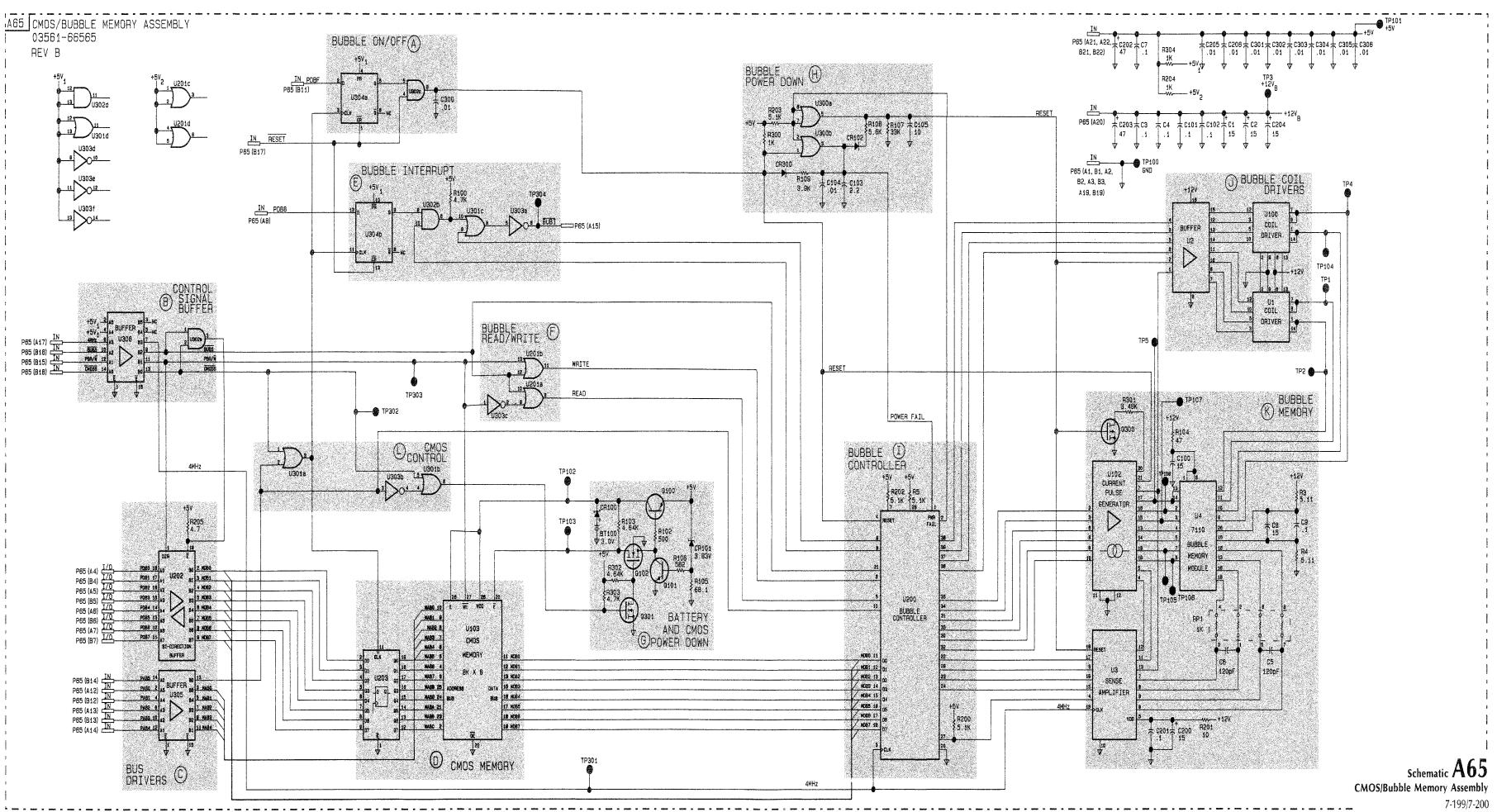


A65 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and ± 5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and ± 5 V is connected to pin 16)



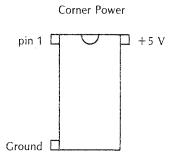
+12V	+5V	GND
6.13		2,9
16		8
1,6		15
6,13		2,9
1	22	11,12
	28	22
	40	20
	6,13 16 1,6	6,13 16 1,6 6,13 1 22 28



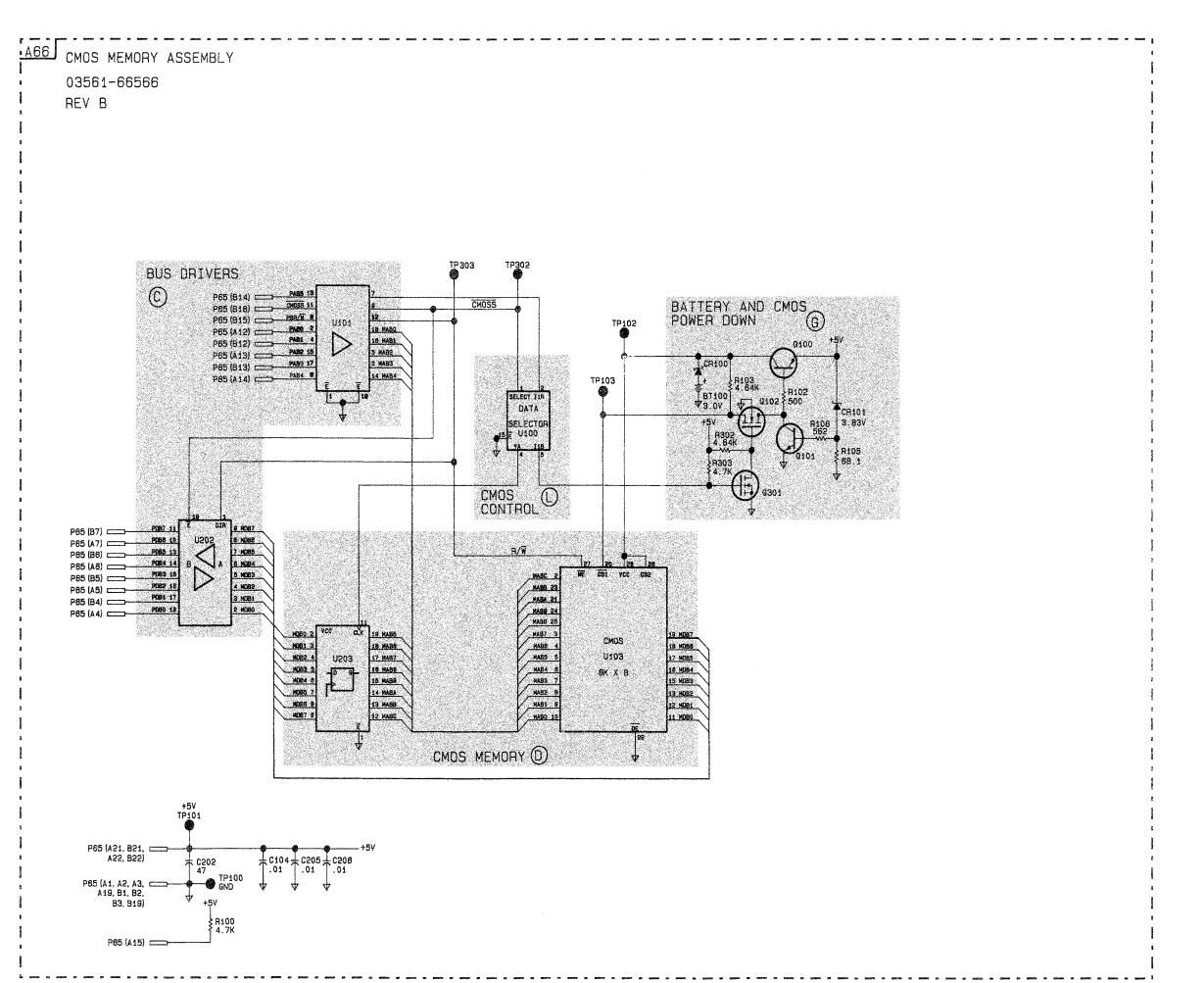
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A66 Assembly

All integrated circuits are corner powered except those shown in the table below. Corner powered ICs have ground connected to the lower left pin, and +5 V connected to the upper right pin regardless of the total pin count. (eg., for a 16 pin DIP, ground is connected to pin 8 and +5 V is connected to pin 16)



	+5V	GND
U103	28	22



Schematic A66 CMOS Memory Assembly 7-201/7-202

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7-28 A70, A71, A72 POWER SUPPLY ASSEMBLIES AND PART OF A99 MOTHERBOARD ASSEMBLY

7-29 Power Supply Circuit Description

GENERAL

The -hp-3561A power supply is a Master/Slave switching supply. That is, one supply is used as the control (master) and the other supplies are "slaved" to the master. It uses two power MOS-FET transistors in a half-bridge configuration to drive the main power transformer at a frequency of 128 kHz. The duty-cycle of the drive is determined by the pulse-width control circuits which monitor the output of the master supply. The +5V master supply is used as the logic supply. Nine slave supplies, which are independently L-C filtered and post-regulated by 3-terminal regulators, are used by analog and isolated ground logic circuits.

There are two control feedback loops in the main +5V supply. A voltage feedback loop provides control of the supply output during normal operation. During an over-current condition, another loop takes control and provides current limiting.

The power supply has protection circuits which monitor the supply outputs. These circuits are connected to a latching fault supervisor circuit which turns off the gate drive of the power FETs. An LED is is turned on when a fault is detected to indicate the fault condition. Any supply can cause a fault condition which would shut down all supplies.

A separate bias supply provides $\pm 12V$ to the control circuits of the master supply. This supply uses 3-terminal linear regulators and derive its power from a separate power transformer. This supply must be present for operation of the power supply.

[A] START UP CONTROL

This circuit prevents the main supply from turning on until the bias supply voltage exceeds +11V. U101 compares the +5V reference voltage to a divided down +12V bias voltage. The output disables the "Over Current Sense Pulse Width Control" and "Fault Supervisor" circuits and sends the Start Up Enable signal to the SHUT input on the Pulse Width Modulator.

[B] OVER CURRENT SENSE PULSE WIDTH CONTROL

The over current control circuitry monitors the current through resistor R200. The voltage developed across R200 is input to comparator U401. As the current reaches maximum, U401 starts to turn Q1 and Q400 on. This causes the Pulse Width Modulator IC to reduce the duty-cycle of the switching FETs which reduces the supply current.

[C] CLOCK SYNC CONTROL

This circuit buffers the 256kHz clock from the A20 Assembly and drives the SYNC input of the Pulse Width Modulator. It also monitors the +5V main supply and inhibits the clock to the Pulse Width Modulator until the supply reaches 4.75 volts.

[D] VOLTAGE SENSE PULSE WIDTH CONTROL

This circuit compares the +5V main supply with the +5V reference. As the main supply starts to exceed the reference, this circuit pulls the COMP line lower causing the Pulse Width Modulator to reduce the duty-cycle of the drive to the switching FETs which reduces the main voltage.

[E] PULSE WIDTH MODULATOR

The Pulse Width Modulator is the controller for the -hp-3561A power supply. It drives the switching circuits in a manner which maintains a constant voltage at the supply output. It does this by varying the on-off time (duty cycle) of the switching FETs. The on-off time is controlled by the COMP input at U1(3). As this voltage level lowers, the on time becomes narrower.

[F] SHUT DOWN DRIVER

Signals from the Primary Current Sensor [K] and Fault Supervisor [L] are ORed at the input of the Shut Down Driver. Either of these two signals enable the Shut Down Driver to disable the Pulse Width Modulator IC and trun off the power supply.

[G] POWER SUPPLY OVERVOLTAGE COMPARATORS

[H] ISOLATED POWER SUPPLY OVERVOLTAGE COMPARATORS

These two circuits monitor the isolated and chassis-referenced supplies. If an overvoltage condition occurs in any one of the supplies, the overvoltage circuit will trigger the Fault Supervisor [L] and turn off the power supply.

[I] VMOS DRIVER

The VMOS Driver buffers the drive signals from the Pulse Width Modulator [E] and drives the switching FETs through transformer T200.

[]] +5V OVERVOLTAGE COMPARATOR

This circuit compares the +5V main supply with the +5V reference. If an overvoltage condition occurs, this circuit will activate the Fault Supervisor [L] to turn off the power supply.

[K] PRIMARY CURRENT SENSOR

Current transformer A70T600 senses the primary current of the main transformer A71T300. CR500, CR501 and U501c/d convert this current to a voltage at U501a/b pins 11 and 14. When a primary overcurrent condition is sensed, this circuit enables the Shut Down Driver [F] and turns off the power supply.

[L] FAULT SUPERVISOR

All fault-detecting-circuit outputs are latched by the Fault Supervisor. This latch turns off the Pulse Width Modulator through the Shut Down Driver [F] and lights a fault indicating LED during any fault condition. The four LEDs indicate which fault-detecting circuit was activated. These four LEDs are off during normal operation.

CR1 - Primary Overcurrent Indicator

CR2 — +5V Overvoltage Indicator

CR3 — Power Supply Overvoltage Indicator

(ground referenced slave supplies)

CR4 — Isolated Power Supply Overvoltage Indicator (isolated slave supplies)

[M] RECTIFIER/FILTER

This Full-Wave bridge rectifier and R-C filter network convert the ac power input to approximately 170Vdc which is then supplied to the switching transistors [O]. When S2 is set to 115V, the Rectifier/Filter circuit functions as a voltage doubler. When S2 is set to 230V, the Rectifier/Filter circuit functions as a full-wave bridge.

[N] BIAS TRANSFORMER

The ac Line voltage is stepped down by the bias transformer and sent to the bias power supply circuitry [Q].

[O] SWITCHERS

The Switcher circuit consists of two switching power FETs and transient protection circuitry. The FETs are driven by the VMOS Driver [I] and switch the rectified line power to the power transformer.

[P] LINE SYNC CONTROL

The ac line signal taken from the secondary of the bias transformer is buffered and shaped by the Line Sync Control circuit. The sync output is used by the display circuitry as scan synchronization.

[Q] BIAS VOLTAGE POWER SUPPLY

The secondary voltage of the bias transformer is rectified and filtered to provide the \pm 12V bias supplies which are used by the various power supply control circuits.

[R] LOW VOLTAGE DETECTOR

This circuitry monitors the line voltage through the secondary of the bias transformer. If the line voltage drops below minimum level, this circuit sends a power fail signal to the A40 Processor Assembly.

[S] + 5V RECTIFIER

This circuit rectifies and filters the +5V main supply. This supply powers the logic circuits.

[T] INSTRUMENT GROUND RECTIFIERS

This circuit rectifies one of the two multi-tap secondary windings of the power transformer to produce three supply voltages which are referenced to chassis ground.

[U] ISOLATED GROUND RECTIFIERS

This circuit rectifies one of the two multi-tap secondary windings of the power transformer to produce four supply voltages whose grounds are not referenced to the chassis (floating).

[V] PS FILTER

This is the L-C filtering circuitry for all slave supplies. The Zener diodes in this circuit provide overvoltage protection for the input of the three-pin regulators [W,X].

[W] INSTRUMENT GROUND POWER SUPPLY

These four linear regulators are on the A99 Motherboard Assembly. They provide the four regulated supplies which are chassis grounded.

[X] ISOLATED GROUND POWER SUPPLY

These five linear regulators are on the A99 Motherboard Assembly. They provide the five regulated supplies which are not referenced to chassis ground (floating ground).

7-30 Troubleshooting The Power Supply

WARNING

The -hp-3561A Power Supply A70, A71 and A99 Assemblies contain exposed ± 170 primary voltages. Read the following safety consideration before attempting to troubleshoot the Power Supply assemblies. Contact with these voltages can cause serious personal injury.

SAFETY CONSIDERATION

The -hp-3561A power supply has many exposed areas which contain Primary voltage. These areas are shaded in red on the schematic and component locator. Extra care must be exercised when troubleshooting in these areas.

GENERAL

The power supply in the -hp-3561A is a Master/Slave type. The troubleshooting procedure will be to determine:

- A. If the problem is in the Master or Slave power supply.
- B. Which functional circuit(s) of the power supply failed.

The power supply circuits between the A70, A71 and A72 Assemblies are interactive so the troubleshooting will be to isolate the problem to a functional circuit rather than to an assembly. The approach will be to verify which particular circuits are operating properly.

There are four LEDs on the A70 Assembly which are normally not lighted. When an LED is on, it indicates that a fault condition was detected and which monitoring circuit was involved. This will turn off the drive from the Pulse Width Modulator (shut down condition). However, the power supply can have a failure without an LED lit. For example, the Bias Supply can be bad which would not allow the power supply to operate, or there could be a low voltage condition which would not be detected by the power supply protect circuitry.



The heat sinks on the A70 Assembly are connected to ± 170 primary voltage. Exercise extreme caution when trouble-shooting in this area. Contact with these voltages can cause serious personal injury.

WARNING

Wait at least three (3) minutes after power has been turned off before disconnecting the power supply cables W70 and W71, or removing the A70 or A71 Assemblies. A ± 170 Vdc charge is retained in the A99 Motherboard Assembly capacitors and a sudden discharge may occur if the wait-time is not observed.

REMOVING THE A20 ASSEMBLY

In normal operation, the A20 Assembly provides the 256 kHz switching clock to the power supply. However, when the A20 Assembly is removed the power supply pulse width modulation circuit will generate its own clock. To prevent the A20 Assembly Clock from interfering with power supply troubleshooting, remove the A20 Assembly before troubleshooting any part of the power supply.

ISOLATING THE PROBLEM TO THE MASTER OR SLAVE SUPPLY



When removing or inserting any PC Assembly, the ac Line switch must be in the OFF position. Otherwise, PC Assembly damage may occur.

There are four protection circuits which will light the LEDs on the A70 Assembly. They are primary overcurrent, +5V master overvoltage, power supply overvoltage and isolated power supply overvoltage. If any of these LEDs are on and the power supply is shut down, turn the main power off and remove the A72 Assembly. Turn the main power on. If none of the LEDs light, the master +5V supply is working and the problem is in the slave supply. Troubleshoot the slave supply.

If any of the LEDs light, and the power supply is shut down, turn the main power off and disconnect W71 from A70J300. This will disable the main power transformer and rectifiers. Turn the main power switch on. If any of the LEDs light, there is a problem in the protection circuitry. Troubleshoot the protection circuits.

If none of the LEDs light, there is a problem in the main power transformer (A71T300) or the rectifier circuits [S],[T], or [U] blocks on the power supply schematic.

TROUBLESHOOTING THE SLAVE SUPPLY

Isolate the problem to one or more of the slave supplies by lifting one of the legs of the input inductors on the A72 Assembly (PS Filter block [V]). Troubleshoot the faulty slave supply. Note that switching the front panel input reference switch to CHASSIS connects the isolated ground to the chassis.

TROUBLESHOOTING THE MASTER SUPPLY

There are three supplies needed in order for the master supply to operate. They are the $\pm 12V$ Bias and the +5V reference. The Bias supply circuitry is on the A71 Assembly [Q], with its transformer on the A99 Assembly. The +5V reference is generated by the PWM IC U1(18) on the A70 Assembly. Also needed is the Sync signal coming into the PWM IC at U1(12). Before troubleshooting the master supply, verify that the bias and reference supplies and sync signal are operating.

WARNING

This setup procedure exposes ± 170 Vdc primary voltage on the large heat sinks and other parts of the A70 Assembly. Extreme caution must be exercised when troubleshooting during this condition. Contact with the high voltage can cause serious personal injury.

A70 [G],[H],[J],[K],[L] TROUBLESHOOTING

Place the A70 Assembly on an extender board and remove cable W70 from A70J700 (to the A99 Motherboard Assembly). This removes the \pm 170Vdc primary voltage from the A70 and A71 Assemblies. Turn on the AC Line power switch. If one of the A70 LEDs comes on and the main power supply is shut down, there may be problem in the protection circuit. Troubleshoot the indicated protection circuit.

A70 [B],[D] TROUBLESHOOTING

With the cable removed from A70J700, turn on the main power switch. If no LEDs light, and the main supply is shut down, the problem may be in the pulse-width feedback control or the primary switching circuits. To verify proper operation of the feedback pulse-width control circuits [B] and [D]:

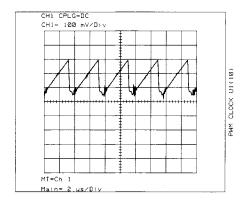
- 1. Adjust a dc power supply to 5V \pm .2V and connect it to A70TP105 (+ to TP105, to TP130).
- 2. Monitor the pulse width signal at A70TP100 and A70TP101.
- 3. Increase the dc supply voltage to +6V. The pulse width should change width to minimum. If it does not, troubleshoot the Voltage Sense Pulse Width Control circuit [D].
- 4. Monitor the pulse width at A70TP100 and TP101 (drive signal).
- Connect a clip lead to TP400. Ground the other end of the clip lead. The pulse width should change width to minimum. If it does not, troubleshoot the Overcurrent Sense Pulse Width Control [B].

If these two pulse width control circuits are working, troubleshoot the primary switching circuits [O] and [I].

OSCILLOSCOPE SIGNAL PICTURES

The oscilloscope plots are used for troubleshooting the power supply. Note that all measurements are taken with a 10:1 probe. Other notes unique to the measurement are written next to the plot. Figure 7-49 gives those waveforms necessary for troubleshooting circuits on the A70 Assembly and Figure 7-50 gives those waveforms necessary for troubleshooting circuits on the A71 Assembly.

Figure 7-49 A70 Assembly Troubleshooting Waveforms

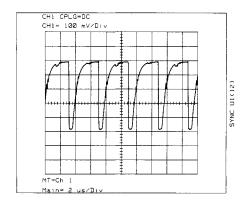


Probe: 10:1

Ch1: Connection- A70U1(10) Coupling- dc Ground- Center Graticule

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On



Probe: 10:1

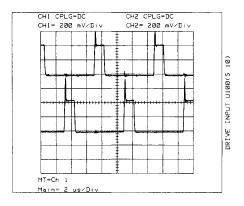
Ch1: Connection- A70U1(12)

Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal-Ch1 Slope: Positive

Bandwidth Limit: On



Probe: 10:1

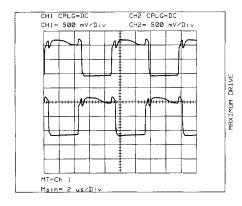
Ch1: Connection- A70U100(10)
Coupling- dc

Ground- Third Graticule From Top

Ch2: Connection- A70U100(5)
Coupling- dc
Ground- Third Graticule From Bottom

Trigger: Internal-Ch1
Slope: Positive

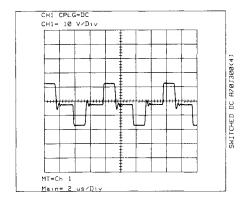
Bandwidth Limit: On



CHI CPLG=DC CH2 CPLG=DC CH2 S80 mV/DIV

WT=Ch 1

Main= 2 us/Div



Probe: 10:1

Ch1: Connection- A70 TP100

Coupling- dc

Ground- Third Graticule From Top

Ch2: Connection- A70 TP101

Coupling- dc

Ground-Third Graticule From Bottom

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On

This is the drive signal at maximum duty cycle (cable removed from A70J700)

Probe: 10:1

Ch1: Connection- A70 TP100

Coupling- dc

Ground- Third Graticule From Top

Ch2: Connection- A70 TP101

Coupling- dc

Ground- Third Graticule From Bottom

Trigger: Internal- Ch1 Slope: Positive

Bandwidth Limit: On

This is the drive signal at normal duty cycle

(all assemblies installed).

WARNING

WARNING! THIS MEASUREMENT CONTACTS 300VP-P PRIMARY DC VOLTAGE. USE EXTREME CAUTION WHEN PROBING THIS SIGNAL!

Probe: 10:1, $10M\Omega$, 600V Maximum Voltage

(-hp-10014A)

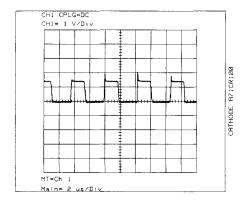
Ch1: Connection- A70J300(4)

Coupling- dc

Ground- Center Graticule

Trigger: Internal-Ch1
Slope: Positive

Bandwidth Limit: On



Probe: 10:1

Ch1: Connection- Cathode of A70CR100

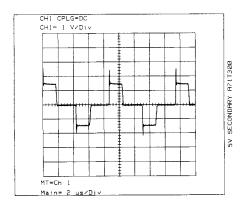
Coupling- dc

Ground- Center Graticule

Trigger: Internal-Ch1 Slope: Positive

Bandwidth Limit: On

Figure 7-50 Correct Waveform At A71CR100



Probe: 10:1

Ch1: Connection- Junction Of A71CR100

and A71R203

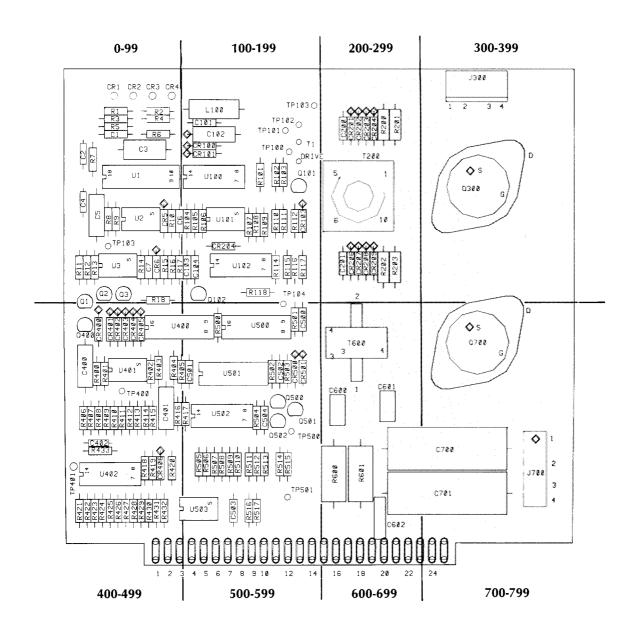
Coupling- dc

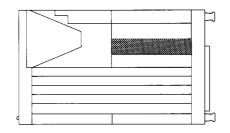
Ground- Center Graticule

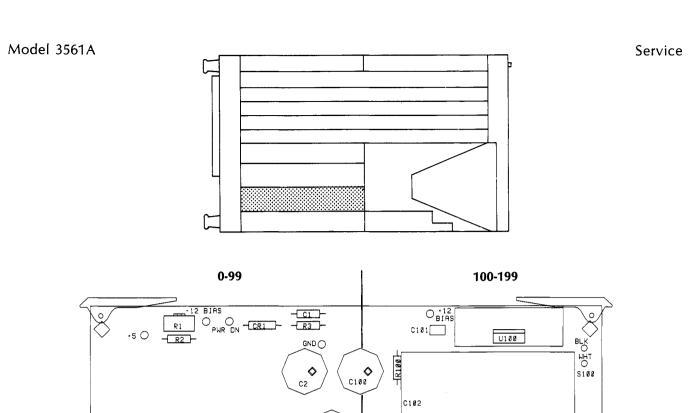
Trigger: Internal-Ch1

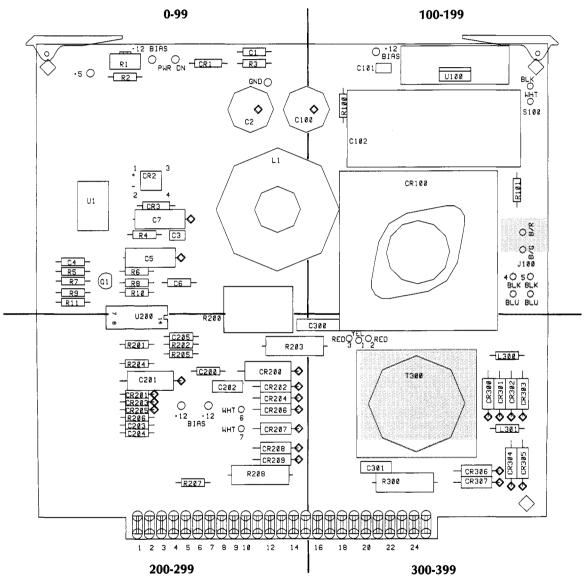
Slope: Positive

Bandwidth Limit: On

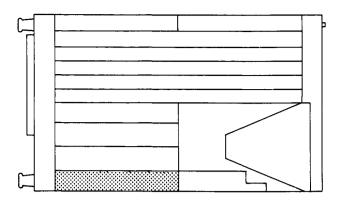


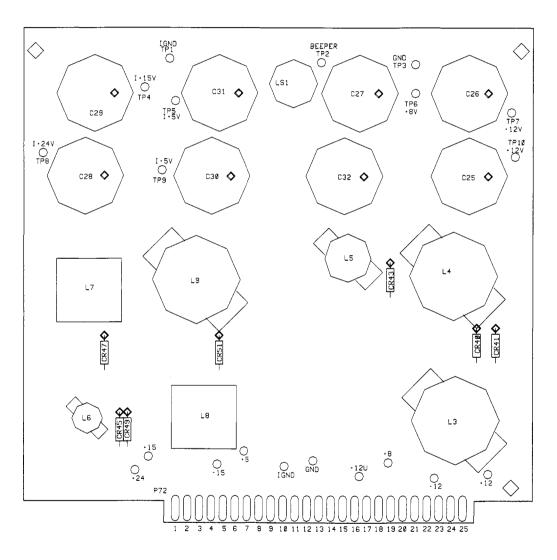






A71

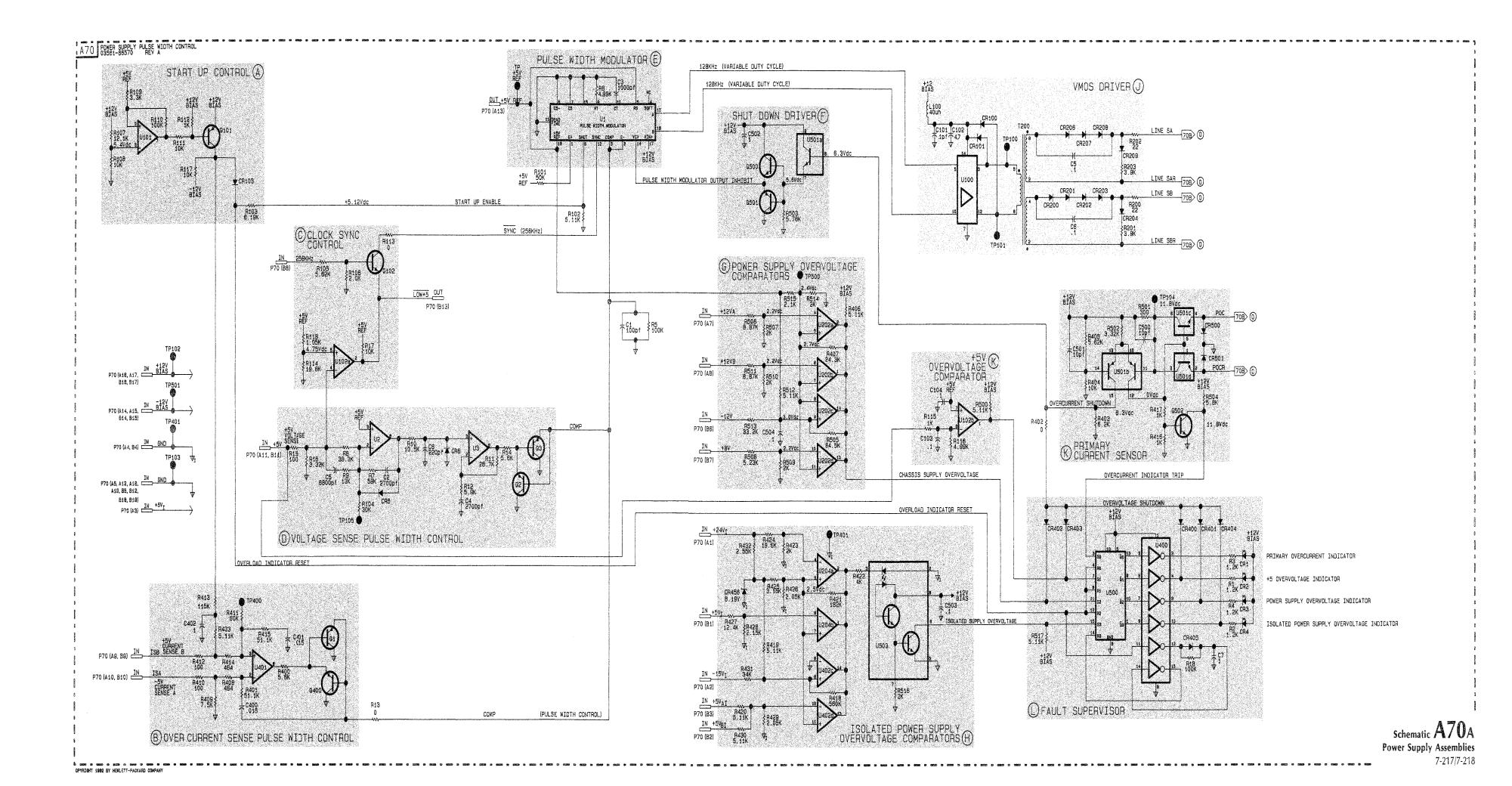




A72

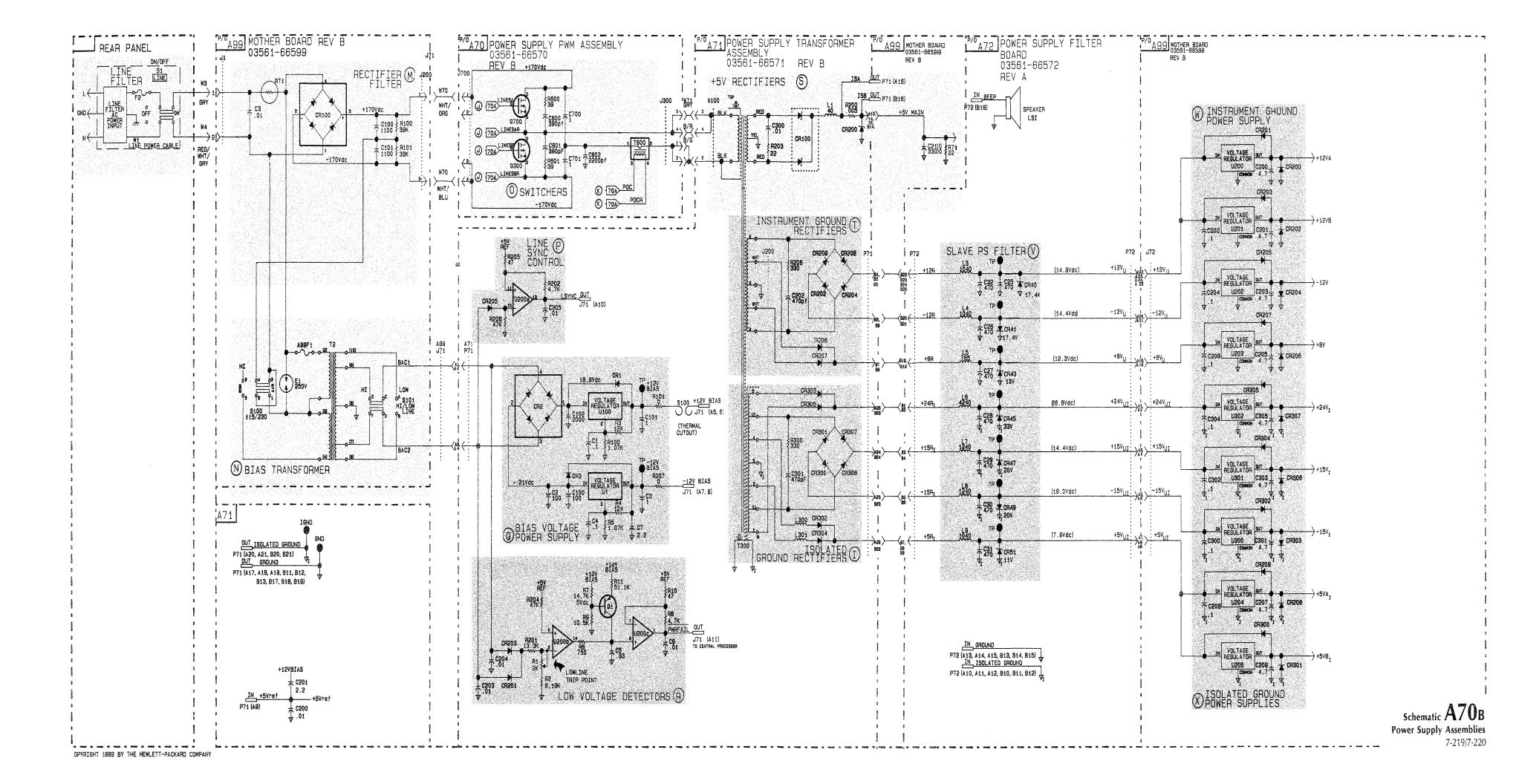
A70 Assembly

	+12VBIAS	-12VBIAS	+5V _{IU}	-15 _{VI}	GND
U1	17			The state of the s	15
U2	7	4		1	
U3	7	4			
U101	8	1,4			
U400	1 1				8
U401	7	4			
U402			3	12	
U500	16				8
U502	3				12



A71 Assembly

	+12VBIAS	GND
U200	3	12



7-31 A80 AND A81 KEYBOARD ASSEMBLIES

7-32 Keyboard Driver Circuit Descriptions

GENERAL

The front panel switches and LED's communicate with the processor over data line: PDB0 through PDB7. The processor can write to or read from the keyboard assembly. The processor periodically scans the keyboard to see if a switch has been pressed rather than working with an interrupt scheme. The individual blocks are explained in the text that follows.

[A] ADDRESS I/O DECODING

This circuitry is used to enable the various latches and drivers to accept or transmit data onto the front panel's internal bus. Processor address bits 0 and 1 are decoded by a 1 of 4 circuit. The four output lines are the enable lines for the functional blocks [C], [D] and [E].

[B] PROCESSOR DATA BUS BUFFER

This is a bi-directional 3-state device which interfaces the front panel with bits 0 through 7 of the data bus. The data direction and enable signals are PBR/W (read/not write) and FPS (front panel scan).

[C] SWITCH COLUMN DRIVE

This circuitry contains an octal latch and eight inverting buffers. The 8-bit bus is applied to the column switch poles through these devices. When a switch is depressed, the column data is transferred to the row circuitry and read by the processor.

[D] SWITCH ROW READ

The switch row read is an octal receiver. When a switch is depressed, the column data is applied to the input. When the processor wants to read the key, it will enable the receiver to output via the switch row select. This output then goes through the processor data bus buffer to the processor's data bus.

[E] LED DRIVE

Two octal D-flops store the LED data sent from the processor board. This data is output through two resistor packs to the cathodes of the LED's. The LED's are not multiplexed but rather enabled continuously.

7-33 Removing The Front Panel

WARNING

Disconnect the main power cord before attempting to remove the front panel.

The following procedure outlines the steps necessary to remove the front panel.

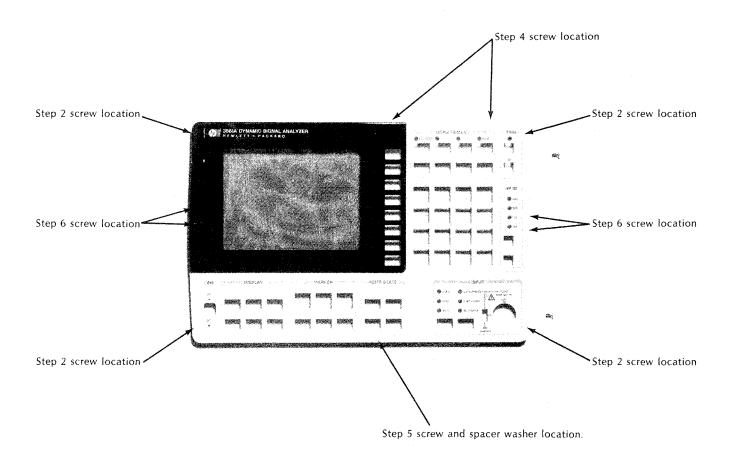
1. Remove the instrument's top and bottom covers.



+8000 Vdc is present at all times in the flyback transformer and CRT EVEN WITH THE MAIN POWER CORD REMOVED. Be extremely careful when working in proximity to this area. The high voltage could cause serious personal injury or death if contacted.

- 2. Remove the four screws which secure the dress panel to the front panel casting. Refer to Figure 7-51 for their location.
- 3. Press the top dress panel tab on either side to remove the dress panel from the front panel casting.
- 4. Remove the two screws on the top right of the front panel casting which hold it to the aluminum board guide bracket. The location is shown in Figure 7-51. Do not remove the two screws over the CRT. These screws hold the CRT shield to the front panel.
- 5. Remove the screw and spacer washer from the bottom center of the front panel casting. The location is shown in Figure 7-51.
- 6. Remove the four screws holding the front panel casting to the left and right side rails as shown in Figure 7-51.
- 7. Remove the input cable W10 from the A10 Input Amplifier Assembly by pulling the A10 connector away from the A10 Assembly toward the front of the instrument.

Figure 7-51 Front Panel Disassembly Screw Locations



The front panel can now be pulled away from the instrument frame. If the black and white wire assembly going from the Motherboard Assembly to the CRT yoke is removed from the motherboard connector, the front panel can be placed flat in front of the instrument frame.

WARNING

Do not damage or remove the green grounding wire which connects the front panel casting to the instrument's aluminum frame. Removing this wire will allow the front panel casting to float up to +8000 Vdc.

ECAUTION 3

Be careful not to damage the ribbon cable W81 which connects the front panel circuitry with the instrument's mother-board assembly.

7-34 Troubleshooting the A80 and A81 Keyboard Assemblies

GENERAL

Failures on the A80 or A81 Keyboard Assemblies are not detected by the power-up test routine. There are also no built-in diagnostics which will test the keyboard assemblies and display an ERROR RETURN CODE should a failure exist. For these reasons, a list of keyboard failure symptoms is given in Table 7-58.

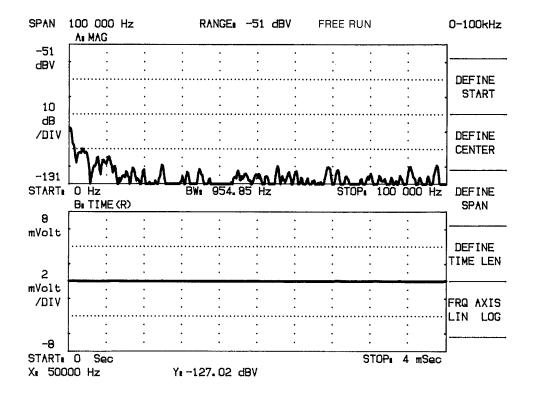
Signature analysis is used to troubleshoot the A81 Keyboard Driver Assembly.

Table 7-58 Keyboard Failure Symptoms

The following symptoms may occur if there is a failure on the keyboard assemblies:

- During the power-up routine, the front panel LEDs should go through two lamp tests during which all LEDs should illuminate. If any of the LEDs do not illuminate, the failure may be on the A80 Keyboard Assembly. If none of the LEDs illuminate, the problem may be on the A81 Keyboard Driver Assembly.
- 2. Immediately after the 10 second power-up routine, only the MEAS and AUTO LEDs should be illuminated. If either is not, the problem may be on the A80 Keyboard Assembly. If both are not, or there are any others illuminated, the problem may be on the A81 Keyboard Driver Assembly.
- 3. Immediately after the 10 second power-up routine, the display shown in Figure 7-52 should appear on the CRT. Note particularly the definitions of the softkey menu. If the display does not match, there may be a stuck key on the A80 Keyboard Assembly. Check all keys and make sure that none are stuck in. There may also may be a shorted trace on the A80 Keyboard Assembly traces.
- 4. Immediately after the 10 second power-up routine, if the CRT display continually flashes and the internal beeper continually sounds, there may be a stuck key or shorted trace on the A80 Keyboard Assembly.
- 5. During instrument operation, pressing one of the front panel keys has no affect.
- 6. During operation, pressing one of the front panel keys does not illuminate the correct LED indicator.
- 7. Some or all of the HP-IB LED indicators does not illuminate during HP-IB operation and the instrument is operating properly under remote control.

Figure 7-52 Correct Power-up CRT Display



A81 KEYBOARD TROUBLESHOOTING

To troubleshoot the A80 and A81 Keyboard Assemblies, the front panel must be removed by following the instructions in Paragraph 7-33. However, to repair or replace either of the two assemblies, they must be removed from the front panel casting and separated.

With the front panel removed, the A81 Keyboard Driver Assembly is exposed. The A80 Keyboard Assembly is between the A81 Assembly and the front panel casting. The two assemblies make electrical contact through W80 which is a foam pressure cable. The foam supports one plane of fine wires. If these assemblies are pulled apart for repair, make certain that W80 is oriented properly with the fine wires making contact with the assembly connectors. Otherwise no contact will be made and the A80 Keyboard Assembly will not function.

To verify that the keyboard assemblies are causing symptoms 3 and 4, remove the keyboard interconnect cable W81 from the Motherboard Assembly and turn the instrument LINE switch ON.

WARNING

The green grounding wire which connects the front panel casting to the mainframe sheet metal must be connected and making good contact. If this wire is missing or not making good contact, the front panel will float up to +8000 Vdc!

If the instrument powers-up correctly, there is a problem with the Keyboard Assemblies. If however, the instrument still exhibits symptoms 3 and 4, there is a problem elsewhere in the instrument and you should refer to the fault isolation information in Section 6. Refer to Table 7-59 for the keyboard DSA troubleshooting information.

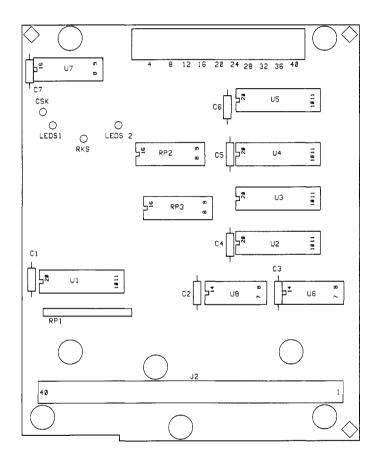
- 1. With the power turned OFF, remove the A60 Digital Display Driver Assembly (this disables the internal beeper which is activated during this test).
- 2. Move A40W1 from the left position to the right position as shown:
- 3. Turn the instrument ON and wait approximately 10 seconds before checking the signatures in Table 7-59.

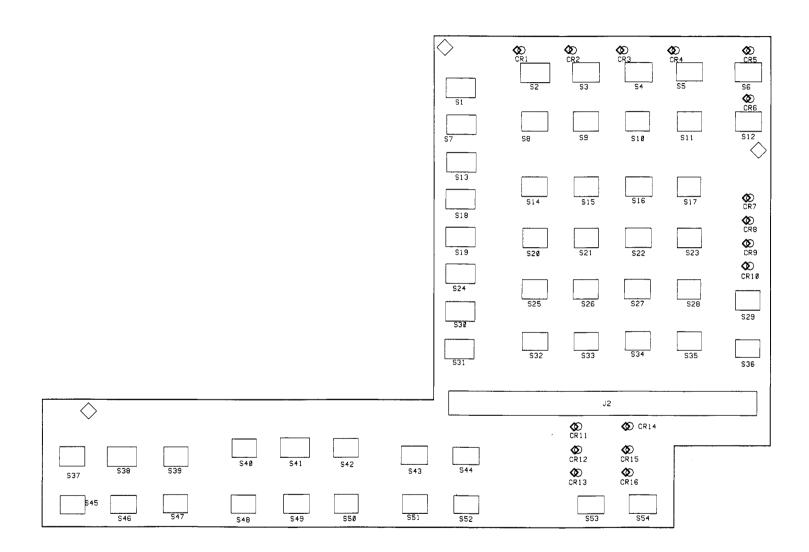
Table 7-59 Keyboard DSA Troubleshooting Information

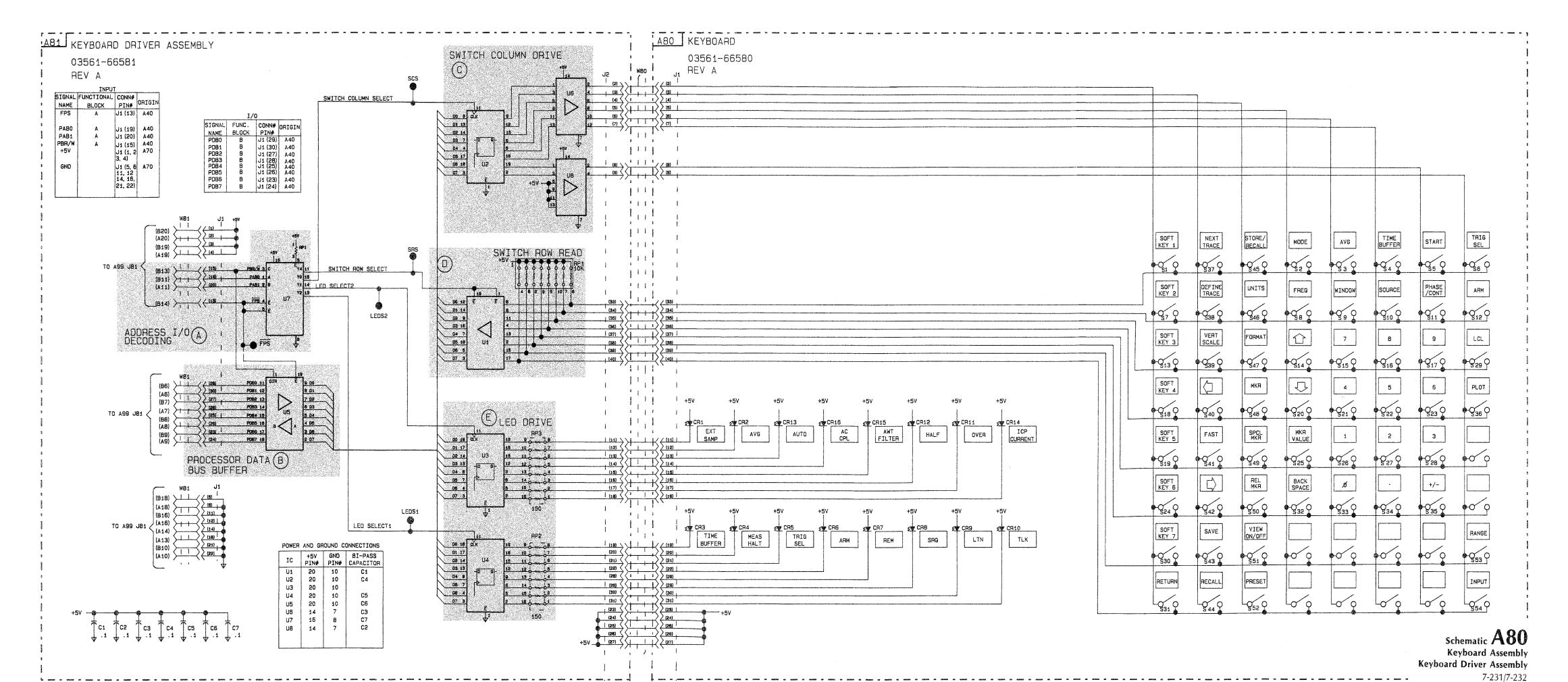
Start	Polarity	Connection	
Clock Start Stop			
		A81 TP FPS	
Cton		A40 CR1 (Green LE	
Згор		A40 CR1 (Green LE	D Cathode)
+5 V Signature -	5UAH		
[A] Address I/O Do	ecoding	[B] Processor Data	Bus Buffer
	.		
U7(11)	5UAH	U5(2)	0836
U7(13)	47P6	U5(3)	A925
U7(14)	9HU <i>7</i>	U5(4)	C17U
U7(15)	P553	U5(5)	106F
		U5(6)	524A
		U5(7)	8209
		U5(8)	F02U
		U5(9)	A495
[C] Switch Columr	n Drive	[E] LED Drive	
U2(2)	9968	U3(2)	82H3
U2(5)	5UAH (HIGH)	U3(5)	62 FD 5
U2(6)	0000 (LOW)	U3(6)	
	9968		5UAH (HIGH)
U2(9)		U3(9)	P19C
U2(11)	P553	U3(11)	9HU7
U2(12)	H416	U3(12)	P19C
U2(15)	8CCC	U3(15)	3FP5
U2(16)	4H7P	U3(16)	CP36
U2(19)	8CCC	U3(19)	CP36
U6(2)	0000 (LOW)	U4(2)	4402
U6(4)	0000 (LOW)	U4(5)	4402
U6(6)	0000 (LOW)	U4(6)	PF69
U6(8)	5UAH	U4(9)	A86C
U6(10)	0000 (LOW)	U4(11)	47P6
U6(12)	0000 (LOW)	U4(12)	A86C
		11475-5	40.5
118(3)	0000 (1004)	U4(15)	A86C
U8(2)	0000 (LOW)	U4(16)	C3F4
U8(4)	0000 (LOW)	U4(19)	U7F6

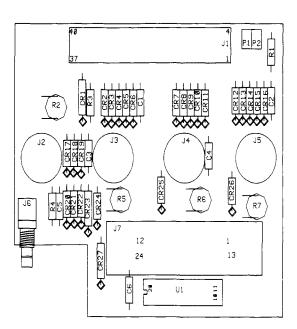
Model 3561A

Service

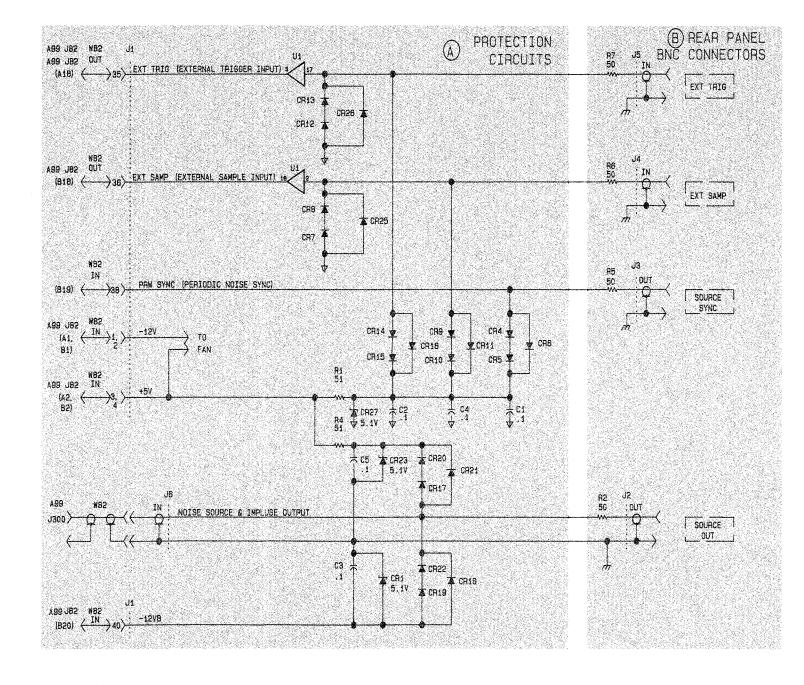


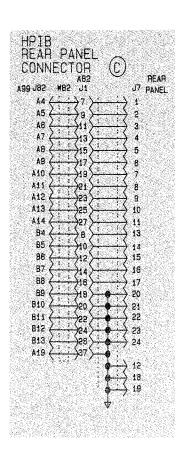












7-36 A90 ANALOG DISPLAY DRIVER ASSEMBLY AND PART OF A99 MOTHERBOARD ASSEMBLY

7-37 Analog Display Driver Circuit Description

GENERAL

The main function of the analog display driver is to provide the CRT bias voltages and drive signals. The -hp-3561A uses a magnetic deflection CRT with a raster scan CRT sweep pattern. The raster scan pattern consists of a 512 horizontal by 256 vertical grid on the CRT screen. Each grid position is called a pixel. A pixel is illuminated when it is hit by the electron beam inside the CRT. This beam is turned on and off by the cathode drive signal and can be moved to any part of the CRT by a magnetic field created by the yoke. The yoke has two control inputs; vertical position control and horizontal position control. With the horizontal and vertical beam controls, the beam is swept down each vertical column of pixels, starting with the left most column and moving to the right. When all 512 columns of pixels have been covered, the beam is blanked and retraces to the start position. With this sweep pattern there are 512 vertical sweeps for each horizontal sweep, thus the vertical sweep is called the fast sweep and the horizontal sweep is called the slow sweep. The slow sweep operates at the power line frequency when jumper A60J200 is in the SYNC position and at 62.8 Hz when jumper A60J200 is in the 60 Hz position. The fast sweep operates at 36 kHz.

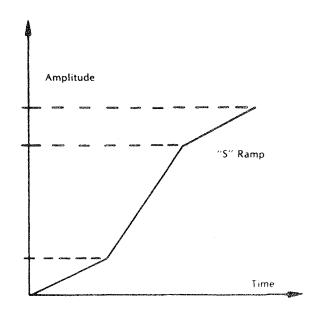
[A] VIDEO DRIVE

The video drive circuit provides the cathode drive signal (CATHD) which turns the CRT beam on or off. When the VIDH and the VIDF signals are both high, the CATHD signal is pulled high to ± 14.8 Vdc through Q203. This turns the CRT beam off. When the VIDF (video full bright) signal goes low, the CATHD signal is pulled low to -12 Vdc through Q202. This turns CRT beam on full intensity. When the VIDH (video half bright) goes low, the CATHD signal is pulled low to -9 Vdc \pm 3 Vdc, (depending on the position of the half bright adjustment), through Q205. This turns the CRT beam on half intensity. The $\pm 12V_U$ volt supply is an unregulated supply and may vary in voltage around ± 14.8 Vdc.

[B] SLOW SWEEP HORIZONTAL DRIVE

The slow sweep circuit generates an "S" shaped ramp signal used to drive the horizontal position of the yoke. This ramp is generated from the SSYNC signal which is output from the A60 Assembly. When SSYNC is high, Q400 is turned off allowing the current source (Q3) to charge C400 creating a ramp at TP100. When SSYNC goes low, Q400 is turned on pulling the voltage across C400 to ground. Feedback around C400 is provided to put an "S" shape into the ramp. This feedback loop uses CR1 and CR2 to divide the ramp into three sections. The "S" shape is created by giving the center section a larger gain as shown in Figure 7-53.

Figure 7-53 "S" Ramp



[D] FAST SWEEP VERTICAL DRIVE, [E] FLYBACK TRANSFORMER

The fast sweep circuit works in conjunction with the flyback transformer to generate a ramp signal to drive the vertical control of the yoke. The FSYNC (fast sync) signal generated on the A60 Assembly establishes the frequency of the vertical ramp. At power-on, capacitors C9, C102, and C103 all charge up to approximately \pm 30 Vdc. These capacitors then provide constant voltages to power the flyback transformer. When PDRIVE goes high, Q1 on the A99 Assembly is turned on, shorting pin three of the flyback transformer to ground. This causes C102 to discharge through the vertical yoke coil, creating a ramp. When PDRIVE goes low, Q1 on the A99 Assembly is turned off causing a large current surge from the flyback transformer. The current surge charges C102 through the vertical yoke coil causing the CRT beam to retrace. Feedback of the retrace pulse is provided through the PSENSE signal. This feedback works to align the rising edge of PSENSE with the falling edge of FSYNC by changing the ON time of the PDRIVE signal. If the edges of the FSYNC and PDRIVE signals are not aligned, the display pattern will not be vertically centered on the CRT screen.

The matching between the flyback transformer, T100, and capacitors A99 C5, C6, C7, and C8 determines the retrace pulse width and the value of the CRT anode voltage. Whenever T100 is replaced, these capacitors must be re-selected using the procedures given in Section 7-38.

[F] HIGH VOLTAGE

The high voltage circuit uses two taps from the flyback transformer to generate the grid bias voltages for the CRT. When the PDRIVE signal goes low, a current surge is generated in the flyback transformer which causes a +450 Volt peak and a -150 Volt peak voltage spike. These voltages are low pass filtered and divided down to drive the CRT grids.

Table 7-60 A90 Assembly Signal Descriptions

Signal	Description
CATHD	CATHode Drive: Turns the CRT beam on or off; the voltage of this signal relative to the voltage of the BRIGHTNESS signal determines the intensity of the CRT beam.
FDRIVE	Fast Sweep Yoke DRIVE: Powers the vertical yoke coil.
FDRIVER	Fast Sweep Yoke DRIVE Return: Current return from the vertical yoke coil.
FSYNC	Fast Sweep SYNCronizer: This signal syncronizes the fast sweep trace with the slow sweep trace and the cathode drive signal.
PDRIVE	Pulse Drive: Initiates a retrace pulse on falling edge of PDRIVE.
PSENSE	Pulse SENSE: Detects a retrace pulse. Provides feedback to vertically center the display on the CRT screen.
RTRC	ReTRaCe: This signal is the PSENSE signal clipped to +5 Volts and indicates when a retrace is occurring.
SDRIVE	Slow Sweep Yoke DRIVE: Powers the horizontal yoke coil.
SDRIVER	Slow Sweep Yoke DRIVE Return: Current return from the horizontal yoke coil.
SSHAPE	S SHAPE: Provides feedback to put an "S" shape into the slow sweep ramp.
SSYNC	Slow Sweep SYNCronizer: This signal syncronizes the slow sweep trace with the fast sweep trace and the cathode drive signal.
VIDH	VIDeo Drive Half Bright: Turns the CRT beam on half intensity.
VIDF	VIDeo Drive Full Bright: Turns the CRT beam on full intensity.

7-38 Troubleshooting the Analog Display Driver

SAFETY CONSIDERATIONS

Troubleshooting the analog display driver may require placing the A90 Assembly on an extender board or removing the plastic shield from the bottom of the A99 Motherboard Assembly exposing dangerous voltages. Service should only be performed by service trained personnel who are aware af the hazards involved. voltages. Hazardous voltage areas are outlined in red on the schematic diagram and component locators. Use extreme care when troubleshooting in these areas.

WARNING

8000 Vdc are present at all times in the flyback transformer and CRT EVEN WHEN THE INSTRUMENT IS TURNED OFF. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

Power Supply Capacitors on the A99 Motherboard Assembly will remain charged to ± 170 Vdc for at least three (3) minutes after power is removed from the instrument. These voltages are exposed when the protective plastic shield is removed. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

WARNING

+450 and -150 Volts are present on the A90 Analog Display Driver Assembly and the A99 Motherboard Assembly. Be extremely careful when working in proximity to this area. The high voltage can cause serious personal injury if contacted.

TROUBLESHOOTING AND REPLACING PARTS ON THE A99 MOTHERBOARD ASSEMBLY

All parts on the A99 Assembly should be checked by removing the protective plastic shield covering the bottom of the A99 Motherboard Assembly. The front panel should not be removed while power is applied to the instrument. Once a faulty component is isolated, the front panel can then be removed and the component replaced. Instructions for removing the front panel are given in Section 7-35 "A80 AND A81 KEYBOARD ASSEMBLIES"

WARNING

Disconnect the power cord before removing the front panel and replace the front panel before re-applying power. Do not disconnect the green grounding wire connecting the front panel the the chasis. If this grounding wire is disconnected the front panel can charge up to 8000 Vdc.

General Troubleshooting

By observing the characteristics of a display failure, the problem can usually be isolated to either the A90 Analog Display Driver Assembly or the A60 Digital Display Driver Assembly. If the CRT screen is completely blank, the failure could be related to any -hp-3561A assembly. Start the fault isolation procedure at TEST A to isolate these types of failures. The following display symptoms most likely indicate a failure in the A90 or A99 Analog Display Driver Assemblies:

- Vertical Position Incorrect
- Vertical Size Incorrect
- Horizontal Position Incorrect
- Horizontal Size Incorrect
- Brightness Will Not Adjust Correctly
- Focus Will Not Adjust Correctly
- Excessive Background Light

The following display symptoms most likely indicate a failure in the A60 Digital Display Driver Assembly, however, these symptoms can also be caused by the main processor. For information on isolating a failure to either the digital display driver or the main processor, see the fault isolation section of this manual.

- Random Dots Appear on the Screen
- Random Dots Missing on the Screen
- Failure Appearing Only on the Alpha Numerics
- Failure Appearing Only on the Graphics
- Graticule has Missing Lines, Missing Dots, or Extra Dots

The following display symptoms most likely indicate a failure in the CRT or yoke.

- Display Pattern Trapezoidal
- Display Pattern Tilted to one side or the other

The display adjustment procedures given in Section 2 of this manual should always be performed both before and after troubleshooting the A90 or A99 Assemblies.

A60 ASSEMBLY TEST SETUP

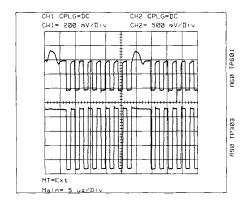
The A60 Assembly must be setup as shown below before troubleshooting the A90 and A99 Assemblies.

- 1. Turn the -hp-3561A LINE power switch OFF.
- 2. Move test jumper A60J100 to the PLANE2 position and jumper A60J200 to the 60 Hz position as shown on the A60 Assembly Component Locator.

[A] VIDEO DRIVE

With Jumper A60J100 in the PLANE2 test position, turn the -hp-3561A LINE power switch ON and check the waveforms given in Figure 7-54. Move test Jumper A60J100 to the PLANE1 test position and check the waveforms given in Figure 7-55.

Figure 7-54 PLANE2 Video Drive Waveforms



Probe: 10:1

Ch1: Connection- A90 TP601 "VIDH" Coupling- dc Ground- Fourth Graticule From Top

Ch1: Connection- A90 TP303 "CATHD"

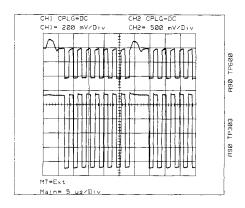
Coupling- dc

Ground- Second Graticule From Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: OFF

Figure 7-55 PLANE1 Video Drive Waveforms



Probe: 10:1

Ch1- Connection- A90 TP600 "VIDF" Coupling- dc Ground- Third Graticule From Top

Ch2: Connection- A90 TP303 "CATHD" Coupling- dc Ground- Third Graticule From Bottom

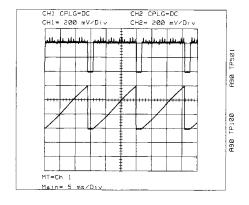
Trigger: External- A90 TP501 "SSYNC" Slope- Positive

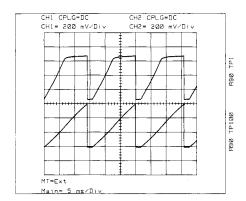
Bandwidth Limit: OFF

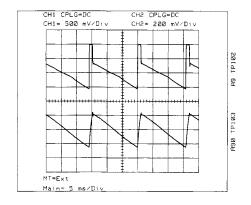
[B] SLOW SWEEP HORIZONTAL DRIVE

Check the waveforms given in Figure 7-56 in the order given. Due to feedback, a failure in the voltage to current driver may cause an incorrect signal at the test point TP102.

Figure 7-56 Slow Sweep Horizontal Drive Waveforms







Probe: 10:1

Ch1: Connection- A90 TP501 "SSYNC" Coupling- dc Ground- Third Graticule from Top

Ch2- Connection- A90 TP100 "S Ramp" Coupling- dc Ground- Third Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A90 TP1 "S Feedback" Coupling- dc Ground- Third Graticule from Top

Ch2: Connection- A90 TP100 "S Ramp" Coupling- dc Ground- Second Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A90 TP102
Coupling- dc
Ground- Third Graticule from Top

Ch2: Connection- A90 TP103 "SYDRIVER" Coupling- dc Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: ON

Note: The amplitude and dc offset of these signals will vary with the horizontal gain adjustment and the horizontal position adjustment.

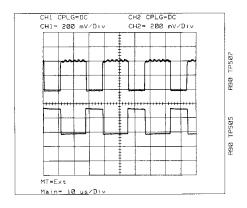
[D] FAST SWEEP VERTICAL DRIVE, [E] FLYBACK TRANSFORMER

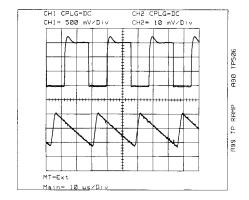
The fast sweep vertical drive circuit should be tested first in open loop mode and then in closed loop mode. To break the PSENSE feedback loop, use a clip lead to short the two pins of A90J400 together. With A90J400 shorted, check the waveforms given in Figure 7-57 in the order given. If all of the waveforms in Figure 7-57 are correct, close the feedback loop by removing the clip lead shorting A90J400 and check the waveforms given in Figure 7-58.

NOTE

When A90 J400 is shorted, the display will appear to be vertically off center and will appear to wrap around the end of the screen.

Figure 7-57 Fast Sweep Waveforms in Open Loop Mode





Probe: 10:1

Ch1: Connection- A90 TP507 "FSYNC" Coupling- dc Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP505 "LOW PDRIVE" Coupling- dc Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: ON

Probe: 10:1

Ch1: Connection- A90 TP506 "PDRIVE" Coupling- dc Ground- Fourth Graticule from Top

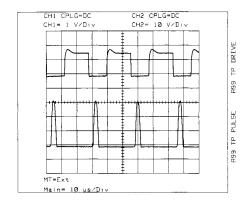
Ch2: Connection- A99 TP"RAMP"

Coupling- dc

Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope: Positive

Bandwidth Limit: ON



Probe: Ch1- 10:1 Probe on Ch1
Ch2- 10:1, 10 $M\Omega$, Maximum Voltage \geq 600 Vdc
(-hp-10014A)

Ch1: Connection- A99 TP"DRIVE"

Coupling- dc

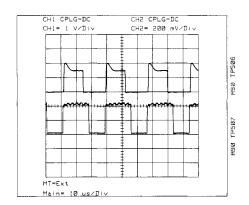
Ground- Third Graticule from Top

Ch2: Connection- A99 TP"PULSE"
Coupling- dc
Ground- Second Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: ON

Figure 7-58 Fast Sweep Waveforms in Closed Loop Mode





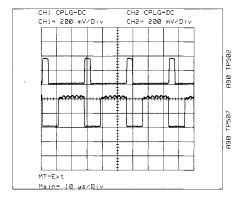
Probe: 10:1

Ch1: Connection- A90 TP506 "PDRIVE" Coupling- dc Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP507 "FSYNC" Coupling- dc Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

Bandwidth Limit: ON



Probe: 10:1 Probe on Ch1 and Ch2

Ch1: Connection- A90 TP502 "LOW PSENSE" Coupling- dc Ground- Fourth Graticule from Top

Ch2: Connection- A90 TP507 "FSYNC" Coupling: Dc Ground- Third Graticule from Bottom

Trigger: External- A90 TP501 "SSYNC" Slope- Positive

[F] HIGH VOLTAGE, [C] CATHODE RAY TUBE

WARNING

8000 Vdc present at all times in the flyback transformer and CRT EVEN WHEN THE INSTRUMENT IS TURNED OFF. Be extremely careful when working in proximity to this area. The high voltage could cause serious personal injury if contacted.

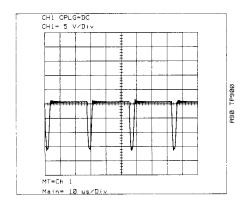
Use only high voltage probes with the specified characteristics when troubleshooting the high voltage circuits.

Before checking the high voltage signals, check for proper operation of the CRT heater. If the heater is operating correctly, there will be an orange glow at the back of the CRT.

A 10 $M\Omega$ 10:1 probe (-hp-10014A) which meets the required characteristics listed in Table 1-5 is required to check the +450 Vpeak and the -150 Vpeak waveforms of the flyback transformer. Lower impedance probes will load the high voltage circuit down, changing its operating characteristics. Check the high voltage waveforms given in Figure 7-59.

A 1000 M Ω , 1000:1 high voltage probe (-hp-34111A) which meets the required characteristics listed in Table 1-5 is required to check the 8000 Vdc CRT anode voltage. To measure this voltage, touch the tip of the probe to the anode cap as shown in Figure 7-60. The voltage should be 8200 Vdc \pm 820 Vdc.

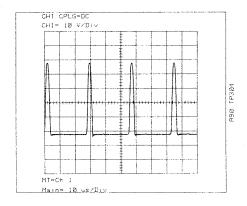
Figure 7-59 High Voltage Waveforms



Probe: 10:1, 10 MΩ, Maximum Voltage ≥ 600 Vdc (-hp-10014A)

Ch1: Connection- A90 TP900 "-150 Vpeak" Coupling- dc Ground- Center Graticule

Trigger: Internal- Ch1
Slope- Negative



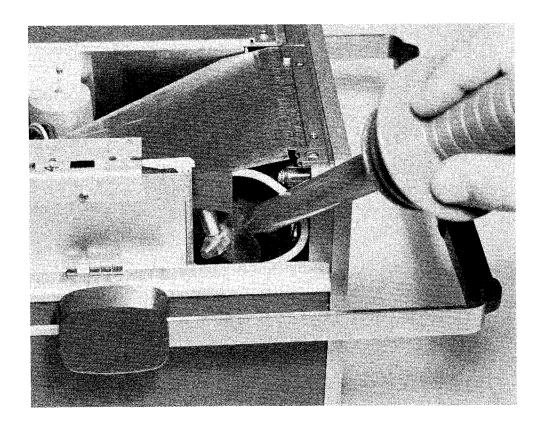
Probe: 10:1, 10 M Ω , Maximum Voltage \geq 600 Vdc (-hp-10014A)

Ch1: Connection- A90 TP304 "+450 Vpeak" Coupling- dc

Ground- Third Graticule from Bottom

Trigger: Internal- Ch1 Slope- Positive

Figure 7-60 Measuring the CRT Anode Voltage



SELECTING A99 C5, C6, C7, AND C8



Review the "Safety Considerations" and "Troubleshooting and Replacing Parts on the A99 Motherboard Assembly" paragraphs in this section before performing these procedures. The matching between the flyback transformer, T100, and capacitors A99 C5, C6, C7, C8 determines the retrace pulse width and the CRT anode voltage. Whenever T100 is replaced, these capacitors must be reselected using the procedures given below. Capacitors C5, C6, C7, and C8 can each be loaded with any of the capacitor values given in Table 7-61, with the optimum loaded values given in Table 7-62. The optimum values will be correct for most transformers and is the usual factory loaded configuration.

Table 7-61 Possible Values for A99 C5, C6, C7, C8

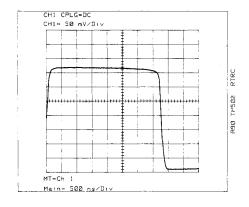
Capacitor Value	Maximum Voltage	-hp-Part Number
not loaded		
220 pF	1000 Vdc	0160-3454
470 pF	1000 Vdc	0160-3455
1000 pF	1000 Vdc	0160-3466

Table 7-62 Optimum Loaded Values for A99 C5, C6, C7, C8

Capacitor	Optimum Value
C5	1000 pF
C6	1000 pF
C7	not loaded
C8	not loaded

1. Connect the oscilloscope probe to A90TP502, turn the -hp-3561A LINE power switch ON, and set the oscilloscope to obtain the waveform given in Figure 7-61. Set the oscilloscope ground to the bottom graticule.

Figure 7-61 Retrace Pulse Width Measurement



Probe: 10:1

Ch1: Connection- A90 TP502 "RTRC" Coupling- dc Ground- Bottom Graticule

Trigger: Internal- Ch1 Slope- Positive

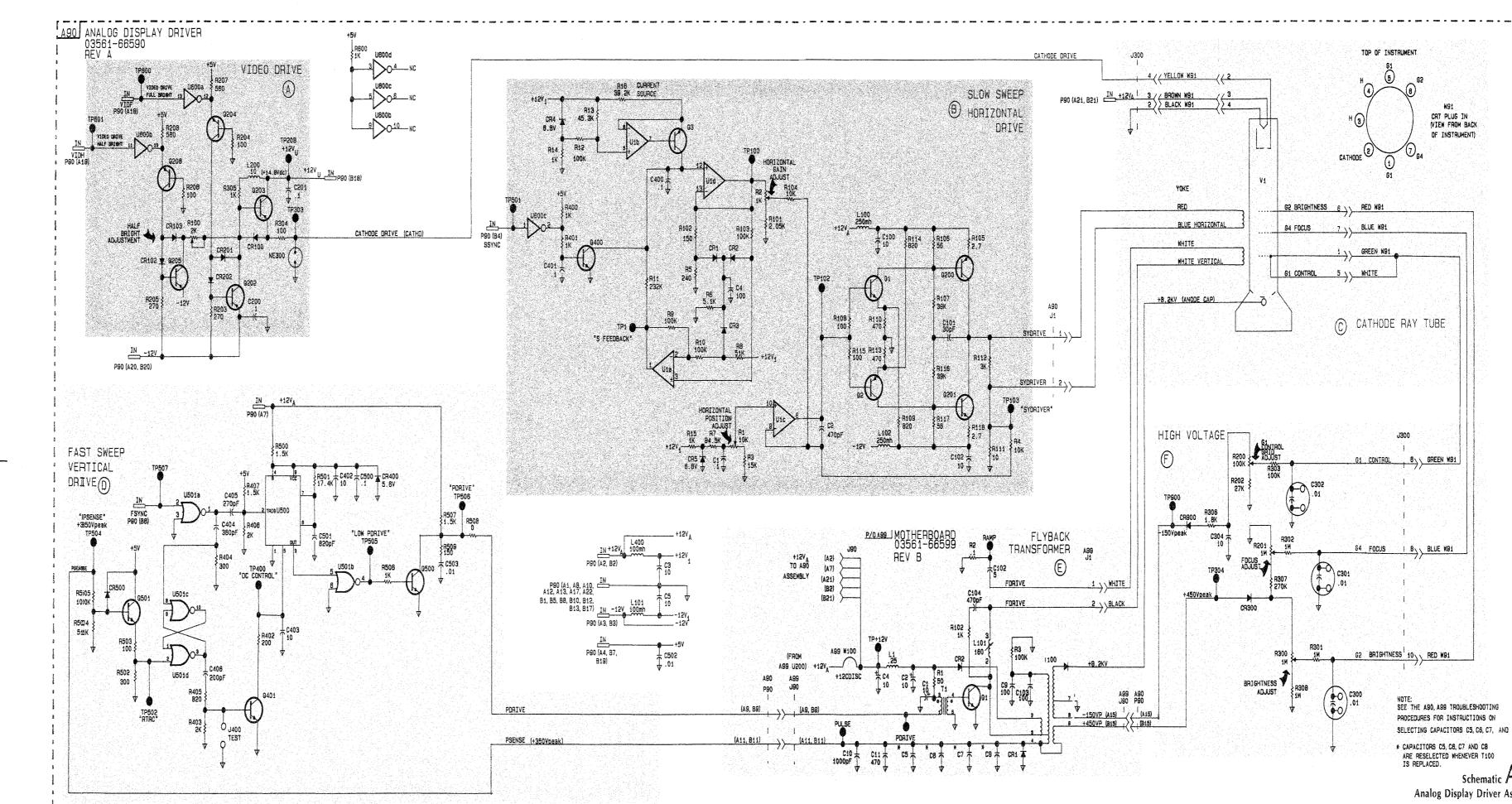
2. Measure the width of the "RTRC" pulse at the center horizontal graticule. The pulse width should be 3.7 microseconds \pm .15 microseconds (\pm 1.5 minor division).

3. If the pulse width is too narrow, increase the total capacitance of C5 + C6 + C7 + C8 by by adding 230 pF for every .1 microseconds that the pulse width is too narrow. (e.g., If the pulse width is 3.5 microseconds wide, add a 470 pF capacitor to any one of the unloaded positions to bring the pulse width up to 3.7 microseconds.)

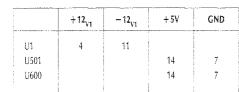
If the pulse width is too wide, decrease the total capacitance of C5 + C6 + C7 + C8 by deleting 230 pF for every .1 microseconds that the pulse width is too wide. (eg., If the pulse width is 3.9 microseconds wide, replace one of the 1000 pF capacitors with a 470 pF capacitor to bring the pulse width down to 3.7 microseconds.

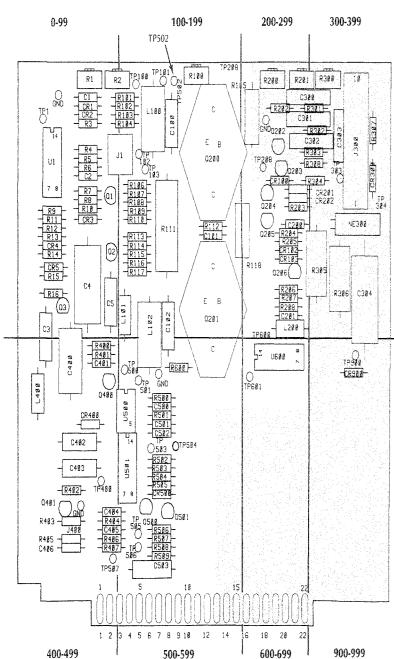
Table 7-63 A90 Assembly Signal Connections INPUTS

Signal Name	Functional Block	Connector Number	Origin Assemblies
FSYNC	D	P90(B6)	A60
SSYNC	В	P90(A4)	A60
VIDF	A	P90(A18)	A60
VIDH	A	P90(19)	A60



A90 Assembly





* CAPACITORS C5, C6, C7 AND C8 ARE RESELECTED WHENEVER T100 IS REPLACED. Schematic A90 Analog Display Driver Assembly

7-249/7-250

SEE THE ASO, ASS TROUBLESHOOTING

PROCEDURES FOR INSTRUCTIONS ON

SELECTING CAPACITORS C5, C6, C7, AND C8

TOP OF INSTRUMENT

G2 BRIGHTNESS 6 >> RED W91

61 CONTROL 5 >> WHITE

BLUE W91

GREEN W91

© CATHODE RAY TUBE

1 BA BLUE W91

G2 BRIGHTNESS 10 N RED W91

CAT PLUG IN

VIEW FROM BACK OF INSTRUMENT)

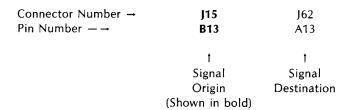
COPYRIGHT BY HEXLETT-PACKARD 1983

7-39 A99 MOTHERBOARD ASSEMBLY

7-40 Motherboard Circuit Description

The primary function of the motherboard assembly is to interconnect the signals of all -hp-3561A circuit assemblies. In addition to signal interconnect, the Motherboard Assembly contains part of the power supply circuits and part of the analog display driver circuits. Troubleshooting information for the power supply circuits is included with the A70, A71, and A72 Assemblies troubleshooting information. Troubleshooting information for the analog display circuits is included with the A90 Assembly troubleshooting information. Table 7-64 lists all inter-assembly signal connections.

Table 7-64 Signal Interconnect



Signal	Ass	emblie	es											_	,
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
A/D DATA		J15 B13	J22 A2												
ATN I/O			/ _			J52 A18							J82 A14		
BEEP							J62 B8				J72 B16				
BUBI		E			J41 A6			J65 A15							
BUBS					J41 A10			J65 B16							
CMOSS					J41 B10			J65 B18							
COMP	J10 B25	J15 B1		1							ŧ			İ	İ
CONVERT		J15 B16	J22 B2			154									
COSINE			J21 A19			J51 B8							102		
I/O				i		J52 B16							J82 A9		
DATAREQ DMAI		J15 B14	J22 B3		1.44										
DSPH			J21 B16		J41 A7		164	E							
DSPS				i	J41 B5		J61 A7								
DF1BG			122	122	J41 A9		J61 A8								
DF2BG			J22 A11	J32 B12											
DF3BG			J22 A10 J22	J32 B13 J32											
DF1BR			A9 J22	B14 J32											
DF2BR			B11 J22	A12 J32											
DF3BR			B10 J22	A13 J32											
ESR*4			B9 J21	A14		J51									
EOI 1/O			A23			B3 J52 B15							J82 A8		

J10 A15	A15	A20 J22 A7	A30	A40	450		A65							
J10 A15		J22			A50	A60	A66	A70	A71	A72	A81	A82	A90	A99
A15												J82 B18		
A15					J52 A8							J82 A18		
		J21 B12			7.0							7		
J10 A24	J15 A2	J. 2					:				į			
J10	/ 12	J21												
J10		J21						:						
J10	J15	AII												
A25	AI	J21	i											
J10	J15	D14					:							
J10	A3	J21				l						ļ		
B15	J15	J22												
	A13	B5	J31	J41										
			B4	J41	İ						J81			
				B8		J61					В14			J90
				J41	J51	В4								В6
				J41	J51									
				J41	J51									
				В11	J52							J82		
					A16			J70	J71			A12		
								B10						
i								A9	J71 B16					
J10	J15							В9						
B23	A6			J41	J51									
				J42	A10			J70						
				B13		J62	!	B13	J71					
					J52	89			A10			J82		
	A16 J10 B16 J10 A25 J10 B15	A16 J10 B16 J10 J15 A25 A1 J10 B15 A3 J10 B15 J15 A13	A16 B11 J21 A11 J10 J15 A25 A1 J21 B14 J10 J15 A23 A3 J10 B15 J22 A13 B5 B5 A13 B5 A13 A15 A16	A16	A16 J10 J15 A11 J21 A11 J11 J	A16 J10 B11 J21 J22 J22 J22 J22 J31 J41 J51 J61 J62 J62 <td>A16 J10 J15 A25 A1 J21 B14 J21 B15 J22 A13 B5 J31 J41 B8 J41 J51 B6 A6 J41 J51 B11 A11 J51 B11 A11 A11 J51 B11 A11 A11 J51 B11 A11 /td> <td>A16 10 115 121 121 121 121 121 122 131 1</td> <td>A16</td> <td>A16 100 151 121 121 121 131 141 151 151 152 152 A16 152 A16 B10 /td> <td>A16 100 115 121 </td> <td> A16</td> <td>A16 10 11 12 12 12 12 12 12</td>	A16 J10 J15 A25 A1 J21 B14 J21 B15 J22 A13 B5 J31 J41 B8 J41 J51 B6 A6 J41 J51 B11 A11 J51 B11 A11 A11 J51 B11 A11 A11 J51 B11 A11 A16 10 115 121 121 121 121 121 122 131 1	A16	A16 100 151 121 121 121 131 141 151 151 152 152 A16 152 A16 B10 A16 100 115 121	A16	A16 10 11 12 12 12 12 12 12			

Signal	Ass	emblie	es												
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
NRFD						J52							J82		
I/O NOISE			1			B17 J52							A11 J6		J300
						B21)6		1300
PBG				J32 B16	J42 B16										
PBLDS				J31	J41										
PBR				A6 J32	A12 J42										
PBR/W				A16 J31	A16 J41	J51	J61	J65				J81			
PBUDS				В7	B13	A13	A13	B15				B13			
PRODS				J31 B6	J41 A13	J51 B13									
PDRIVE														J90 A9	A99 T1
														B9	11
PRAMRE				J31 A7	J41 A4		•								
PRIOS				J32	J42		ē								
PRN SYNC				B17	B17	J52							J82		
						A21							B19		
PSENSE														J90 A11	A99 T100
DDD ///			104	•••										B11	
RBR/W			J21 A10	J31 B16											
PWR FAIL					J41					371					
REN					A4	J52				A11			J82		
I/O RESET			124	124	144	A15	164	165				101	В8		
			J21 A21	J31 B3	J41 B3	J51 A3	J61 A3	J65 B17				J81 B17			
RIOS			J21	J31											
SINT			B10	A16	J41	j51						l	İ		
-SINE			J21		B12	A12 J51									
			B19			A8									
SRQ I/O						J52 A17							J82 A13		
SSTAT		J15	J22			(11)							/(13		
SSYNC		A14	B4				J61							J90	
SYNC2			J21			J51	B5							B4	
TRIG LVL	J10	J15	B18			A5									
	B24	B2													
VIDF							J61 B3							J90 A18	,
VIDI							B3							A18	

Signal	Ass	embli	es						,						
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
VIDH							J61							J90	
							B2							A19	
ZPHTRIG			J21 A17			J51 A9									
1/3TRIG			J22			J52									
1/5111113			B7			A6						1			
				Da	ıta an	d Add	ress B	us Sig	nals						
DIO1						J52			}				J82		
I/O					ŀ	B11		,					A4		
DIO2						J52							J82		
I/O						B12							A5		
DIO3						J52							J82		
I/O	ŀ					B13		·					A6		
DIO4						J52							J82		
I/O DIO5						B14 J52							A7 J82		
1/O	i					A11							B4		
DIO6						J52						}	J82		
I/O						A12							B5		l İ
DIO7	ŀ					J52							J82		
I/O						A13							B6		
DIO8						J52						,	J82		
I/O						A14							B7		
PAB0					j41	J51	J61	J65				J81	"		Ì
,,,,,,,				i	B16	B16	B16	A12				B11			
PAB1					J41	J51	J61	J65				J81			
					Á16	A16	A16	B12				A11			:
PAB2					J41	J51	J61	J65							
					B15	B15	B15	A13							
PAB3					J41		J61	J65							
					A15		A15	B13							
PAB4					J41			J65							
					B14			A14							
PAB5					J41			J65							
					A14			B14							
PDB0				J31	J41	J51	J61	J65				J81			
1/0				B15	B24	B24	B24	A4				B6	Í		1
PDB1				J31	J41	J51	J61	J65				J81			
I/O				A15	A24	A24	A24	B4				A6			1
PDB2				J31	J41	J51	J61	J65				J81			
I/O				B14	B23	B23	B23	A5				B7			
PDB3				J31	J41	J51	J61	J65				J81			
I/O PDB4				A14 J31	A23	A23	A23	B5				A7			l
I/O				B13	J41 B22	J51 B22	J61 B22	J65 A6				J81 B8			
PDB5				J31	J41	J51	J61	J65				J81			
I/O	1			A13	A22	A22	A22	B6				A8	-		
PDB6				J31	J41	J51	J61	J65				J81			
I/O				B12	B21	B21	B21	A7				B9			
PDB7				J31	J41	J51	J61	J65				J81			
I/O				A12	A21	A21	A21	B7				A9			
PDB8				J31	J41	J51	J61	J65				'			İ
1/O				B11	B20	B20	B20	A8							

Data and Address Bus Signals

Signal	Asse	emblie	es		·			,					y		
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A9
PDB9				J31	J41	J51	J61								
/O				A11	A20	A20	A20								
PDBA				J31	J41	J51	J61								1
/O				B10	B19	B19	B19								
PDBB				J31	141	J51	J61								
/O				A10	A19	A19	A19								
PDBC				J31	J41	J51	J61								
/O				В9	B18	B18	B18								
PDBD				J31	J41	J51	J61								
/O				A9	A18	A18	A18								
PDBE				J31	J41	J51	J61								
/O				B8	B17	B17	B17								
PDBF				J31	J41	J51	J61	J65							
I/O				A8	A17	A17	A17	B11					-		
RAB0			J21	J31	J42	(()	, (17	511							
I/O			A2	B24	B11										
RAB1			J21	J31	J42										
I/O			1	ı	1										
RAB2			B2 J21	A24	A11										
				J31	J42										
I/O			A3	B23	B10										
RAB3			J21	J31	J42										
I/O			B3	A23	A10										
RAB4			J21	J31	J42								ļ		
I/O			A4	B22	B9										
RAB5			J21	J31	J42										
I/O			B4	A22	A9										
RAB6			J21	J31	J42										
I/O			A5	B21	B8										
RAB7			J21	J31	J42										
/O			B5	A21	A8										
RAB8			J21	J31	J42										
I/O			A6	B20	B7										
RAB9			J21	J31	J42										
/O			В6	A20	A7										
RABA				J31	J42										
/O			A7	B19	В6										
RABB			J21	J31	J42										
/O			B7	A19	A6								1		
RABC			J21	J31	J42								-		
/O			A8	B18	B5										
RABD			J21	J31	J42										
/O			В8	A18	A5									1	
RABE			J21	J31	J42										
/O			A9	B17	B4										
RABF			J21	J31	J42										
/O			В9	A17	A4										
RDB0			J22	J32											
/O			A12	B11										1	
RDB1			J22	J32											
/O			B12	A11											
										1				1	1

Data and Address Bus Signals

Cianal	Ass	emblie	es						1						
Signal Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
RDB2			J22	J32											
1/O			A13	B10							1				
RDB3			J22	J32									!		
1/O			B13	A10		ĺ									
RDB4			J22	132									!		
I/O			A14	В9											
RDB5			J22	J32											-
I/O			B14	A9											
RDB6			J22	J32										1	!
I/O			A15	B8								1	!		
RDB7			J22	J32											
I/O			B15	A8									I		
RDB8			J22	J32											
I/O			A16	B7											
RDB9			J22	J32									1		
I/O			B16	A7	ļ										
RDBA			J22	J32											
I/O			A17	B6											
RDBB			J22	J32											
I/O			B17	A6										ļ	
RDBC			J22	J32					ļ						
I/O			A18	B5]						
RDBD			J22	J32											
I/O			B18	A5											
RDBE			J22	J32											
1/O			A19	B4											
RDBF			J22	J32											
I/O			B19	A4											
			1			Cle	ocks		· · · · · · · · · · · · · · · · · · ·			1			
100 kHz				J31 B2	J41 A3										
256 kHz			J21						J70						
4 4 4 1 2			B23			15.4			B8						
4 MHz					J41	J51		J65							
10 24 1411-]11 -	124		B2	A2		A17			1				
10.24 MHz		J15 A15	J21 A24			J51 B2									
20.48 MHz		J15	J21	J31	J41	DZ		1							
20.40 WITZ		B15	B24	A2	A2										
		D13	D2-7	L	L		d Dav		nnline					L	
+ 5V	J10	J15	J22	J32	J42	Groun J52	J62	J65	J70	J71		J81	J82	J90	
, J¥	A13	A8	A21	A1	A1	A1	A1	A21	A11	A13		A19	A2	A4	
	B13	B8	B22	B1	B1	B1	B1	A22	B11	A14		A20	B2	B7	
	013	סט	B22	B2	B2	01	B2	B21	ווט	A14		B19	62	B19	
			022	102	DZ		DZ	B21		B14		B20		БІЭ	
						İ		D22		B14		B2U			
+8V			J22							D 13					A9
; O V			B21											1	U2
	1	I	UZ 1	1	1	1	1	I	I	1	i	1	1	i	UZ
											ļ	ļ			

Common Ground Power Supplies

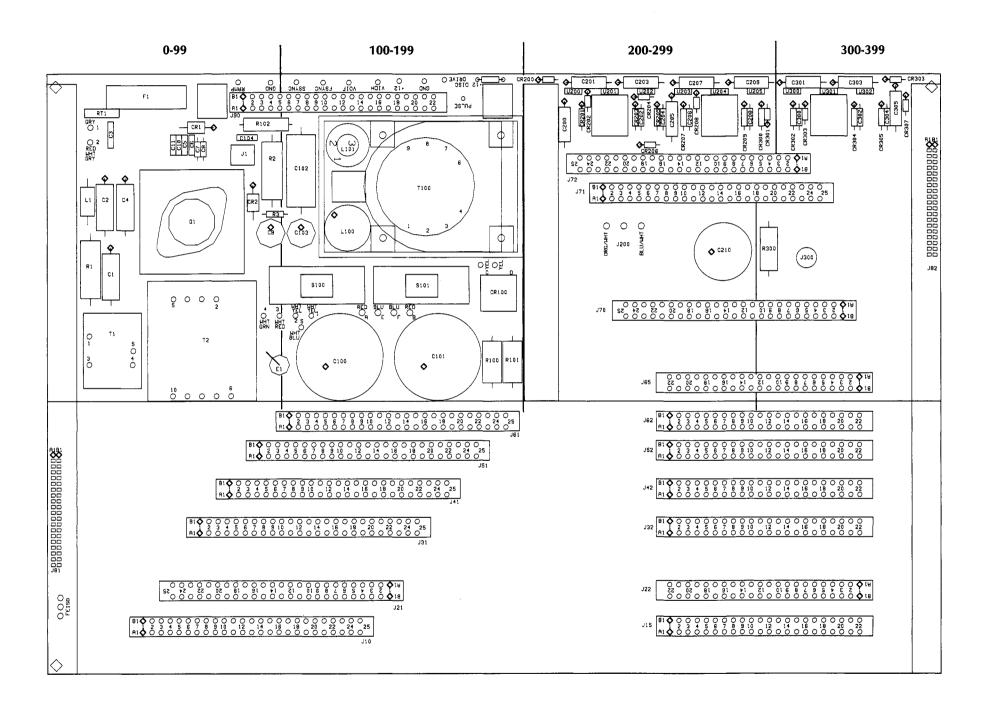
Signal	Ass	emblic	es								-				
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
+12V _A									J70 A7			The state of the s		J90 A2 A7 A21 B2 B21	A99 U200
+12V _B		J15 A9 B9	J22 A20		J42 B3	J52 B3	J62 B3	J65 A20	J70 A8						A99 U201
-12V		J15 A10 B10	J22 B20		A3	J52			J70 B6				J82 B20	J90 A3 A20 B3 B20	A99 U202
$+5V_{ref}$:			J70	J71				D20	
+12VBIAS		:				:			A13 J70	A9 J71					
									A16 A17 B16 B17	A5 A6					
-12VBIAS									J70 A14 A15 B14 B15	J71 A7 A8					
+450 Vpeak				İ					נוט					J90	A99
-150 Vpeak		:	:											J90 A15	T100 A99 T100
	1		L	Iso	lated (Groun	⊥ d Pow	er Su	pplies	1			1		
+ 5V _{AI}		J15 A21 B21							J70 B3						A99 U204
+ 5V _{B!}	J10 A21 B21	BZT		:					J70 B2						A99 U205
+15V ₁	J10 A18	J15 A18							J70 B1	3					A99 U301
+ 24V ₁	J10 A11	B18					ì		J70 A1						A99 U302
-15V ₁	B11 J10 A17 B17	J15 A19 B19							J70 A2						A99 U300

Unregulated Power Supplies

	Ass	emblie	es												
Signal Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
+8V _U											J72				A99
(+12V)											A18				U203
+ 121/											A19			100	400
+12V _U (+15V)											J72 A22			J90 B18	A99 U200
(1154)											A23				U201
											A24				
401/											A25				
-12V _U (-15V)											J72 A16		J82 A1		A99 U202
(-13V)											A17		B1		020
											A20		_ ,		
											A21				
+5V _{U!}								•	J70		J72				A99
(+8VI)									A3		A7 A8				U204 U205
											A9				020
+15V _{UI}											J72				A99
(+19VI)											A3				U301
											A4				
+ 24V _{UI} (+ 27VI)											J72 A1				A99 U30:
(T 2/ VI)											A2				030.
-15V _{∪I}											J72				A99
(-19VI)											A5				U30
			<u> </u>		. D			(unfilt		<u> </u>	A6				
				Kav	W FUW	er Sul	pnes	lanını	ereas						
$+8V_R$										J71 B7	J72 B18				
										B8	B19				
$+12V_R$										J71	J72				
			ĺ							B1	B22			ĺ	
										B2	B23				
										B3 B4	B24				
-12V _R										J71	B25 J72				
12 Y R										B5	B20				
										B6	B21				
$+5VI_R$										J71	J72				
										A22	B7				
			,							B22	B8 B9				
+15V _{IR}										J71	J72				
114										A24	B3		-		
										B24	B4			-	
$+24V_{IR}$										J71	J72				
										A25 B25	B1 B2				
-15V _{IR}										J71	J72				
- · IK										A23	B5				
										B23	В6				
														1	

Line power supplies

Signal	Asse	emblie	es												
Name	A10	A15	A20	A30	A40	A50	A60	A65 A66	A70	A71	A72	A81	A82	A90	A99
BIAS AC1										J71 A1					A99 T2
BIAS AC2										A2 J71 A3					A99 T2
+170 Vdc									J700 1	A4					J200
-170 Vdc									J700				,		2 J20
									3						3 4



APPENDIX A QUICK REFERENCE

This quick reference contains abbreviated operating information for the -hp-3561A. Included in this section is a brief description of the -hp-3561A front and rear panels, and a map illustrating the -hp-3561A menus.

MENU DEFINED KEYS

The menu defined keys are defined by the display menu entries. Menus are selected and displayed by pressing a labeled front panel key.

MEASUREMENT KEY GROUP

The measurement group indicators illuminate when a measurement is in progress, or measurement options are selected or enabled. The measurement group keys control the measurement and select menus for altering measurement parameters and options.

EXT SAMP indicator illuminates when the external sampling mode is enabled.

AVG key indicator illuminates when an averaging process is selected.

TIME BUFFER key indicator illuminates when the time capture mode is selected.

MEAS indicator illuminates when a measurement is in progress.

MODE key displays a menu for selecting the instrument measurement mode (narrow band, third octave, full octave, time capture, external sample, or test modes).

AVG key displays a menu for selecting the type of averaging process applied to the measurement.

TIME BUFFER key displays a menu for initiating a time capture operation and defining the time capture mode parameters.

START key clears the time record and accumulated average results, and initiates a measurement.

FREQ key displays a menu for defining the measurement frequency parameters.

WINDOW key displays a menu for selecting the window applied to the input signal.

SOURCE key displays a menu for enabling the -hp-3561A noise source and selecting the noise type.

PAUSE/CONT key suspends an in progress measurement or continues a suspended measurement

TRIGGER KEY GROUP

The trigger group keys control the trigger function. The trigger indicators illuminate to indicate the trigger status.

TRIG SEL key indicator illuminates when the -hp-3561A is triggered.

TRIG SEL key displays a menu for selecting and defining the trigger used for starting a measurement.

ARM key indicator illuminates when the -hp-3561A is armed and waiting for a valid trigger.

ARM key resets the trigger circuits when the manual arm trigger mode is selected.

HP-IB KEY GROUP

HP-IB group keys control the HP-IB and plotting functions. HP-IB indicators illuminate to indicate the HP-IB status.

RMT indicator illuminates when the -hp-3561A is operating under HP-IB control. In the remote mode, (and the LCL key is not locked out by the controller), only the LCL key is recognized by the -hp-3561A.

SRQ indicator illuminates when the -hp-3561A generates an HP-IB service request.

LTN indicator illuminates when the -hp-3561A is addressed to listen over the HP-IB.

TLK indicator illuminates when the -hp-3561A is addressed to talk over the HP-IB.

LCL key displays a menu for setting the HP-IB address, enabling the talk only mode, and enabling the HP-IB power on service request.

PLOT key displays a menu for selecting and defining plotter options.

LINE KEY

LINE key applies power to the -hp-3561A circuits.

DISPLAY KEY GROUP

The display group keys affect the display format.

NEXT TRACE key selects the active trace on the display. For a single trace format, NEXT TRACE toggles the display between the two available traces. The active trace is the trace displayed. For an upper/lower trace format, the active trace is identified by an intensified label over the trace graticule. For a front/back trace format or map format, the active trace is intensified.

DEFINE TRACE key displays a menu for selecting the magnitude, phase, time, or math trace functions.

VERT SCALE key displays a menu for scaling the vertical display axis.

STORE/RECALL key displays a menu for storing traces in memory, recalling traces from memory, and entering trace labels.

UNITS key displays a menu for selecting and defining the vertical and horizontal axis units of the display.

FORMAT key displays a menu for selecting a single trace, upper/lower trace, front/back trace, or map display format.

MARKER GROUP KEYS

The marker group keys affect the operation of the marker. The , FAST, and keys position the marker on the active trace. FAST, when used with the arrow keys, moves the marker at a faster rate.

MKR key displays a menu for selecting absolute marker functions.

SPCL MKR key displays a menu for selecting band marking, harmonic marker, and sideband marker measurements.

REL MKR key displays a menu for enabling the relative marker function and defining the reference values for the relative measurements.

INSTRUMENT STATE KEY GROUP

The instrument state group keys affect the instrument setup configuration.

SAVE key displays a menu for storing the current instrument state in nonvolatile memory.

RECALL key displays a menu for recalling an instrument state from nonvolatile memory.

VIEW ON/OFF key toggles the display between a graphic trace display and a tabular text display of the instrument state.

PRESET key initializes the -hp-3561A to the most commonly required setup.

INPUT KEY GROUP

The input group keys control the -hp-3561A input circuits. The input group indicators provide an indication of the input circuit status.

OVER indicator illuminates when the input signal amplitude exceeds the maximum range of the signal processing circuits

HALF indicator illuminates when the input signal level is greater than one-half the maximum input range value. An optimum input level illuminates the HALF indicator without illuminating the OVER indicator.

AUTO indicator illuminates when the -hp-3561A auto-ranging circuits are enabled

ICP CURRENT indicator illuminates when the -hp-3561A ICP current source is enabled.

A WT FILTER indicator illuminates when an internal A-weighting filter is in the -hp-3561A input signal path.

AC COUPLE indicator illuminates when ac coupling is selected.

RANGE key displays a menu for setting the input range or selecting auto-range.

INPUT key displays a menu for selecting the -hp-3561A input circuits (ac/dc coupling, A-weighting filter, or ICP current source) or calibration circuits. FLOAT-CHASSIS switch connects the input circuit ground reference to chassis ground or isolates (floats) it from chassis ground.

WARNING

Do not isolate the -hp-3561A from earth ground by interrupting the protective earth conductor inside or outside the -hp-3561A. Interruption of the protective earth conductor can subject the operator to lethal voltages.

INPUT connector provides a high impedance input (1 M Ω).

REAR PANEL CONNECTORS

SOURCE OUTPUT connector is the output for the -hp-3561A pseudo-random noise source or impulse generator. This output is enabled through the SOURCE key menu.

A positive **SOURCE SYNC** output marks a time record that coincides with an impulse or pseudo-random noise output. The output occurs at the start of the time record. If the trigger is derived from the internal noise source or impulse generator, the output is synchronized to the source trigger signal. The **SOURCE SYNC** output is a TTL level pulse.

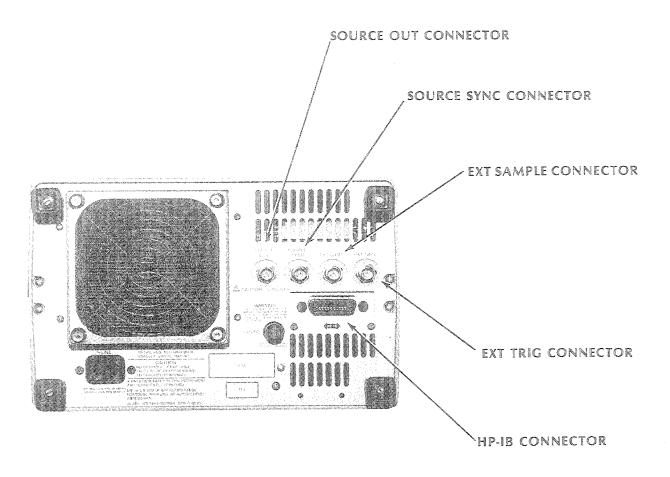
The -hp-3561A sampling frequency is controlled through the EXT SAMPLE connector when the external sampling mode is enabled through the MODE key. The EXT SAMPLE input is TTL compatible.

External trigger sources connect to the -hp-3561A through the EXT TRIGGER input connector. The -hp-3561A trigger circuits sense this connector when EXTERNAL TRIGGER is selected through the TRIG SEL key menu. The trigger input is TTL compatible.

External HP-IB devices communicate with the -hp-3561A through the rear panel HP-IB connector. The -hp-3561A controls a printer or plotter through this connector.

CROSS REFERENCE TO CHAPER II OPERATOR'S REFERENCE

KEY/KEY GROUP	PAGE
C COUPLE INDICATOR	95
RM KEY/INDICATOR	73
UTO INDICATOR	95
VG KEY/INDICATOR	63
WT FILTER INDICATOR	95
ACK SPACE KEY	74
EFINE TRACE KEY	78
ISPLAY KEY GROUP	78
OWN ARROW KEY	74
XT SAMPLE CONNECTOR XT SAMPLE INDICATOR XT TRIG CONNECTOR	97
XI SAMPLE INDICATOR	60
XI TRIG CONNECTOR	98
AST KEY	88
LOAT - GROUND SWITCH	97
REQ KEY	69
ORMAT KEY	86
ALF INDICATOR	95
P-IB CONNECTOR	97
P-IB KEY GROUP	75
CP CURRENT INDICATOR	95
NPUT CONNECTOR	97
NPUT KEY	96
NPUT KEY GROUP	95
NSTR STATE KEY GROUP	91
CL KEY	75
EFT ARROW KEY	88
INE KEY	77
TN INDICATOR	75
MARKER KEY GROUP	88
TEAS INDICATOR	60
MEASUREMENT KEY GROUP	60
MKR KEY	88
IKR VALUE KEY EXT TRACE KEY	74
	78
IUMERIC ENTRY KEYS	74 95
OVER INDICATOR	95 71
AUSE/CONT KEY LOT KEY	71 76
RESET KEY	93
ANGE KEY	95 95
EAR PANEL CONNECTORS	95 97
ECALL KEY	97
EL MKR KEY	90
ETURN KEY	60
	88
IGHT ARROW KEY MT INDICATOR	75
AVE KEY	91
OFTKEYS	59
OURCE KEY	71
OURCE OUT CONNECTOR	98
OURCE SYNC CONNECTOR	98
PCL MKR KEY	89
RO INDICATOR	75
TART KEY	69
TORE/RECALL KEY	84
ALK INDICATOR	75
IME BUFFER KEY/INDICATOR	66
RIG KEY GROUP	72
RIG SEL KEY/INDICATOR	72
INITS KEY	85
JP ARROW KEY	74
ERT SCALE KEY	83
IEW ON/OFF KEY	93
VINDOW KEY	70
TINDOW KLI	/(



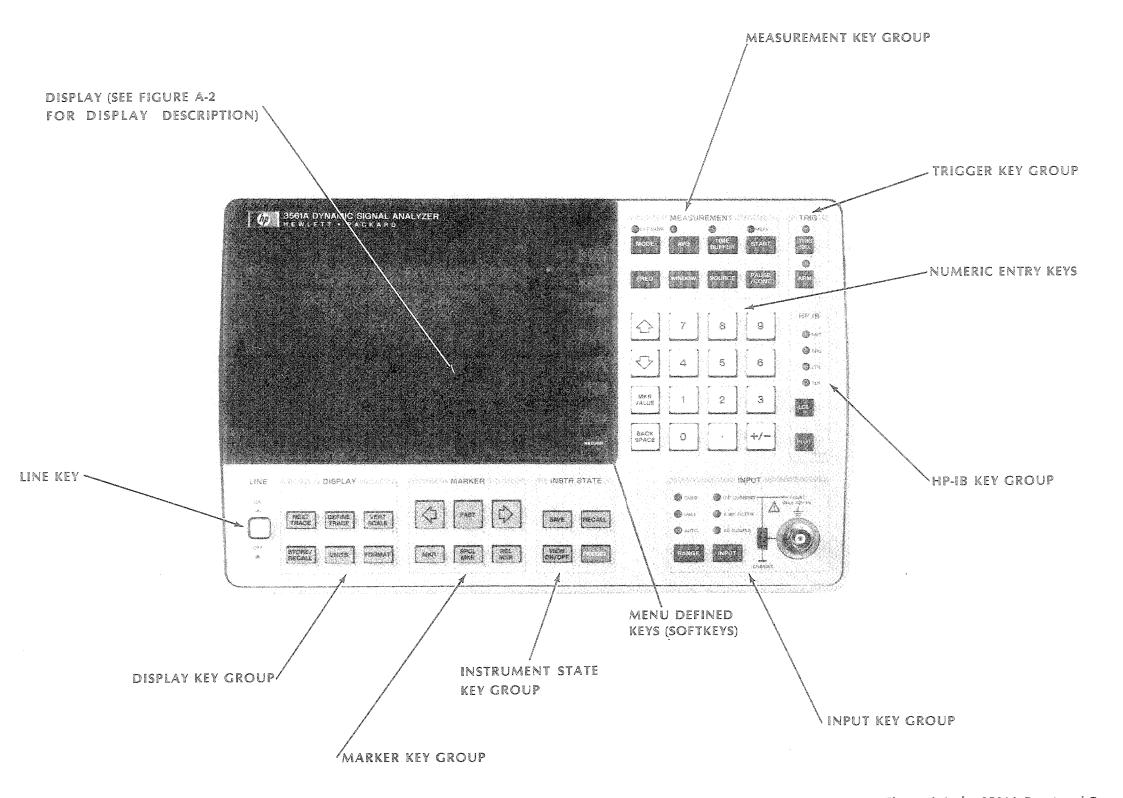


Figure A-1. -hp-3561A Front and Rear Panels.

DISPLAY DESCRIPTION

ENTRY AREA displays the alphanumeric characters used in defining a parameter. The current entry for a key requiring a numeric or character input is displayed here when the key is selected.

INPUT RANGE area displays the full scale input range.

STATUS AREA displays the current status of the -hp-3561A.

TRACE DESCRIPTION indicates the trace function. An intensified trace description indicates the active trace.

TRACE LABEL displays the trace annotation entered through the DEFINE TRACELBL menu entry when the trace label display is enabled. If the trace label display is disabled, a detailed description of the trace function is displayed in this

AVERAGE STATUS area provides information regarding the averaging process applied to the measurement.

OVERLOAD STATUS area indicates overloads occuring during a measurement.

Y-AXIS LABEL displays the annotation for the graticule vertical axis.

X-AXIS LABEL displays the annotation for the graticule horizontal axis.

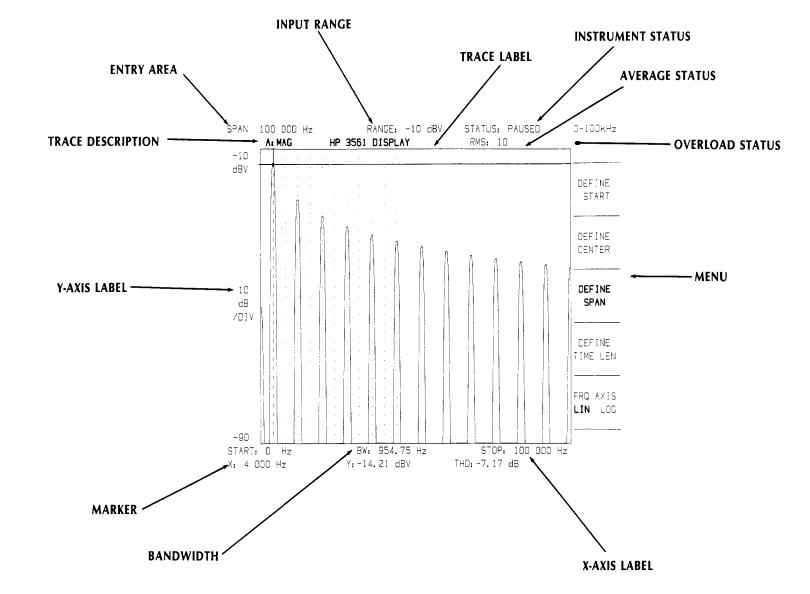
BANDWIDTH display area displays the measurement bandwidth.

X MARKER area displays the horizontal axis coordinate value of the marker.

Y MARKER area displays the vertical axis coordinate value of the marker.

MENU area displays the menu defining the unlabeled keys to the right of the menu

SINGLE TRACE AND MAP MODE DISPLAY FORMAT



DUAL TRACE DISPLAY FORMAT

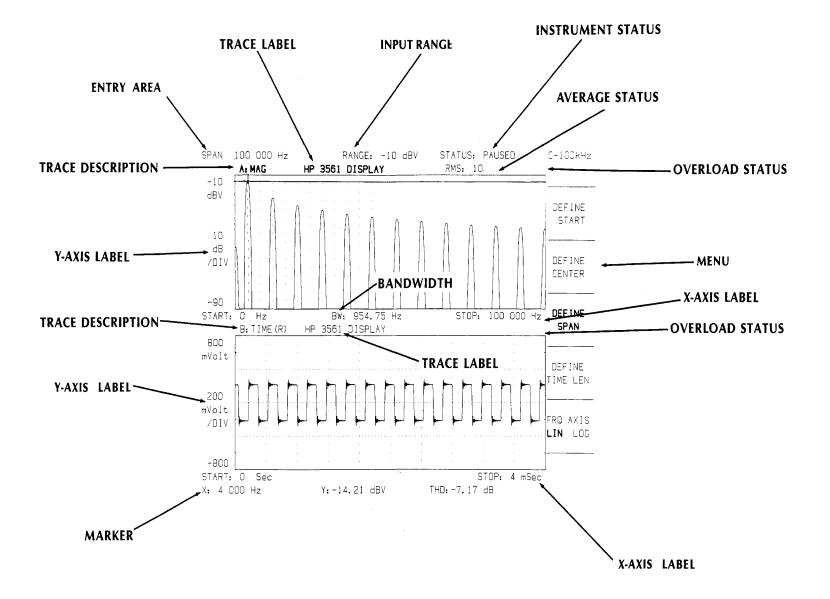
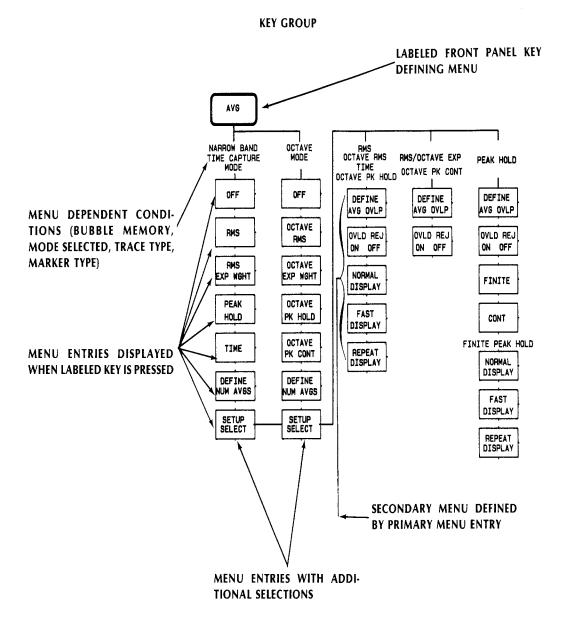
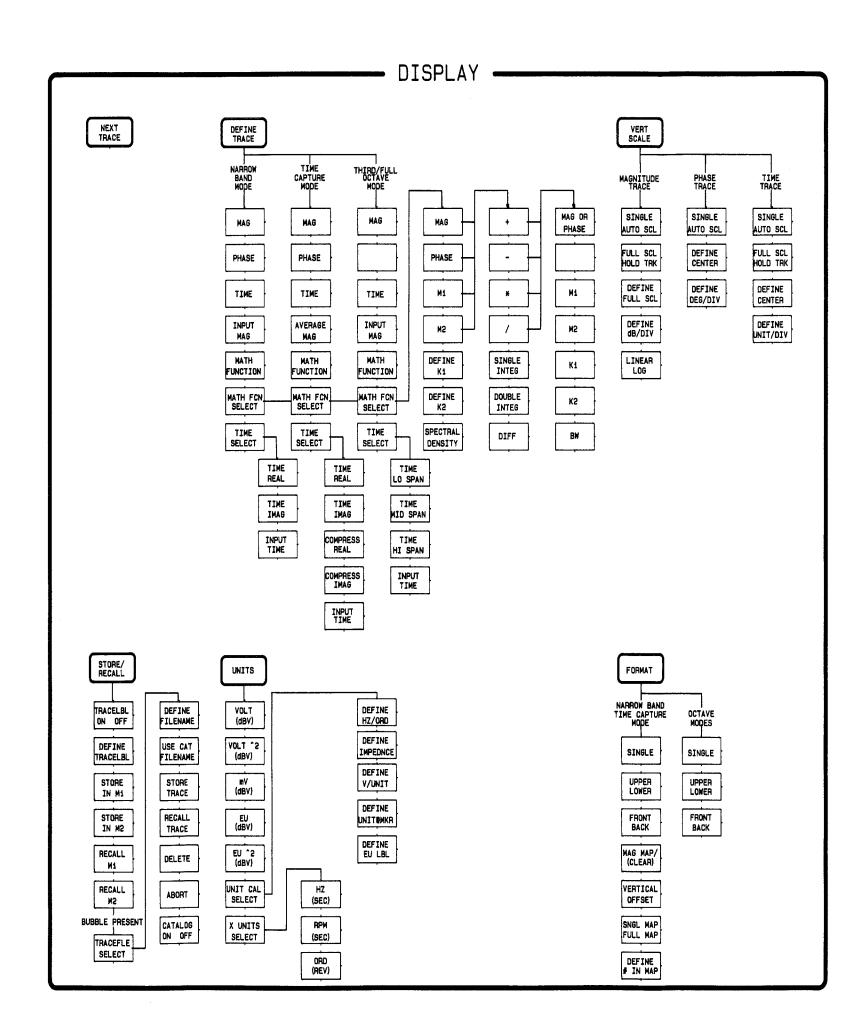
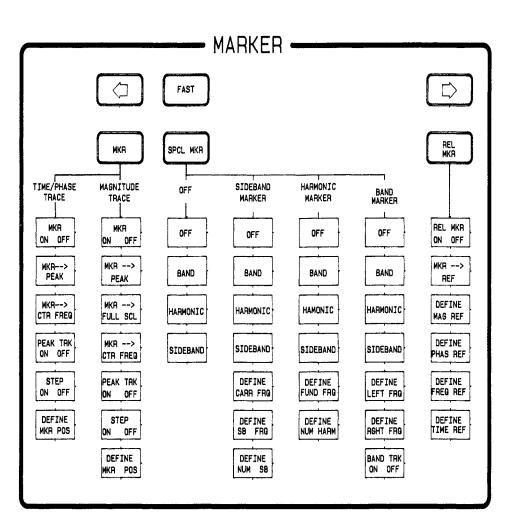


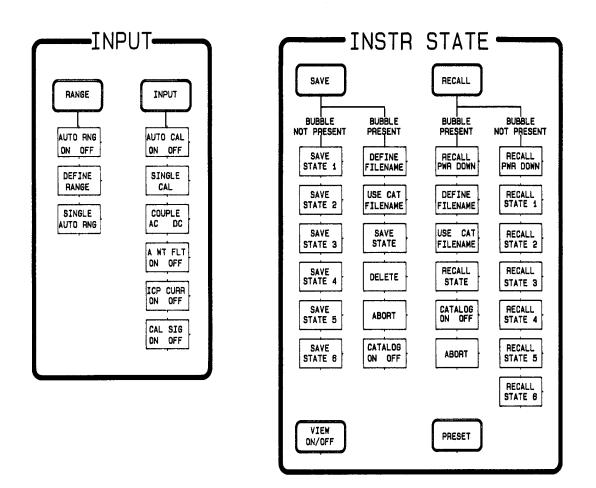
Figure A-2. Display Annotation II

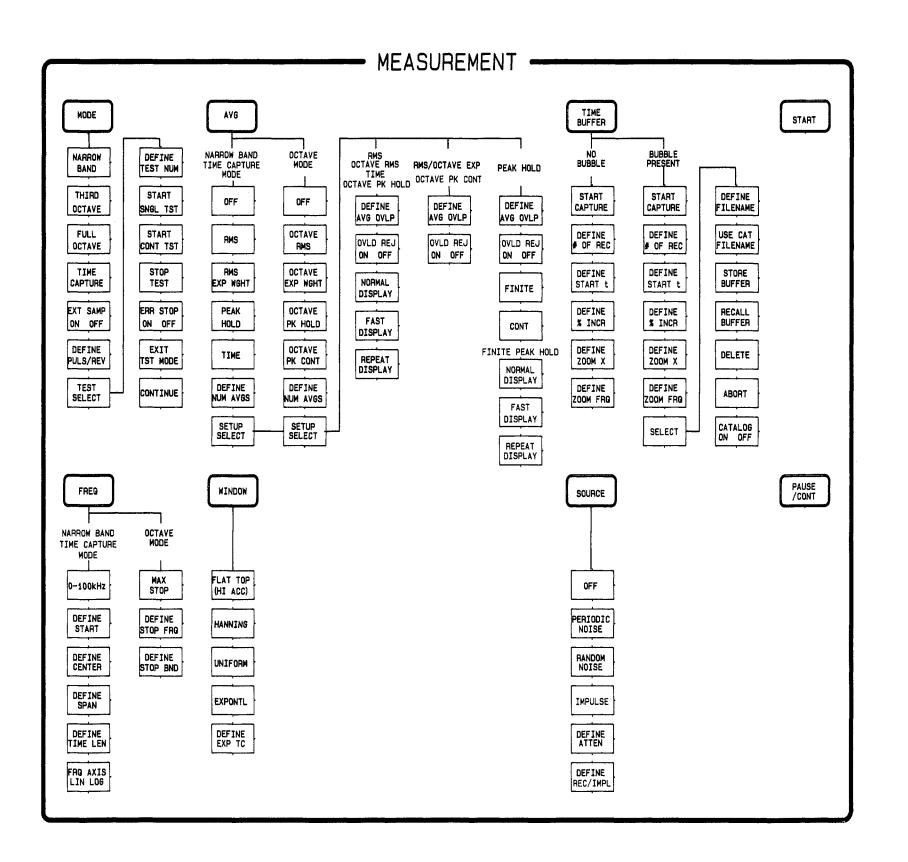
HOW TO INTERPRET THE KEY MAP

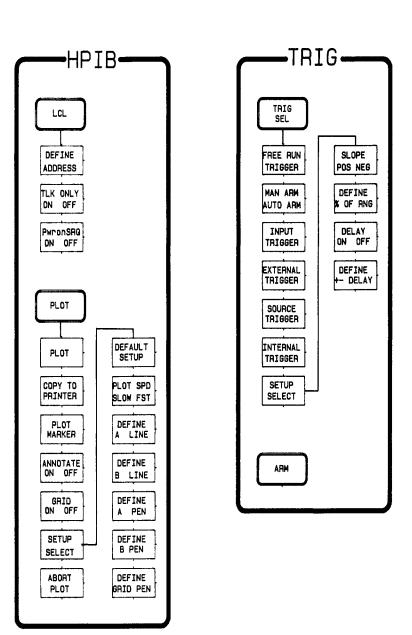
















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